

# **Injection Locked Clocking and Transmitter Equalization Techniques for Chip to Chip Interconnects**

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To my family

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# Abstract

Semiconductor technology scaling has enabled drastic growth in the computational capacity of integrated circuits (ICs). This constant growth drives an increasing demand for high bandwidth communication between ICs. Electrical channel bandwidth has not been able to keep up with this demand, making I/O link design more challenging. Interconnects which employ optical channels have negligible frequency dependent loss and provide a potential solution to this I/O bandwidth problem. Apart from the type of channel, efficient high-speed communication also relies on generation and distribution of multi-phase, high-speed, and high-quality clock signals. In the multi-gigahertz frequency range, conventional clocking techniques have encountered several design challenges in terms of power consumption, skew and jitter. Injection-locking is a promising technique to address these design challenges for gigahertz clocking. However, its small locking range has been a major contributor in preventing its ubiquitous acceptance.

In the first part of this dissertation we describe a wideband injection locking scheme in an LC oscillator. Phase locked loop (PLL) and injection locking elements are combined symbiotically to achieve wide locking range while retaining the simplicity of the latter. This method does not require a phase frequency detector or a loop filter to achieve phase lock. A mathematical analysis of the system is presented and the expression for new locking range is derived. A locking range of 13.4 GHz–17.2 GHz (25%) and an average jitter tracking bandwidth of up to 400 MHz are measured in a high- $Q$  LC oscillator. This architecture is used to generate quadrature phases from a single clock without any frequency division. It also provides high frequency jitter filtering while retaining the low frequency correlated jitter essential for forwarded clock receivers.

To improve the locking range of an injection locked ring oscillator; QLL (Quadrature locked loop) is introduced. The inherent dynamics of injection locked quadrature ring oscillator are used to improve its locking range from 5% (7-7.4GHz) to 90% (4-11GHz). The QLL is used to generate accurate clock phases for a four channel optical receiver using a forwarded clock at quarter-rate. The QLL drives an injection locked oscillator (ILO) at each channel without any repeaters for local quadrature clock generation. Each local ILO has deskew capability for phase alignment. The optical-receiver uses the inherent frequency to voltage conversion provided by the QLL to dynamically body bias its devices. A wide locking range of the QLL helps to achieve a reliable data-rate of 16-32Gb/s and adaptive body biasing aids in maintaining an ultra-low power consumption of 153pJ/bit.

From the optical receiver we move on to discussing a non-linear equalization technique for a vertical-cavity surface-emitting laser (VCSEL) based optical transmitter, to enable low-power, high-speed optical transmission. A non-linear time domain optical model of the VCSEL is built and evaluated for accuracy. The modelling shows that, while conventional FIR-based pre-emphasis works well for LTI electrical channels, it is not optimum for the non-linear optical frequency response of the VCSEL. Based on the simulations of the model an optimum equalization methodology is derived. The equalization technique is used to achieve a data-rate of 20Gb/s with power efficiency of 0.77pJ/bit.

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# Chapter 1: Introduction

We are living in an era where number of transistors in ICs (Integrated Circuits) outnumber earth's population (Figure 1.1). The relentless pursuit of Moore's law has enabled our journey from the first Intel 4004 microprocessor in 1971 with a modest 2.3k transistors to the modern Oracle Sparc M7 microprocessor with an astounding 10 billion transistors (Figure 1.1). This remarkable growth has made today's ICs really complex systems with different communicating and processing components.

In the early stages of CMOS technology, integration of more and smaller transistors allowed increasing complexity in the design of processing and communication units. It led to a trend towards rise in clock speeds (Figure 1.2). This approach provided a tremendous improvement in processing speed and power efficiency until 2004, when designers ran into the problem of increased power consumption. It turned out that by scaling clock frequency, only marginal improvement in processing performance was achieved while a significant power penalty had to be paid [1]. Power reduction became mandatory and the trend towards lower clock frequencies started, as shown in the frequency trends chart in Figure 1.2. The performance loss resulting from lower clock frequencies was compensated for by increased parallelism. Designers employed a parallel computing approach through multi-core processors (Figure 1.2). Present day high performance microprocessors have over tens of cores on a single chip and an aggregate performance of 100's of gigaflops (floating point operations per second). In the near future processors are expected to have hundreds of cores to enable exascale computing.

For the entire system to benefit from this increased computation throughput, the off-chip input/output (I/O) bandwidth should also scale. High aggregate bandwidth can be achieved by employing large numbers of inputs and outputs per chip as well as high data rates per I/O. This has led to the widespread use of parallel links, where interfaces between chips employ tens to hundreds of I/O links in parallel to achieve their aggregate bandwidth targets. But number of pins does not scale as fast due to physical connection and area limitations, thus the per pin bandwidth also needs to increase. Figure 1.3 shows that per-pin data rate has approximately

doubled every four years across a variety of diverse I/O standards ranging from DDR to graphics to high-speed Ethernet.

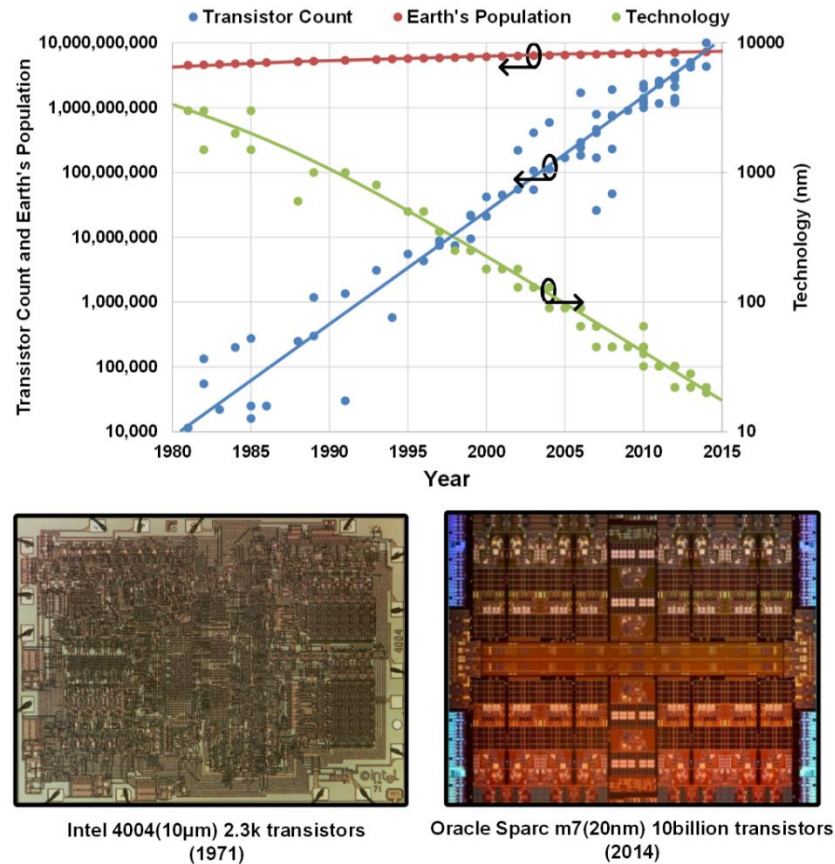


Figure 1.1: Scaling in microprocessors.

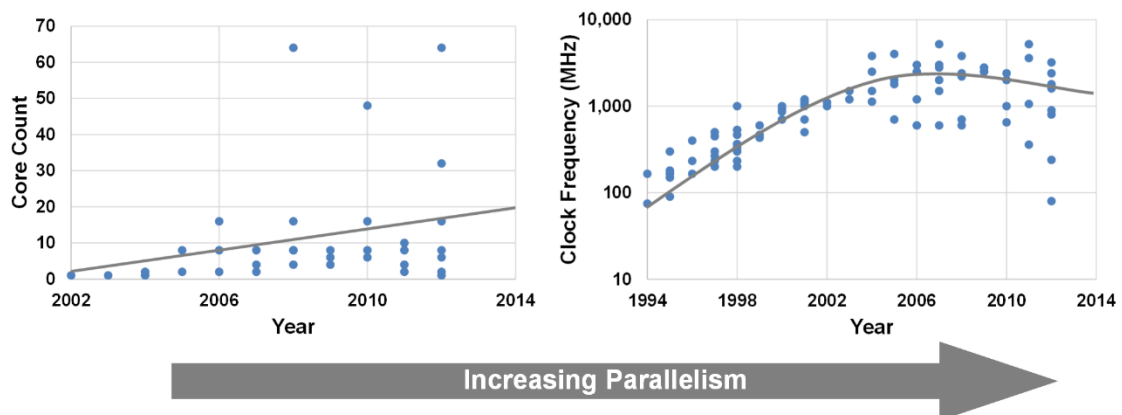
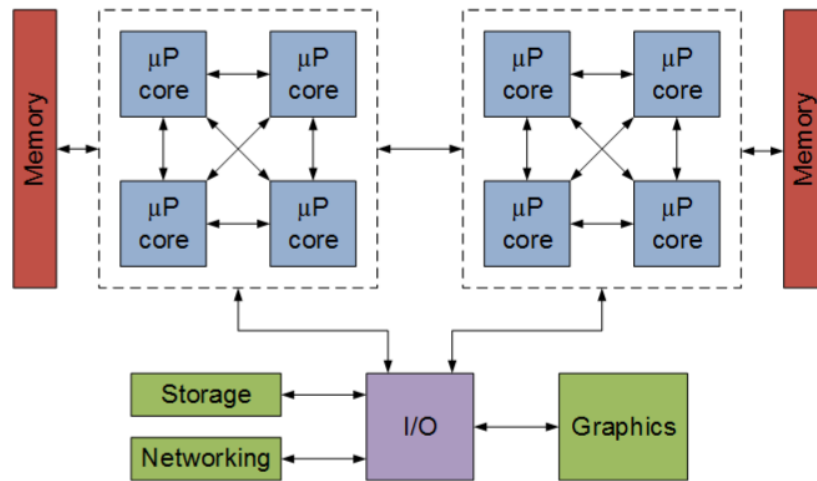
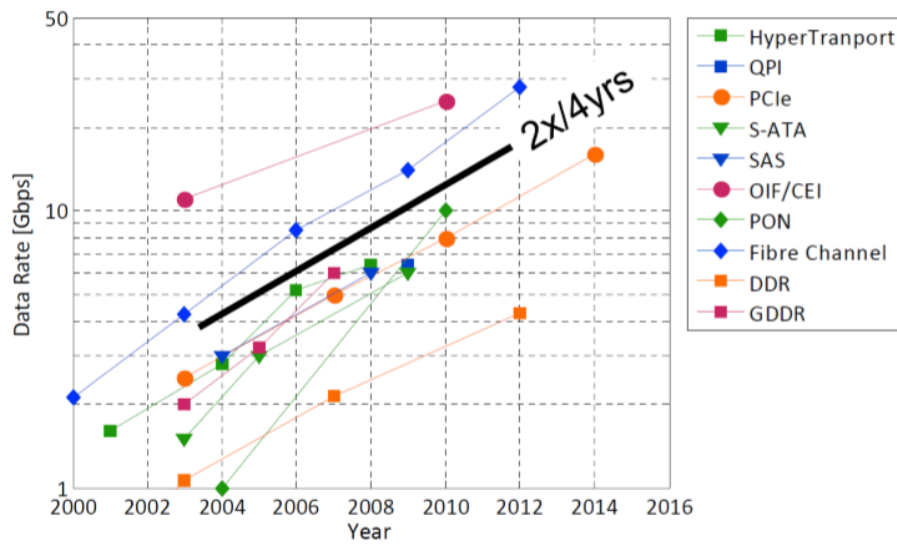


Figure 1.2: Microprocessor core count scaling (left) and microprocessor clock frequency scaling (right) [2] (data from ISSCC trends 2012).



**Chip to Chip Interconnects in a computer server**

Figure 1.3: Scaling of common wireline I/O standards (top) [3] and block diagram of chip to chip links in a computer server.

However, as we reach the limits of electrical channel bandwidth, continuing along this trend for I/O scaling becomes more and more difficult.

## 1.1 Optical Interconnects

Electrical interconnects are conventionally the main platform for data communication. However, due to their limited bandwidth, the scaling of data rate proves to be very challenging.



Channel bandwidth degradation is the result of many physical effects, including skin effect, dielectric loss, and reflections due to impedance discontinuities. As a consequence, high data rate pulses transmitted through these channels will broaden to greater than a unit interval (UI), thus creating intersymbol interference (ISI) with preceding bits and succeeding bits which ultimately leads to signal-to-noise-ratio (SNR) degradation. A common approach in the design of high-speed serial links over bandwidth-limited channels is to employ equalization techniques to cancel destructive effects of ISI. Typical equalization techniques include decision feedback equalization (DFE) [4], feed-forward equalization (FFE) [5] and continuous time linear equalization [6] at the receiver and FFE at the transmitter [7]. However, the power and area overhead associated with equalization makes it difficult to achieve target bandwidth with a realistic power budget. As a result, rather than being technology limited, current high-speed I/O link designs are fast becoming channel and power limited.

A promising solution to the I/O bandwidth problem is the use of optical inter-chip communication links. The negligible frequency dependent loss of optical channels provides the potential for optical link designs to fully utilize increased data rates provided through CMOS technology scaling without excessive equalization complexity. Optics also allow very high information density through wavelength division multiplexing (WDM). However, optical links do require additional circuits that interface to the optical sources and detectors. Thus, in order to achieve the potential link performance advantages, emphasis must be placed on using efficient optical devices and low-power and area interface circuits at the transmitter and the receiver ends.

For optical transmitters, vertical-cavity surface-emitting lasers (VCSELs) [8], [9] are often used for electrical to optical conversion. A VCSEL is a semiconductor laser diode which emits light perpendicular from its top surface. These surface emitting lasers offers several manufacturing advantages over conventional edge-emitting lasers, including wafer-scale testing ability and dense 2D array production. They can be modulated directly by varying the laser current, thus offering advantage over multiple-quantum-well modulators [10] and ring resonator modulators [11] which require a separate continuous-wave laser source. Modulators, also require high voltage swing electrical inputs, making them difficult to integrate with modern CMOS technology. Unique properties of VCSELs make them a viable candidate for low-power and low-cost, optical modulation.

Typical optical receivers use a photodiode to sense the high-speed optical power and produce an input current. This photocurrent is then converted to a voltage and amplified sufficiently, for data resolution, conventionally using a transimpedance amplifier (TIA). However, as data-rates

increase TIA based approaches have become more and more power hungry [12]. New techniques such as integrating frontend [13] and double-sampling [14] have improved optical receivers' power consumption remarkably. These approaches have paved the way for massively parallel optical communications. However, complete utilization of the potential of these low-power techniques requires innovations on the clocking front as well. In conventional clocking schemes that employ a global phase-locked-loop (PLL) locked reference and digitally distributed clock through buffer chains and clock grids, the power required to constantly switch the large capacitive loads can consume 40% of the chip's total power budget [15]. Thus, alternative low-power clocking schemes are required for the next generation of massively parallel optical links.

Overall, for optical interconnects to become viable alternatives to established electrical links, they must be low cost and have competitive energy and area efficiency metrics. To address future optical interconnects power consumption requirement, in this dissertation we describe a low-power clocking circuit for a 4 channel quarter-rate optical receiver and a low-power VCSEL based optical transmitter.

## 1.2 Injection Locked Clocking in Parallel Links

In communication systems, the generation and distribution of synchronizing clock is a fundamental task. Two types of clocking architecture are common in today's multi-Gb/s I/Os. The first is the embedded clock (EC) architecture [16] where timing information is extracted from the data by performing clock and data recover (CDR). A per pin CDR proves too power hungry and complicated for parallel links with multiple data channels. Hence, for simplicity and better power efficiency, a synchronous forwarded clock (FC) architecture [17] is generally adopted in parallel. A typical block diagram of FC architecture is shown in Fig. 1.4. It consists of a single line of clock and multiple lines of data. The cost and power overhead of the FC circuits are amortized across multiple links in the system. Examples of source-synchronous parallel links include memory interfaces such as DDR3 [18], and chip-to-chip interfaces such as HyperTransport [19] and QuickPath [20].

In FC links the clock pattern, sent on a separate but similar channel, is used in the receiver to sample the data pattern at the optimum point. At multi-Gb/s speeds each data channel may have phase mismatch or skew with respect to the reference clock. This necessitates a per channel

“deskewing”. This is performed by the timing recovery circuit (Figure 1.4) which may be based on a phase-locked loop (PLL), a delay-locked loop (DLL) or an injection locked (IL) architecture. The pros and cons of each are discussed below.

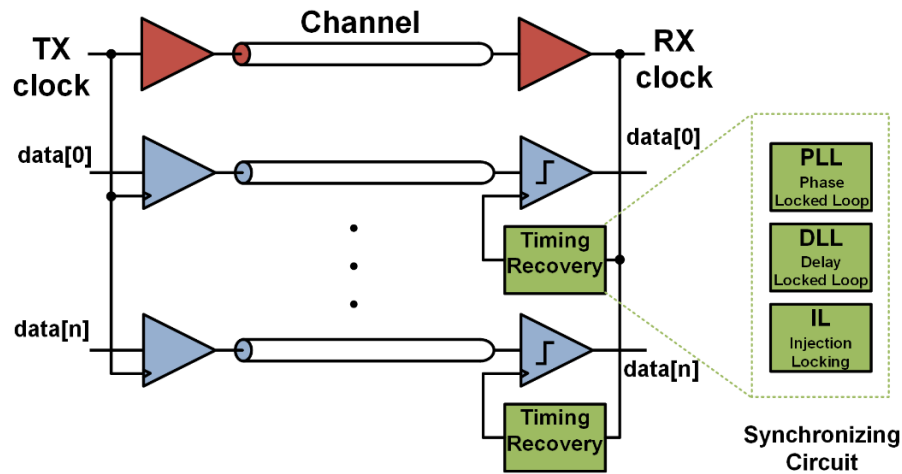


Figure 1.4: Forwarded clock parallel link.

Jitter on the forwarded clock is correlated with jitter on the data because both are generated by the same transmitter. Hence, jitter performance is improved by retiming the data with a clock that tracks correlated jitter on the forwarded clock [21]. However, since the delay of the data and clock paths typically differ by several UIs, very high frequency jitter will appear out-of-phase at the receiver and should not be tracked. To account for latency mismatch and sample the data pattern at the optimum point, a clock deskew mechanism is used to optimally shift the forwarded clock. DLLs in conjunction with phase interpolators (PIs) are commonly used to deskew the clock phase. However, due to an all-pass jitter transfer characteristic, a DLL cannot filter the high frequency jitter [17]. In fact the high frequency may also be amplified due to the finite bandwidth of the delay line of the DLL [22]. High-frequency clock jitter can be filtered by using a PLL in conjunction with PIs, owing to the inherent low-pass jitter transfer characteristic of a PLL. However, this low-pass phase transfer characteristic diminishes useful jitter components (i.e., those that are correlated to the data channel jitter) which could result in suboptimum performance and lower clock recovery bandwidth. PLLs also have other disadvantages such as susceptibility to jitter accumulation and stability issues.

Injection locked oscillators (ILO) are a power and area efficient alternative to PLLs and DLLs. As discussed in Chapter 2, ILO can be modelled as first order PLL and hence can be used

to filter high frequency jitter. But unlike a PLL, an ILO has a higher jitter tracking bandwidth and thus it does not filter out the useful low frequency correlated jitter [17]. Additionally, ILO can perform clock deskew by introducing a frequency offset between the ILO's free running frequency and the injected frequency. The first order nature of injection locking proves very useful as it ensures no peaking and guarantees stability. This makes the design of injection locked based circuits very simple compared to a PLL.

Despite being so well suited to timing recovery in forwarded clock applications; the fundamental hindrance with all injection locked based systems is their small locking range. Ring and LC oscillators typically have a maximum locking range of 10% [23] [24]. This problem exacerbates with scaling as process, voltage and temperature (PVT) variations make it difficult to design reliable systems with small locking ranges. We propose techniques to enhance the locking ranges of LC and ring oscillators to ensure reliable operation of injection locking based techniques in forwarded clock architectures.

One of the challenges that arise at higher data rates is timing and synchronization. As the UI (unit-interval) size, or bit time, decreases, the receiver has smaller and smaller timing margin and clocking becomes more difficult. In a full-rate link, the period of the clock is the same as the length of a UI and, for example, a 10Gb/s link will operate with a 10GHz clock. At multi-Gb/s data rates, however, the high-frequency clocks required for this approach consume large amounts of power and complicate the process of timing recovery. As a result, designers use sub-rate clocking schemes. These are essentially multiplexing/demultiplexing schemes, where the clock operates at some integer fraction of the data rate and the data is transmitted and/or received using multiple phases of a clock period. Particularly popular are half-rate and quarter-rate schemes. An essential prerequisite for these is the generation of quadrature phase clocks at low power overhead. Both ring and LC based dividers have been frequently used for quadrature phase generation [25]. However, they operate at twice the desired frequency, hence tend to be power inefficient. Quadrature phase generation through ring ILO's without frequency division leads to phase inaccuracies [26]. In this dissertation, we describe techniques for injection locking based wideband accurate quadrature phase generation in LC and ring oscillators without any frequency division.

## 1.3 Organization

This dissertation is composed of three major parts. Chapter 2 provides a review of clocking in high-speed data transmission systems. Metrics used for characterizing clock and data in high-speed links are introduced. Injection locking dynamics are discussed. Basics of the VCSEL based optical transmitter are introduced.

Chapter 3 describes a novel technique for wideband injection locking in an LC oscillator. We show how PLL and injection-locking elements can be combined symbiotically to achieve a wide locking range while retaining the simplicity of the latter. A mathematical analysis of the system is presented and the expression for the new locking range is derived. A locking range of 13.4 GHz–17.2 GHz (25%) and an average jitter tracking bandwidth of up to 400 MHz are measured in a high- $Q$  LC oscillator. This architecture is used to generate quadrature phases from a single clock without any frequency division. It also provides high frequency jitter filtering while retaining the low frequency correlated jitter essential for forwarded clock receivers.

A unique injection locking technique called the QLL (Quadrature Locked Loop) is introduced in Chapter 4. It utilizes the inherent dynamics of the injection locked quadrature ring oscillator to improve its locking range from 5% (7-7.4GHz) to 90% (4-11GHz). The QLL is used to generate accurate clock phases for a four channel optical receiver using a forwarded clock at quarter-rate. Chapter 5 details the QLL based clocking for a four channel quarter-rate optical receiver. The QLL drives an ILO at each channel without any repeaters for local quadrature clock generation. Each local ILO has deskew capability for phase alignment. The optical-receiver uses the inherent frequency to voltage conversion provided by the QLL to dynamically body bias its devices. A wide locking range of the QLL helps to achieve a reliable data-rate of 16-32Gb/s, and adaptive body biasing aids in maintaining an ultra-low power consumption of 153pJ/bit.

From an optical receiver we move on to discussing a VCSEL based optical transmitter in Chapter 6. A non-linear time domain optical model of the VCSEL is built and evaluated for accuracy. Based on the simulations of the model, an optimum equalization methodology to enable low-power, high-speed optical transmission is derived. The equalization technique is used to achieve a data-rate of 20Gb/s with power efficiency of 0.77pJ/bit.

Conclusions of the work are presented in Chapter 7.

# Chapter 2: Background

In this chapter we develop the framework for discussions in the later chapters. We start with a quick review of the metrics of a high-speed link. Next we delve into the details of clocking in high-speed interconnects. We describe the nature of timing uncertainty (jitter) in clocks and the common techniques used to characterize it. Then we describe the fundamentals of injection locking; a promising technique for high performance clock generation and distribution. We end this chapter by discussing a fundamental building block of an optical transmitter, vertical-cavity surface-emitting laser (VCSEL).

## 2.1 Metrics of High-Speed Interconnect

Figure 2.1 (a) shows the components and configuration of the basic clocked link. It consists of a transmitter, receiver, and channel. The transmitter (Tx) converts the digital data into an electrical/optical signal and launches it on the channel. Since the signal sent down the channel exists in the continuous time analog domain, the purpose of the receiver (Rx) is to determine the optimum decision point, in time and amplitude, in order to estimate the original bit-stream and minimize errors. Since a link's receiver needs to convert an analog signal back into digital data, there is always a probability that (bit) errors will occur. Thus an important metric called bit-error rate (BER) is used to measure the reliability of the link in data communication links. A link's maximum data rate is usually specified at a specific BER (e.g.  $10^{-12}$ ) to guarantee the robustness of the overall system. In an additive white Gaussian noise (AWGN) channel, the BER is classically characterized by the voltage margin,  $V_m$  at the sampling point [27]:

$$\text{BER} = e^{-\frac{(V_m/V_r)^2}{2}} \quad (2.1)$$

where  $V_r$  is the root-mean square (RMS) voltage noise; since Gaussian noise is assumed, this is equivalent to the noise standard deviation.

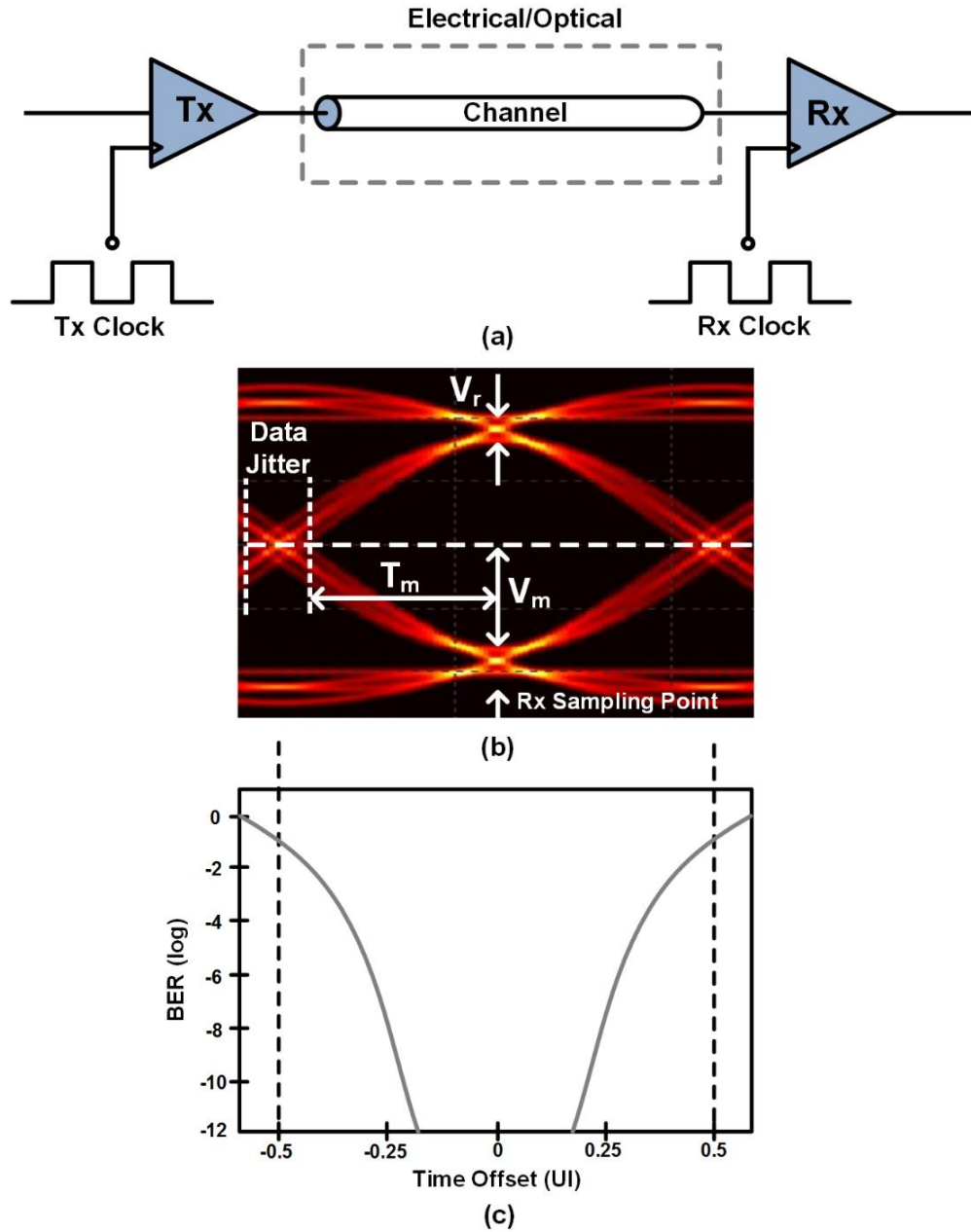


Figure 2.1: (a) Basic clocked high-speed link. (b) Typical receiver data eye-diagram with voltage and timing margins ( $V_m$  and  $T_m$ ). (c) Translation of eye-diagram to bathtub curve.

Besides voltage noise, the second major contributor to BER is timing uncertainty at the receiver. Like voltage noise, this uncertainty is a random process, and it is characterized by the jitter of the receiver clock as well as that of the transmitted signal. Both sources of jitter shift the sampling point away from its optimum, and have the effect of reducing the voltage margin and

degrading the BER. This effect is of particular concern as data rates increase, since jitter can become a substantial portion of a data period (also known as a unit interval, UI). As a result, timing margin can become a larger concern than voltage margin in high-speed links [28]. A helpful and common tool for visualizing the effects of noise and jitter on a link is the eye diagram, which is generated by superimposing many UIs of the data signal (Figure 2.1(b)).

In addition to the eye diagram, the bathtub curve is another diagnostic tool for performing signal integrity analysis. Bathtub curves are usually created by measuring the BER while sweeping the sampling clock over the bit time. Figure 2.1(c) shows a typical bathtub curve. Bathtub curves are useful tools for characterizing the performance of the receiver and show how tolerant the system is to the sampling clock jitter noise, as well as the amount of horizontal and vertical eye opening.

## 2.2 Clocking

One of the challenges that arise at higher data rates is timing and synchronization. As the UI size decreases, the receiver has a smaller and smaller timing margin and clocking naturally becomes more difficult. In order to provide a framework for discussion on this subject, it is helpful to outline several common clocking styles:

- Synchronous: In a synchronous link, the transmitter and receiver clocks are assumed to have the same frequency and phase. This is generally only a tenable assumption at low data rates.
- Mesochronous: In a mesochronous link, the transmitter and receiver clocks are assumed to have the same frequency, but may be out of phase. A popular sub-set of this category is the source-synchronous link, where the clock is generated at the transmitter and forwarded along with the data. These are also known as forwarded clock links.
- Plesiochronous: In a plesiochronous link, the transmitter and receiver clocks may have slight differences in frequency. The receiver is required to align its clock by extracting timing information from the incoming data stream. These are also known as embedded clock links.
- Asynchronous: An asynchronous link is not really clocked at all. Rather, it uses either control symbols inserted in the data stream itself or handshaking signals to convey timing information.



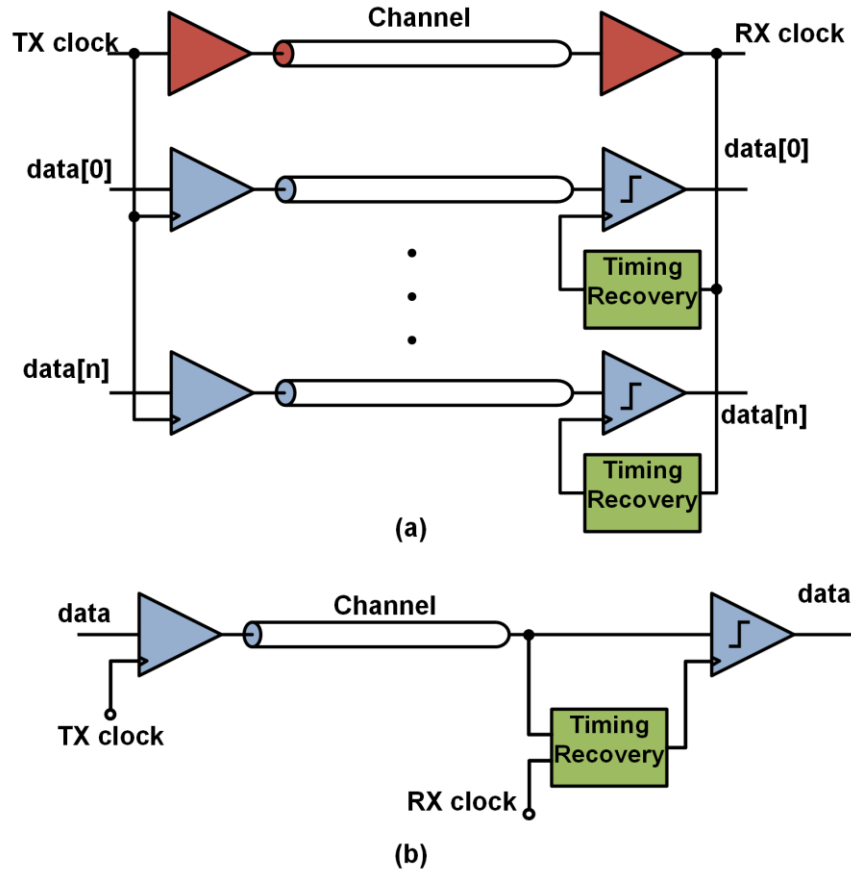


Figure 2.2: (a) Source synchronous (forwarded clock) link. (b) Plesiochronous (embedded clock) link.

As the mesochronous/source-synchronous and plesiochronous styles are most frequently adopted for high-speed interconnect design, they shall be the focus of the discussion here.

In source-synchronous links (Figure 2.2 (a)), the TX transmits its clock on a separate channel along with multiple data channels. The RX uses this forwarded clock as a frequency reference. However, at high data-rates, the inter-signal skew can be a significant percentage of the symbol interval and thus these links need to perform per-pin skew compensation [29] to ensure that data is optimally sampled. The timing recovery circuit receives the forwarded clock and performs jitter filtering and deskewing. Forwarded clock links are used in dense parallel links. Examples of such links include memory interfaces such as DDR3, and chip-to-chip interfaces such as HyperTransport and QuickPath.

In contrast, plesiochronous schemes, shown in Figure 2.2 (b) use independent clock sources in the TX and RX. The TX does not forward a clock and the RX performs its own clock recovery i.e., it uses the timing information embedded in the incoming data to position the sampling clock. It needs to track both the frequency and the phase of the incoming clock. The lower routing overhead makes plesiochronous links popular for communication between add-in cards and over server backplanes (e.g. PCI-Express [30]), which generally have to travel longer distances than the source-synchronous links described previously.

## 2.3 Sub-rate Clocking

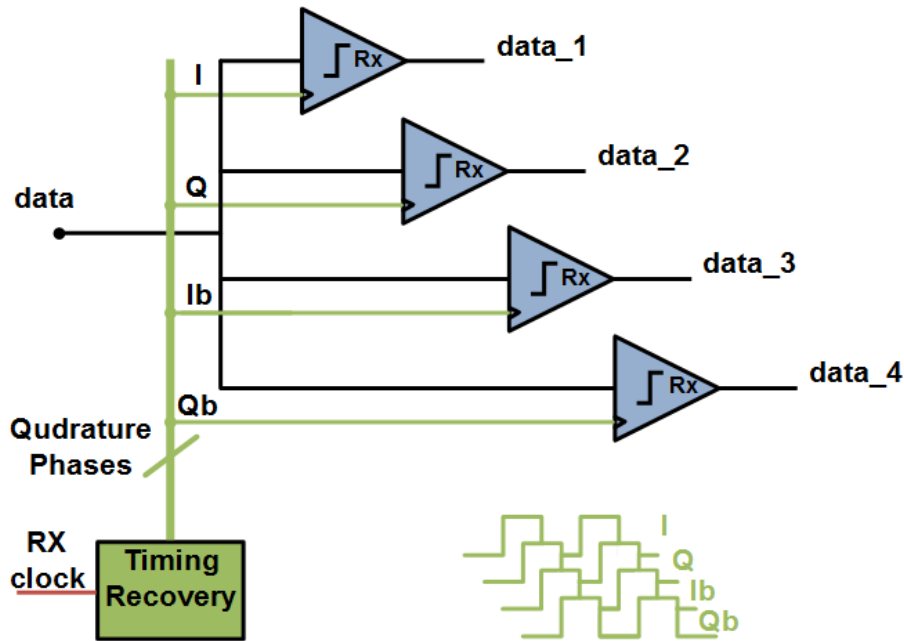


Figure 2.3: Block diagram of a quarter-rate receiver.

At multi-Gb/s data rates, the high-frequency clocks required for a “full-rate” architecture consume large amounts of power and complicate the process of timing recovery. As a result, designers use sub-rate clocking schemes. These are essentially multiplexing/demultiplexing schemes, where the clock operates at some integer fraction of the data rate and the data is transmitted and/or received using multiple phases of a clock period. Although it is, in principle, possible to generate as many phases of the clock as desired and lower the clock rate arbitrarily,

practical concerns typically limit link implementations to half and quarter-rates. Figure 2.3 shows an example of a quarter-rate receiver. The timing recovery circuit generates the quadrature clock from a single phase clock reference (Rx Clock). With increasing data-rates, half-rate and quarter-rate clocking are becoming more prevalent, consequently reliable, low-power quadrature phase generation has become a fundamental building block in high speed transceivers.

## 2.4 Clock Jitter

Jitter can be defined as “short-term variations of a signal with respect to its ideal position in time” (International Telecommunication Union [31]). As clock speeds and communication channels run at higher frequencies, the data UI becomes smaller and smaller. Thus I/O systems become more susceptible to deviation in a clock’s output transition from its ideal position. Excessive jitter can increase the bit error rate (BER) of a communications signal by incorrectly transmitting a data bit stream. Accurate understanding of jitter is necessary for ensuring the reliability of a system. The two major components of jitter are random jitter and deterministic jitter (Figure 2.4).

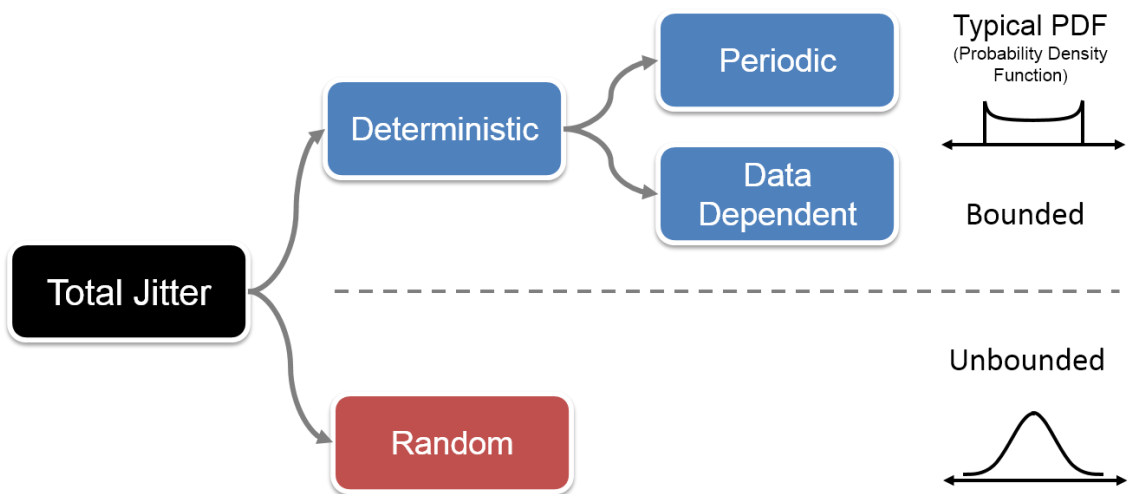


Figure 2.4: Components of jitter.

### **2.4.1 Random Jitter**

Random jitter (RJ) is timing noise that cannot be predicted because it has no discernible pattern. The random component in jitter is due to the noise inherent in electrical circuits and typically exhibits a Gaussian distribution. This noise interacts with the slew rate of signals to produce timing errors at the switching points causing the random jitter. RJ is Gaussian because it results from the composite effects of many uncorrelated noise sources (central limit theorem). Because of its Gaussian distribution, its instantaneous noise value is mathematically unbounded and so it is characterized by its standard deviation (RMS) value.

### **2.4.2 Deterministic Jitter**

Deterministic jitter (DJ) is timing jitter that is repeatable and predictable. It is not intrinsic or random and has a specific source. It is often periodic and narrowband. Sources of DJ are generally related to imperfections in the behavior of a device or transmission media but may also be due to power supply noise, cross-talk, or signal modulation. DJ can be further sub classified into periodic jitter and data-dependent jitter. The example of an interfering noise coming from a switching power supply is periodic because the noise will have the same frequency as the switching power supply. In contrast, an example of data-dependent jitter is intersymbol interference (ISI) caused by an isochronous 8B/10B [32] coded serial data stream. Both types of DJ are linearly additive and always have a specific source i.e. they are correlated to (or caused by) something. This jitter component has a non-Gaussian probability density function and is always bounded in amplitude. DJ is characterized by its bounded, peak-to-peak, value.

## **2.5 Types of Jitter**

There are different types of jitter, based on the techniques used for measuring it. They are described below.

### **2.5.1 Period Jitter**

Period jitter is the deviation in cycle time of a clock signal with respect to the ideal period over a number of cycles. Figure 2.5 shows period jitter measurements P1, P2, and P3 they simply

measure the period of each clock cycle in the waveform. From these measurements the average clock period as well as the standard deviation and the peak-to-peak value can be calculated. The standard deviation and the peak-to-peak value are frequently referred to as the RMS value and the peak-to-peak period jitter, respectively. Period jitter is mostly used in digital systems for calculating timing margins.

## 2.5.2 Cycle-to-Cycle Jitter

Cycle-to-cycle jitter is the difference in a clock's period from one cycle to the next. It is indicated by C1 and C2 in Figure 2.5. It measures how much the clock period changes between any two adjacent cycles. Thus, the cycle-to-cycle jitter can be found by applying a first-order difference operation to the period jitter. Cycle-to-cycle jitter is typically reported as a peak value which defines the maximum deviation between the rising edges of any two consecutive clocks. The cycle-to-cycle jitter measurement is used to determine high frequency jitter in applications as it measures the jitter between two adjacent clock cycles. It is expressed as an RMS (standard deviation) value as well.

It is interesting to note that no knowledge of the ideal edge locations of the reference clock is required in order to calculate either the period jitter or the cycle-to-cycle jitter.

## 2.5.3 Time Interval Error (TIE)

The time interval error (TIE) measures how far each active edge of the clock varies from its ideal position. The TIE is shown in Figure 2.5 by the measurements T1 through T4. For this measurement to be performed, the ideal edges must be known or estimated. As shown in Figure 2.6, TIE may also be obtained by integrating the period jitter, after first subtracting the nominal (ideal) clock period from each measured period. TIE is important because it shows the cumulative effect that even a small amount of period jitter can have over time. TIE measurements are especially useful when examining the behavior of transmitted data streams, where the reference clock is typically recovered from the data signal using a Clock/Data Recovery (CDR) circuit. A large TIE value shows that the CDR circuit is not able to properly track the variation in the incoming data stream. TIE is expressed as an RMS which measures the standard deviation of the timing errors, and peak-to-peak, which measures the difference of the minimum and maximum timing errors.

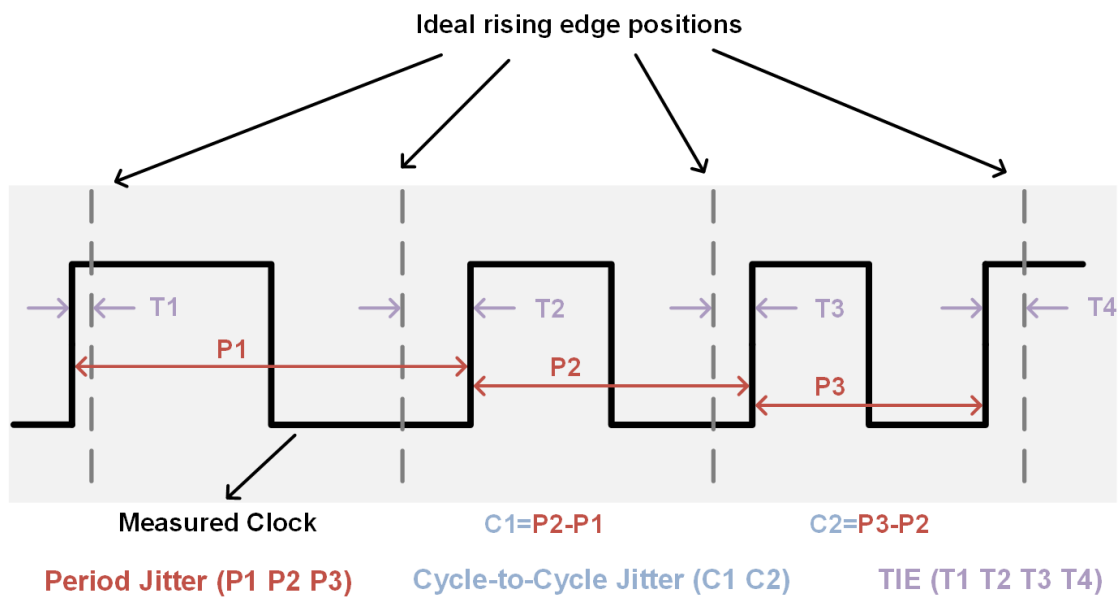


Figure 2.5: Different types of jitter measurements.

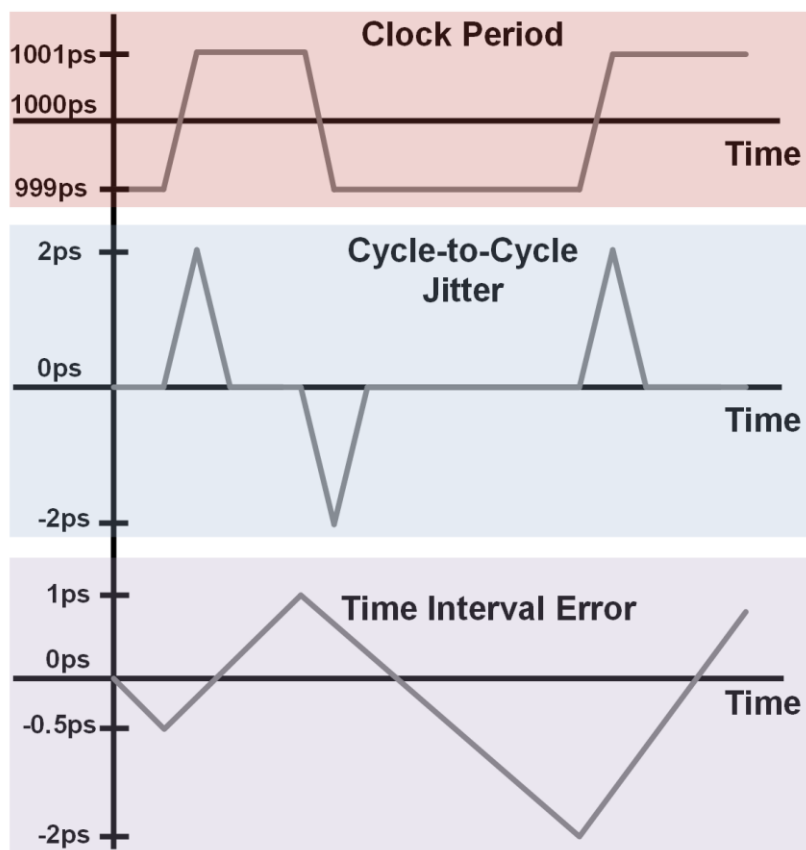


Figure 2.6: Relationship between period, cycle-to-cycle, and TIE jitter.

### 2.5.4 Phase Noise (Integrated RMS Jitter)

Phase noise is measured in the frequency domain, and is a ratio of signal power to noise power normalized to a 1Hz bandwidth at a given offset from the carrier signal. Integrated RMS jitter is measured by integrating the phase noise across specified frequency offsets from the carrier signal. It measures the amount of energy present in the specified frequency offsets from the carrier signal ( $f_c$ ) compared to the energy of the carrier signal by integrating the area under the phase noise plot. It is expressed in seconds. Figure 2.7 shows a phase noise plot for a carrier signal at  $f_c$  and the shaded region between  $f_1$  and  $f_2$  represents the integrated RMS jitter. Mathematically it is defined as

$$\text{RMS Integ. Jitter} = \frac{\sqrt{2 \int_{f_1}^{f_2} 10^{\frac{PN(f)}{10}} df}}{2\pi f_c} \quad (2.2)$$

Integrated RMS jitter proves very useful in I/O design as it can be used to precisely show the effects of jitter addition or jitter filtering by the transmitter or receiver on the reference clock. Different I/O protocols use different frequency offsets to make integrated RMS jitter measurements. As an example, SONET (Synchronous Optical Networking) [33] uses a frequency offset of 12 kHz to 20 MHz from the carrier signal in order to integrate the area under the phase noise plot and measure phase jitter. Fiber Channel [34] uses a frequency offset of 637 kHz to 10 MHz from the carrier signal in order to integrate the area under the phase noise plot and measure phase jitter.

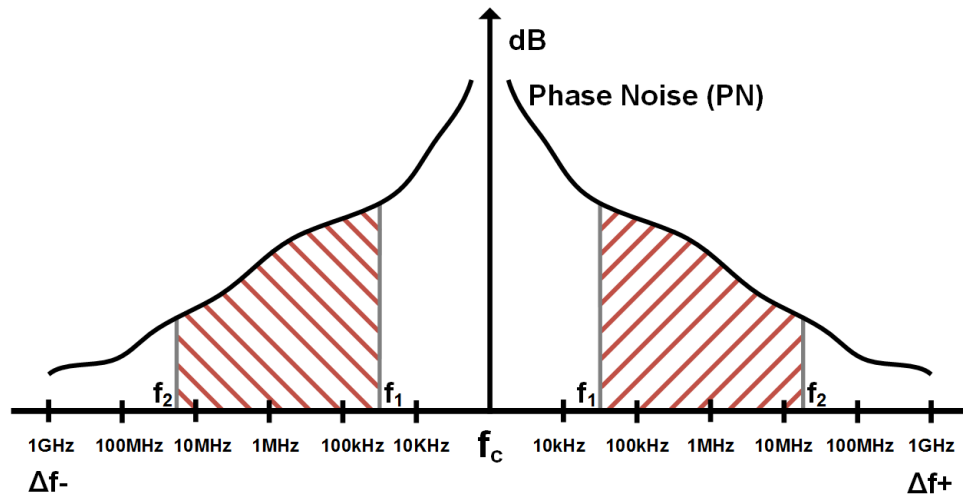


Figure 2.7: Phase noise plot and integrated jitter measurement.

## 2.6 Injection Locking Background

In the multi-gigahertz frequency range, conventional clocking techniques have encountered several design challenges in terms of power consumption, skew and jitter. Injection-locking is a promising technique to address these design challenges for gigahertz clocking. We describe the fundamentals of injection locking dynamics in order to develop a framework for discussion in later chapters.

Oscillator injection locking is a well known and deeply studied phenomenon. 17th century Dutch scientist Christiaan Huygens, noticed that the pendulums of two clocks on the wall moved in unison if the clocks were hung close to each other [35]. He postulated that the coupling of the mechanical vibrations through the wall drove the clocks into synchronization. It has also been observed that humans left in isolated bunkers reveal a “free-running” sleep-wake period of about 25 hours [36] but, when brought back to nature, they are injection-locked to the Earth’s cycle. This phenomenon also occurs in many other biological systems, such as the synchronized flashing of fireflies, the singing of certain crickets, and heartbeat patterns linked to breathing speed. The technique of injection locking has recently gained substantial attention in CMOS communication circuits. Recent applications include quadrature voltage-controlled oscillators (VCOs) [26], frequency dividers [37], frequency multipliers [38], clock recovery [39], and jitter filtering and phase deskew [24].

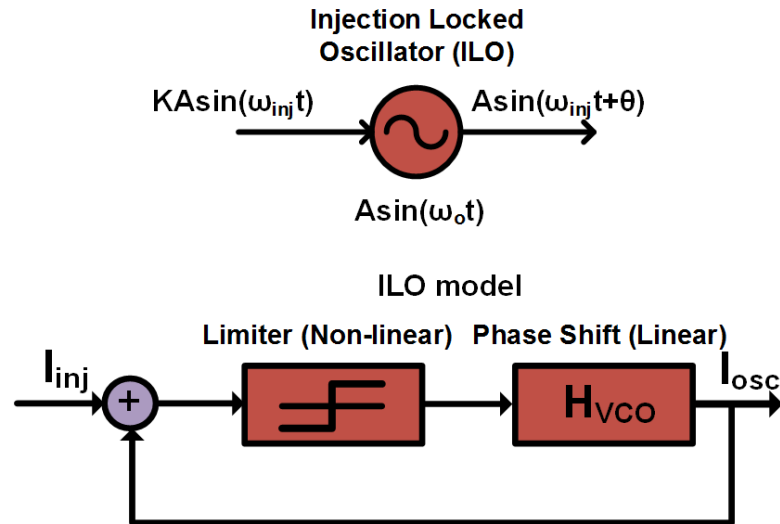


Figure 2.8: Injection locked oscillator.



When an external signal ( $\omega_{inj}$ ) is applied to an oscillator ( $\omega_o$ ), then under the right conditions the latter ceases to be an autonomous circuit and synchronizes to the external signal with a constant phase delay ( $\theta$ ) (Figure 2.8). The conditions under which this happens have been investigated by Adler [40]. Mathematically, the injection locking process can be described by:

$$\frac{d\theta}{dt} = \omega_o - \omega_{inj} - \omega_L \sin(\theta) \quad (2.3)$$

Here  $\omega_L$  is called the locking range. For LC oscillators  $\omega_L$  can be shown to be [41] equal to

$$\omega_L = \frac{\omega_o}{2Q} \times k \quad (2.4)$$

In (2.4)  $Q$  is the quality factor of the LC tank and  $\omega_o$  is the natural frequency of oscillation.  $K$  is the relative injection strength ( $I_{inj}/I_{osc}$ ) (Figure 2.8). For an  $n$  stage ring oscillator  $\omega_L$  can be shown to be [29] equal to

$$\omega_L = \frac{\omega_o}{\left(\frac{n}{2}\right) \sin\left(\frac{\pi}{n}\right)} \times k \quad (2.5)$$

We can analyze (2.3) by its vector fields (Figure 2.9). When  $\omega_L < (\omega_o - \omega_{inj})$  there are no fixed points hence no stable solutions exist. When  $\omega_L > (\omega_o - \omega_{inj})$  there are two fixed points (A and B). Of the two fixed points, the stable point is when  $\theta$  is less than  $\pi/2$  (A) and the other point is unstable in which  $\theta$  greater than  $\pi/2$  (B).

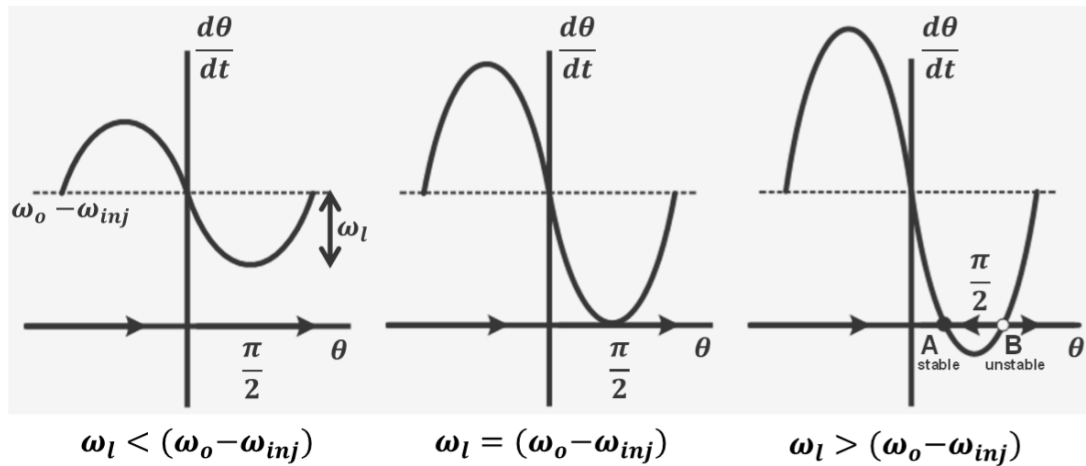


Figure 2.9: Vector field for (2.3).

Within the lock range, the steady state output frequency will always track the injected frequency and the phase difference between the injected and ILO output becomes constant.

$$\theta = \sin^{-1} \left( \frac{\omega_o - \omega_{inj}}{\omega_L} \right) \quad (2.6)$$

As (2.6) suggests, for small frequency offsets the phase shift is approximately linear with respect to  $(\omega_o - \omega_{inj})$ . This property is utilized for ILO-based clock phase shifting or deskewing.

The transient phase response of the ILO can be obtained by integrating (2.3) with respect to time:

$$\theta = 2 \tan^{-1} \left[ \frac{\omega_L}{\omega_o - \omega_{inj}} - \frac{\omega_b}{\omega_o - \omega_{inj}} \tanh \left( \frac{\omega_b t}{2} \right) \right] \quad (2.7)$$

where

$$\omega_b = \sqrt{\omega_L^2 - (\omega_o - \omega_{inj})^2} \quad (2.8)$$

(2.7) although accurate, gives limited intuition. To gain more insight we linearize (2.3) around the stable point  $\theta_o$ . From (2.6) we have  $\sin(\theta_o) = (\omega_o - \omega_{inj}) / \omega_L$ . We replace  $\theta$  with  $\theta_o + \theta_n$  given  $\theta_n \ll \theta_o$ . Here  $\theta_n$  is the time varying component. Thus (2.3) becomes

$$\frac{d(\theta_o + \theta_n)}{dt} = \omega_o - \omega_{inj} - \omega_L \sin(\theta_o + \theta_n) \quad (2.9)$$

Noticing that the derivative of  $\theta_o$  is 0, (2.9) can be further simplified to:

$$\frac{d\theta_n}{dt} = \omega_o - \omega_{inj} - \omega_L \sin(\theta_o) \cos(\theta_n) - \omega_L \sin(\theta_n) \cos(\theta_o) \quad (2.10)$$

As  $\theta_n$  is small we set  $\cos(\theta_n) = 1$  and  $\sin(\theta_n) = \theta_n$  in (2.10):

$$\frac{d\theta_n}{dt} = \omega_o - \omega_{inj} - \omega_L \sin(\theta_o) - \omega_L \theta_n \cos(\theta_o) \quad (2.11)$$

Replacing  $\sin(\theta_o) = (\omega_o - \omega_{inj}) / \omega_i$  we have

$$\frac{d\theta_n}{dt} = -\omega_L \theta_n \cos(\theta_o) \quad (2.12)$$

Using (2.6) and (2.8) we can show that

$$\frac{d\theta_n}{dt} = -\omega_b \theta_n \quad (2.13)$$

(2.13) is a first order response. Thus, ILOs are functionally equivalent to a first order PLL [37] where input phase noise is low pass filtered. Therefore in the frequency domain we can write this relationship as

$$JTF_{in} = \frac{Jitter(s)_{input}}{Jitter(s)_{output}} = \frac{1}{1 + \frac{s}{\omega_b}} \quad (2.14)$$

In a similar manner to a PLL, corresponding VCO noise is high pass filtered:

$$JTF_{VCO} = \frac{Jitter(s)_{vco}}{Jitter(s)_{output}} = \frac{\frac{s}{\omega_b}}{1 + \frac{s}{\omega_b}} \quad (2.15)$$

In totality, if  $S_{inj}$  is the phase noise of the injected signal and  $S_{VCO}$  is the phase noise of the VCO, then the phase noise of the locked output  $S_{out}$  (assuming  $S_{inj}$  and  $S_{VCO}$  are uncorrelated) can be given as

$$S_{out} = |JTF_{in}|^2 S_{inj} + |JTF_{VCO}|^2 S_{VCO} \quad (2.16)$$

Figure 2.10 shows the typical phase noise ( $S_{out}$ ) of the locked output for given  $S_{inj}$  and  $S_{VCO}$ . For frequencies below the  $JTF_{in}$  (2.14) bandwidth (typically very high: hundreds of MHz [17])  $S_{out}$  follows the phase noise of the reference ( $S_{inj}$ ), and for frequencies beyond the  $JTF_{in}$  bandwidth it follows the phase noise of the VCO ( $S_{VCO}$ ). This proves useful for forwarded clock parallel links where the presence of a low phase noise clock reference allows for ‘clean’ clock generation by injection locked based timing recovery.

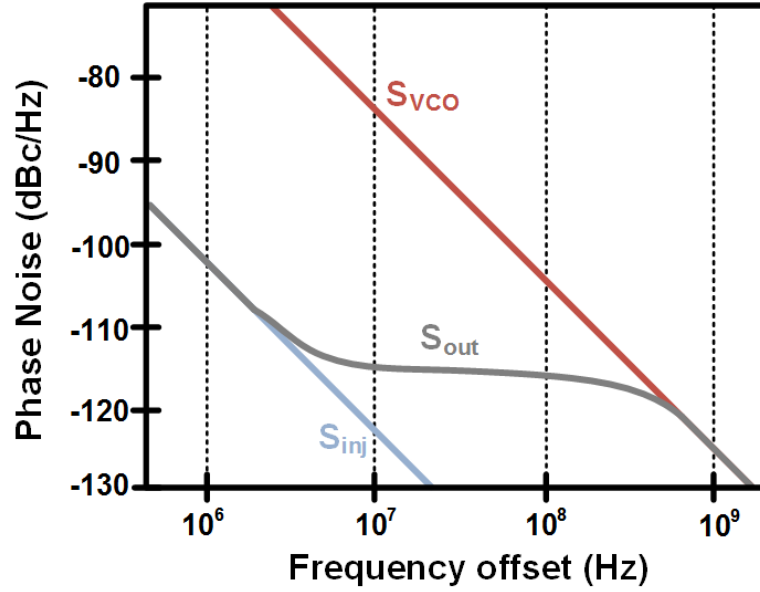


Figure 2.10: Phase noise of the injected output as a function of the phase noise of VCO and input signals.

The first order nature of injection locking proves very useful as it ensures no peaking and guarantees stability. This makes the design of injection locking based circuits very simple compared to design of a PLL. However, injection locking is inherently a narrowband process. The locking range ( $\omega_L$ ) is typically very small. (2.4) and (2.5) may suggest that  $\omega_L$  can be increased indefinitely by simply increasing the injection strength ( $k$ ), but it should be noted that (2.4) and (2.5) are accurate for weak injection ( $k \ll 1$ ), at higher injection strengths the relationship between  $\omega_L$  and  $k$  becomes much weaker [41]. Hence, even with strong injection, ring and LC oscillators typically have a maximum locking range of 10% [23] [24]. This makes injection locking less suitable for wideband application. In addition this also makes system prone to (process, voltage and temperature) PVT variations.

In this dissertation we propose two architectures that tackle this issue. The two techniques relate to two kinds of oscillator common in today's CMOS designs; LC oscillators and ring oscillators.

## 2.7 VCSEL based Optical Transmitter

The rapid scaling of CMOS technology continues to increase the processing power of microprocessors and the storage volume of memories. This increases the need for high

bandwidth interconnection between chips, which can be achieved by employing large numbers of inputs and outputs (IOs) per chip as well as high data rates per IO. As microprocessor system interface data rates have grown, the electrical channel has started to hamper performance. To alleviate this bottleneck, microprocessor interfaces have adopted advanced equalization techniques such as linear equalization, DFE, and optimized interconnect topologies. The power and area overhead associated with equalization make it difficult to achieve target bandwidth with a realistic power budget. A promising solution to the I/O bandwidth problem is the use of optical inter-chip communication links. This section gives an overview of the key optical link component, namely, the optical transmitter.

Multi-Gb/s optical links exclusively use coherent laser light due to its low divergence and narrow wavelength range. Modulation of this laser light is possible by directly modulating the laser intensity through changing the laser's electrical drive current. A popular coherent laser light source used in optical transmitters is the vertical-cavity surface-emitting laser (VCSEL).

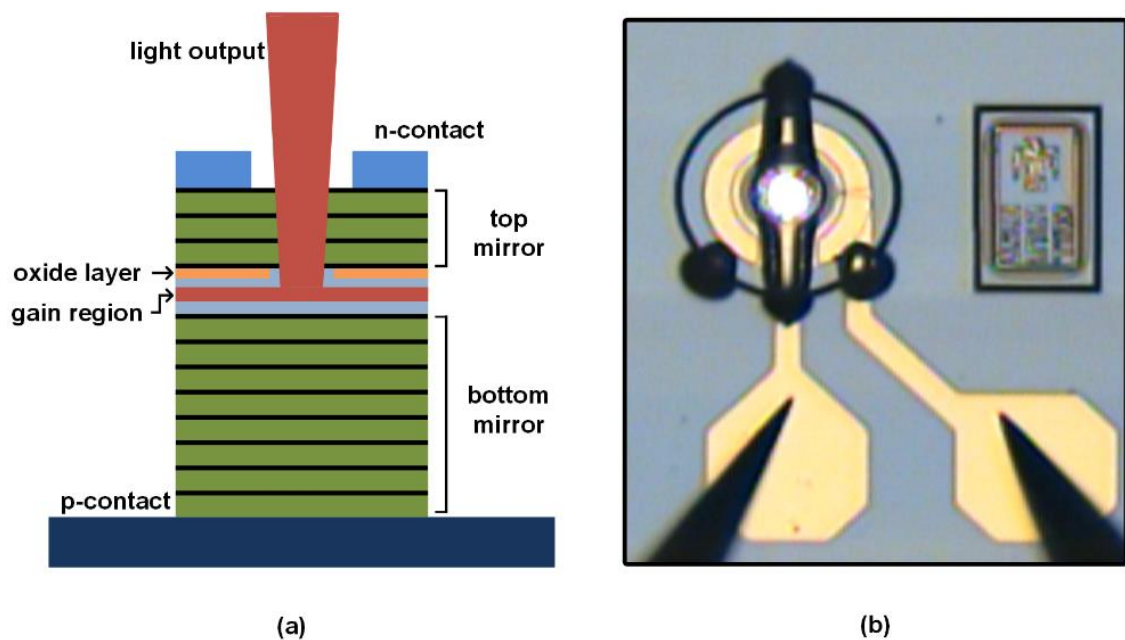


Figure 2.11: (a) Cross-section of a VCSEL. (b) Die micrograph of a VCSEL.

A VCSEL is a semiconductor laser diode which emits light perpendicular to its top surface (Figure 2.11). VCSELs have important practical advantages compared with edge-emitting semiconductor lasers. They can be tested and characterized directly after growth, i.e. before the wafer is cleaved. Furthermore, it is possible to combine a VCSEL wafer with an array of optical

elements (like collimator lenses) and then dice the composite wafer instead of mounting the optical elements individually for each VCSEL. This allows for low cost mass production of laser products. The most common emission wavelengths of VCSELs are in the range of 750-980nm [42] [43], as obtained with the GaAs/AlGaAs material system. While VCSELs appear to be an ideal source due to their ability to both generate and modulate light, they also suffers from some serious bandwidth limitations.

As shown in Figure 2.12, a VCSEL emits optical power that's a linear function of the current flowing through the device once a threshold current,  $I_{th}$ , is reached and stimulated emission, or lasing, occurs. As the threshold current magnitude is a function of the active area current density, it is often reduced by confining the current with an oxide aperture. Typical values of  $I_{th}$  vary from 0.5mA to 1mA [44]. Once the VCSEL begins lasing, the optical output power is related to the input current by the slope efficiency  $\eta$  (typically 0.3-0.5mW/mA), and a high contrast ratio between a logic "one" signal and a logic "zero" signal can be achieved by placing the "zero" current value near threshold. While a low "zero" level current allows for high contrast, a speed limitation does exist due to the VCSEL bandwidth being a function of the device current.

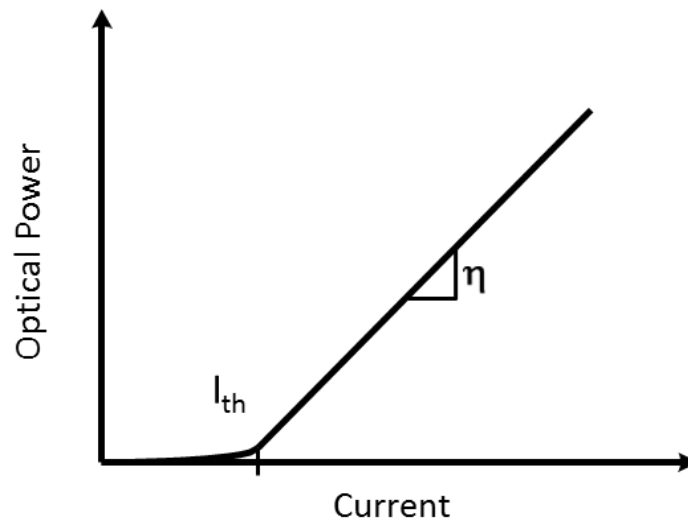


Figure 2.12: VCSEL L-I curve.

VCSEL has inherent bandwidth limitations. Its bandwidth is limited by a combination of electrical parasitics and the electron-photon interaction described by a set of second-order rate equations. Figure 2.13 shows the small-signal ac response of the VCSEL for different bias currents [45]. The modulation characteristics varies as the bias current changes. This dependence

of the VCSEL bandwidth on its bias current makes its modulation response highly non-linear. This is markedly different from the response of an electrical channel which is linear. The details of VCSEL response modelling and non-linearity will be discussed in Chapter 6.

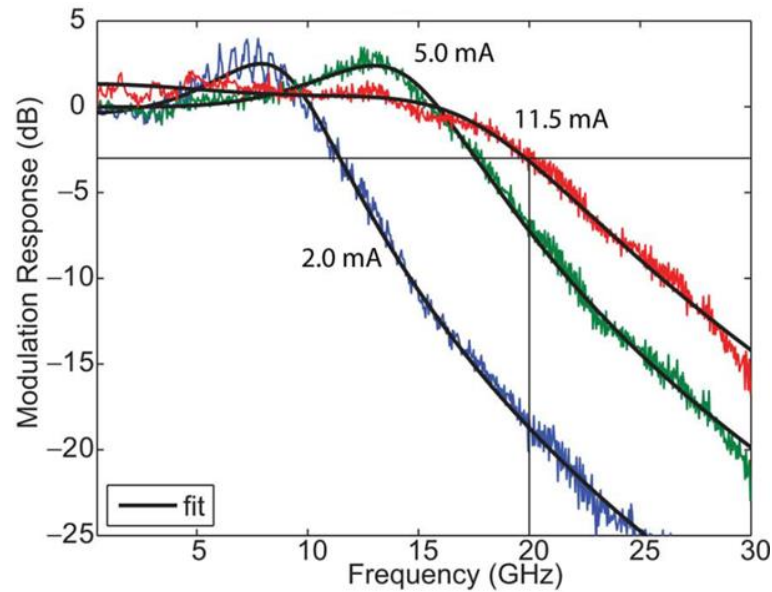


Figure 2.13: VCSEL bandwidth limitations.

Current-mode drivers are typically used to modulate VCSELs due to the direct relationship between drive current and optical output power (Figure 2.14). A typical VCSEL output driver is shown in Figure 2.14, with a differential stage steering current between the optical device and a dummy load, and an additional static current source used to bias the VCSEL sufficiently above the threshold current in order to ensure adequate bandwidth. Often the output stage uses a separate higher voltage supply due to typical VCSEL diode knee voltages (typically 1.7V) exceeding normal CMOS supplies. As data rates scale, designers have begun to implement transmitter equalization circuitry to compensate for VCSEL bandwidth constraints. A VCSEL equalization technique that takes into account the inherent non-linearity in its high speed response, will be introduced in Chapter 6.

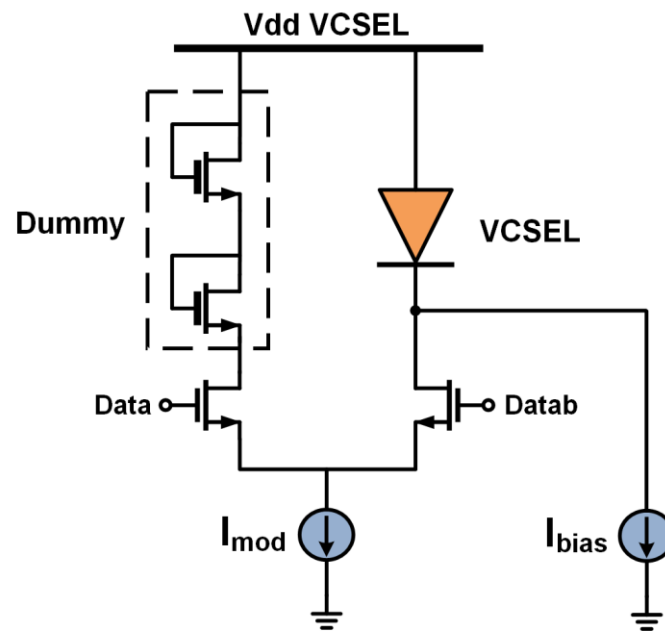


Figure 2.14: Current-mode VCSEL driver.



# Chapter 3: Wideband Injection

## Locking Scheme and Quadrature

### Phase Generation in LC Oscillator

Injection-locked-oscillators (ILOs) have been used in many wireline receivers because of their simple implementation and instantaneous locking characteristics. However, their application is hindered by their limited locking range compared with alternative techniques such as phase-locked-loops (PLLs). Recent standards [46] require operation with data rates that span more than 10% of the nominal frequency. Therefore transceivers must operate reliably over this range. A large locking range is also desirable to counter the inevitable PVT variations in modern scaled technologies.

The injection range of an LC ILO is inversely proportional to  $Q$  of the tank [41]. To this reason low- $Q$  tanks have been used [24] to increase the locking range in an LC ILO, but this comes at the expense of higher power consumption, as shown in Figure 3.1. Intricate frequency-tracking mechanisms such as reference PLL have also been used to set the oscillator's natural frequency so that it is within the injection range of the reference clock [39]. This adds additional design complexity and an area/power penalty to the otherwise simple circuit, thus offsetting the merits of injection-locked based system.

Another important requirement of wireline receivers that employ half-rate and quarter-rate architectures is the generation of accurate quadrature phases. Injection-locked LC dividers have been frequently used for generating quadrature phases [25]. But they require complementary clocks at twice the desired frequency, which tends to be power inefficient. Quadrature phase generation from a single phase of clock without any frequency division is highly desirable for half-rate and quarter-rate CDR architectures.

We propose a method for wideband injection locking in an LC oscillator that maintains the simplicity of an injection locked system. We also describe an extension of this method to produce

quadrature phases from a single reference clock without any frequency division. The system has a wide jitter tracking bandwidth, which makes it useful for forwarded clock receivers [17].

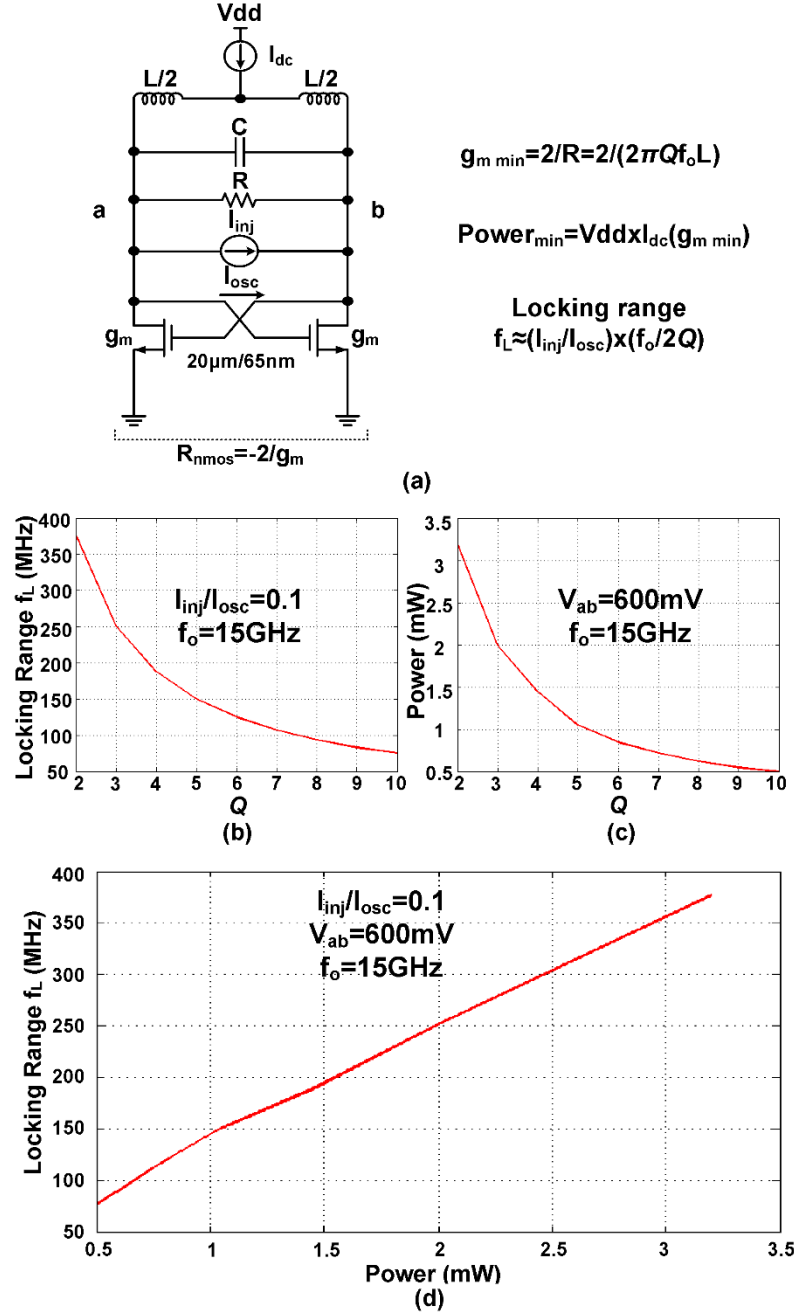


Figure 3.1: (a) LC oscillator with injection. (b) Variation of locking range with  $Q$  for a constant injection strength of 0.1. (c) Variation of power consumption with  $Q$  for a constant oscillation amplitude of 600 mV. (d) Improvement in locking range vs. power consumption for a constant injection strength and oscillation amplitude (Simulation).

This chapter is organized as follows. Section I describes the system architecture. Section II presents a mathematical analysis describing the dynamics of the system. Measurement results are presented in Section III. Finally, Section IV summarizes the work and presents the conclusions.

### 3.1 System Architecture

Figure 3.2(a) shows the simplified block diagram of the proposed system. It consists of three basic elements, namely VCO, mixer and buffer. The buffered VCO output is mixed with the input reference and the resultant signal is fed back to the VCO to complete the feedback architecture.

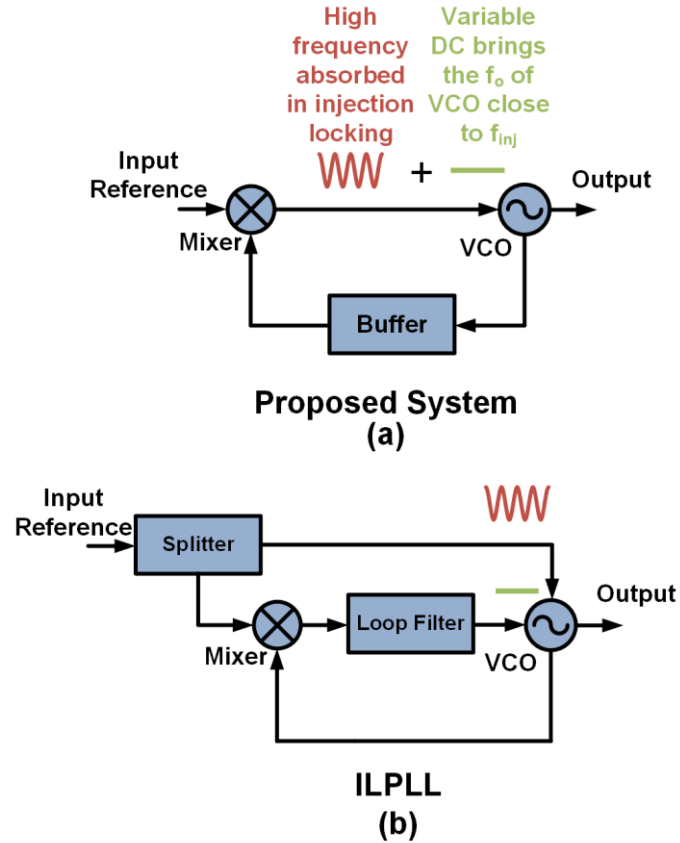


Figure 3.2: Block diagram of (a) proposed system and (b) Injection locked phase locked loop (ILPLL).

### 3.1.1 Comparison with ILPLL

In the locked state, an ILO can be modeled as a first order PLL [37]. A first-order PLL comprises of a VCO, a mixer and a low pass filter. In this work we propose to eliminate the loop filter altogether. The resultant high frequency component of the mixer is used to perform injection locking. This is different from an ILPLL structure (Figure 3.2(b)), which consists of a full PLL with additional injection in the VCO to improve its phase noise characteristics. Additionally, unlike the ILPLL, both IL and PLL actions are performed at the same node using common mode injection in the varactors.

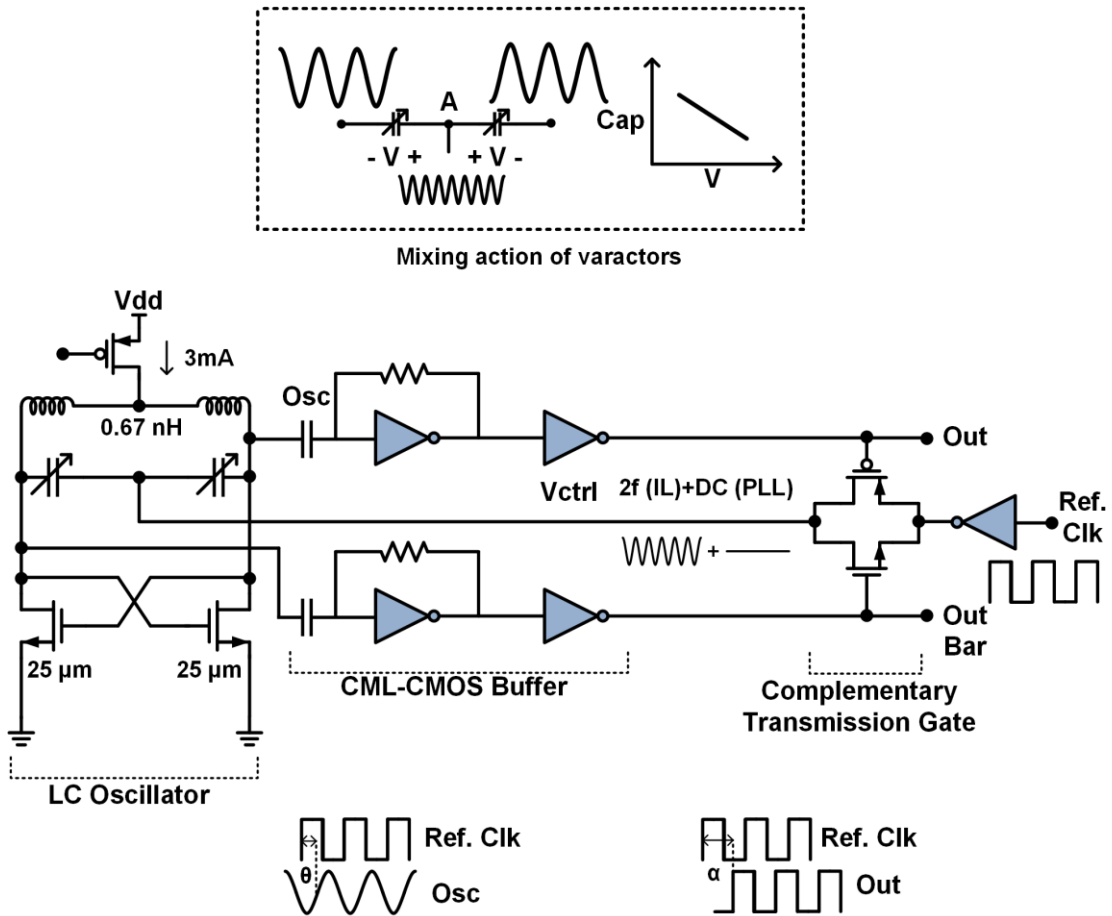


Figure 3.3: Schematic of the proposed system. The input to the common mode of the varactors contains  $2f$  and DC components. The DC component brings the natural frequency close to the frequency of the reference clock and the  $2f$  component does the injection lock.

### 3.1.2 Common Mode Injection

In most LC oscillators, the control voltage of the varactor is used to set the frequency of oscillation,  $f_o$ . In such architectures the instantaneous voltage oscillation at the output node results in transient changes in the capacitance (Figure 3.3). Due to this effect, the voltage of the common-node A has an extra frequency component at  $2f_o$  [47]. Similarly, if we inject a  $2f_o$  component at the varactors' common node, then the mixing action of the varactors will inject a current at  $f_o$  into the tank. However, such a circuit will constitute a frequency divider, which is not desirable in many applications. We will describe the basic principles of the proposed architecture that avoids such a division and provides a very wide locking range.

### 3.1.3 Implementation Details

Figure 3.3 shows the basic schematic of the proposed wideband injection locking system. A complementary transmission gate is used as a single balanced passive mixer. The output of the LC oscillator is buffered by the CML to CMOS stage. The transmission gate is driven by the outputs of the buffer and the reference clock is used as the input. The output of the transmission gate is directly fed to the varactors in the LC oscillator, thereby completing the loop.

### 3.1.4 System Analysis in Locked State

In the locked state the output of the transmission gate contains a high frequency  $2f$  component and a DC component. The value of the DC component is determined by the phase difference between the reference and buffer output ( $\alpha$ ) and is proportional to  $\cos(\alpha)$  (Figure 3.4(d)). The phase difference between the oscillator output and the injected clock ( $\theta$ ) is given by [41]:

$$\sin(\theta) = (\omega_o - \omega_{inj})/\omega_L \quad (3.1)$$

Assuming a constant delay,  $\Delta_o$ , through the CML to CMOS buffer, the phase difference between the clock and buffer output  $\alpha$  is given by

$$\alpha = \theta + \Delta_o \times (2\pi f_{inj}) \quad (3.2)$$

Therefore the DC component of the switch output is dependent on  $\theta$ . In the unlocked state, the DC component brings the  $f_o$  close to  $f_{inj}$  (PLL action) and the  $2f_{inj}$  component performs the

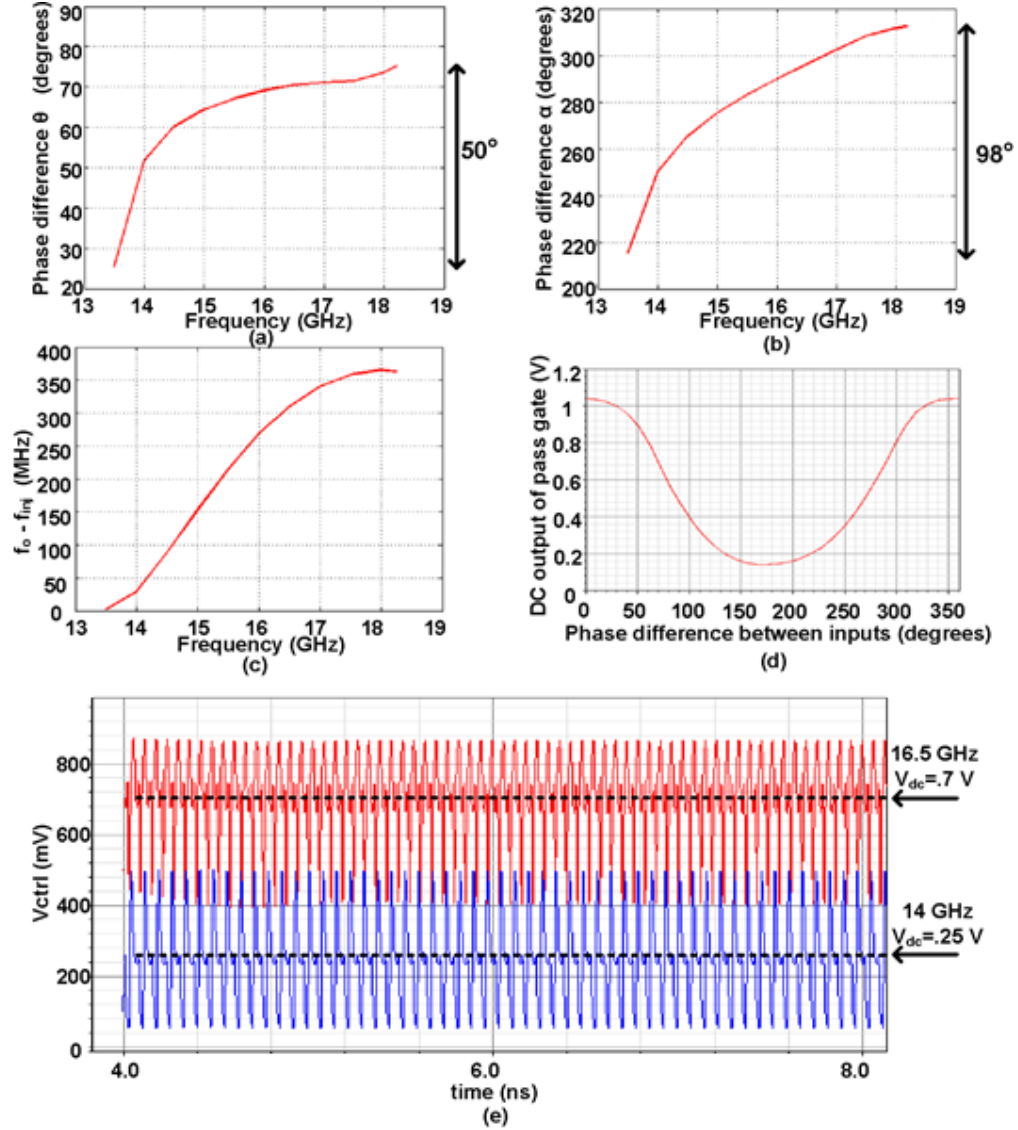


Figure 3.4: Simulation results, (a)  $\theta$  vs. ref. frequency, (b)  $\alpha$  vs. ref. frequency, (c)  $f_o - f_{inj}$  vs. ref. frequency, (d) DC characteristic of the transmission gate, (e)  $V_{ctrl}$  at 14 GHz and 16.5 GHz clock reference.

injection lock. Thus the phase difference  $\theta$  becomes dependent on the reference frequency, which enables wideband locking. Figure 3.4(e) shows the simulated varactor control voltages under locked conditions for two frequencies (14 GHz and 16.5 GHz). The DC levels are different and are overridden by the corresponding  $2f_{inj}$  components.

Figure 3.4(a) shows the simulated oscillator output phase difference ( $\theta$ ) versus input frequency.  $\theta$  is smaller at lower frequencies and it increases as frequency increases. This is in

accordance with the DC characteristic of the transmission gate (Figure 3.4(d)) and phase difference between the CML to CMOS output and the reference clock ( $\alpha$ ). The fact that CML to CMOS buffers add a constant delay across all frequencies helps increase the injection range as it amplifies the phase shift when frequency increases (2). This helps the switch output to cover the entire voltage range (0-V<sub>dd</sub>), as shown in Figure 3.4(d).

It is important to clarify that the proposed work achieves wider locking range due to the PLL like loop which brings the center frequency of the oscillator within the injection range automatically. The inherent properties of a VCO only system like injection range and jitter tracking bandwidth remain intact and are still a function of the  $Q$  of the oscillator. Our unique methodology alleviates the need to use a loop filter so that the system can have a high jitter tracking bandwidth.

### 3.1.5 Quadrature Phase Generation

For quadrature phase generation a secondary matched LC oscillator is coupled to the primary in a QVCO configuration. Figure 3.5 shows the schematic of quadrature phase generation circuit. Anti-phase coupling is achieved using PMOS differential pairs. The strength of the coupling is controlled by varying the tail current of the PMOS differential pair. A coupling factor of above 25% was used to provide sufficient oscillation reliability [48].

The control voltage of the secondary is generated from the output of the transmission gate after sending it through a passive low pass filter, consisting of two RC sections in series with  $R=1\text{ k}\Omega$  and  $C=80\text{ fF}$ . The passive filter is chosen to reduce power consumption and values of RC are chosen to have a 3dB bandwidth of 1 GHz, which provides more than 50dB of attenuation to the  $2f$  component and allows the DC component to pass through. This has two effects. Firstly it allows both oscillators to have the same  $f_0$  and secondly it ensures that there is no coupling between them through the varactors' common mode. A two stage RC section is chosen for more efficient isolation as it provides sharper (-40dB/dec) attenuation without slowing down the feedback loop, as the 3dB bandwidth doesn't need to be too small. This isolation is important for generating accurate quadrature phases as it ensures that coupling between primary and secondary oscillators is solely anti-phase through the PMOS differential pairs and there is no in-phase coupling through the varactors. If not attenuated, in-phase coupling would force the phases of the oscillators to be aligned.

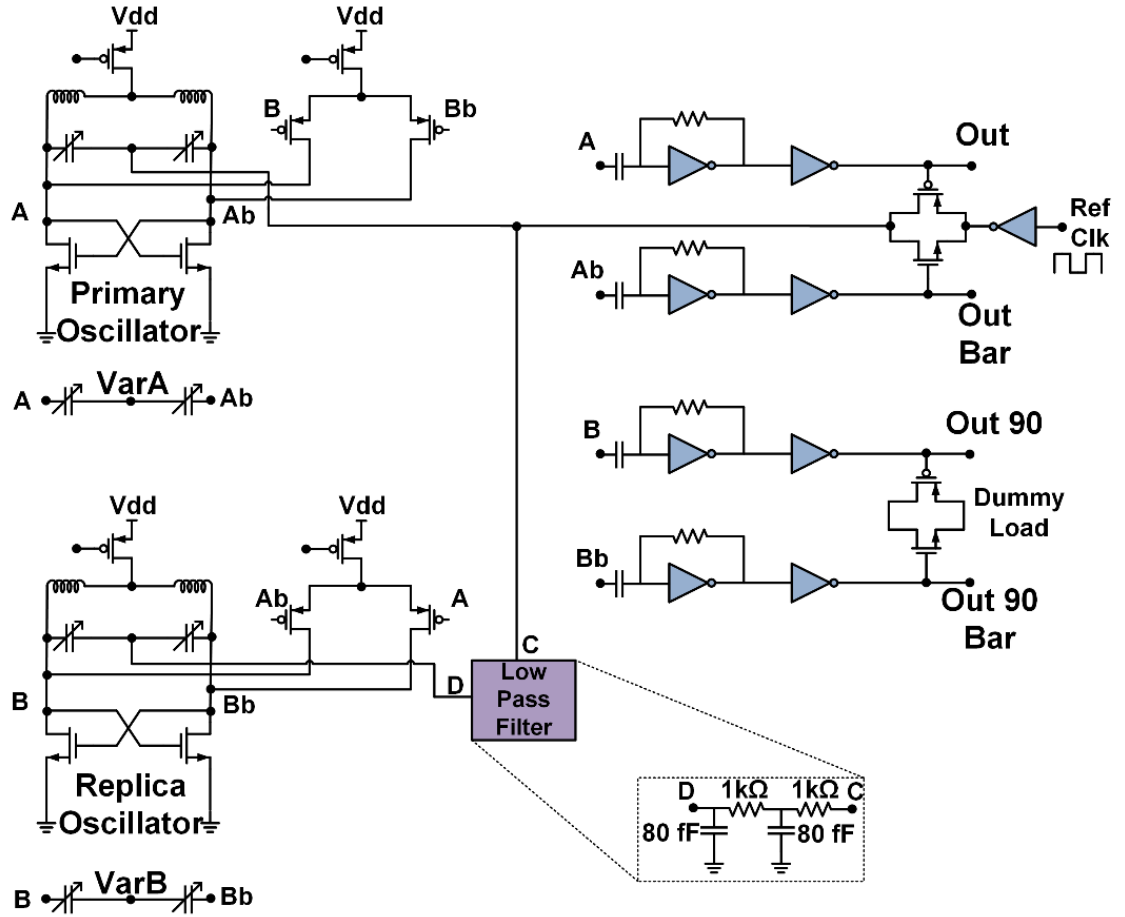


Figure 3.5: Schematic of the proposed system for quadrature phase generation.

ILOs have been frequently used for clock de-skewing applications [24]. (3.1) Suggests that the phase of the output clock can be varied by changing the  $f_o$  of the oscillator. In our architecture the phase of the replica oscillator can be adjusted by changing the bias of secondary varactors VarA and VarB, which are chosen to be more than seven times smaller than the main varactors (Figure 3.5). Secondary varactors are controlled externally and are not a part of the loop. Thus sizing of the secondary varactors present a trade-off between de-skew range and locking range. Sizes of the secondary varactors were kept much smaller than primary varactors so that locking range is minimally altered. To provide sufficient de-skew the control voltages of VarA and VarB were altered in opposite direction. This phase controllability is also imperative for clock receiver application, where exact quadrature phases may not be required due to polarized-mode dispersion effects [49].



## 3.2 Mathematical Analysis

In this section we propose a mathematical model of our system and derive the new effective locking range. To simplify the analysis we delink the IL and PLL aspects of our design. Figure 3.6 shows both IL and PLL characteristics. Injection is modeled as an additive input. The output tracks the input ( $\omega_{inj}$ ) except for a phase difference  $\theta$ , which may be time varying. The PLL part of the system consists of a mixer with a gain of  $\gamma$  and a constant delay of  $\Delta_o$ . Mixer has inputs from the reference clock and the delayed version of the LC oscillator output. The output of the mixer goes to the common mode of the varactors which through its mixing action converts it to equivalent injection at  $\omega_{inj}$ .

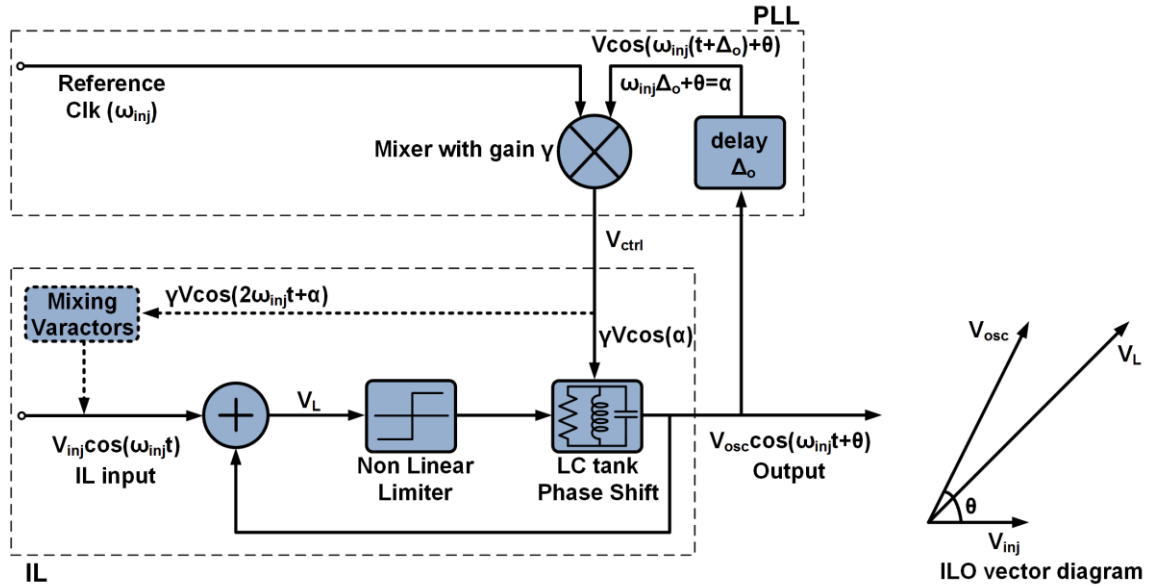


Figure 3.6: System level block diagrams showing injection and PLL feedbacks.

The injection locking dynamics for weak injection  $V_{osc} \gg V_{inj}$  are governed by the famous Adler's equation [40]:

$$\frac{d\theta}{dt} = \omega_o - \omega_{inj} - \omega_L \sin(\theta) \quad (3.3)$$

Here  $\omega_L$  is the locking range defined as

$$\omega_L = \frac{\omega_o}{2Q} \times \frac{V_{inj}}{V_{osc}} \quad (3.4)$$

To take into account the PLL action we replace  $\omega_o$  by  $\omega_o + K_{vco} * V_{ctrl}$ :

$$\frac{d\theta}{dt} = \omega_o + K_{vco} V_{ctrl} - \omega_{inj} - \omega_L \sin(\theta) \quad (3.5)$$

where

$$V_{ctrl} = \gamma V \cos(\alpha) + \gamma V \cos(2\omega_{inj}t + \alpha) \quad (3.6)$$

However we have already taken the  $2\omega_{inj}$  component into account in form of injection so we are left with

$$\frac{d\theta}{dt} = \omega_o + K_{vco}\gamma \cos(\theta + \omega_{inj}\Delta_o) - \omega_{inj} - \omega_L \sin(\theta) \quad (3.7)$$

To make (3.7) comparable to Adler's equation we modify it to have only a single sinusoid:

$$\frac{d\theta}{dt} = \omega_o - \omega_{inj} - [\{\omega_L + K_{vco}\gamma \sin(\omega_{inj}\Delta_o)\} \sin(\theta) - K_{vco}\gamma \cos(\theta) \cos(\omega_{inj}\Delta_o)] \quad (3.8)$$

where

$$K_{vco}\gamma = K_{vco}\gamma V \text{ and } \alpha = \theta + \omega_{inj}\Delta_o \quad (3.9)$$

We therefore have

$$\begin{aligned} \frac{d\theta}{dt} &= \omega_o - \omega_{inj} - \omega_{Lnew} \{\sin(\theta) \cos(\emptyset) - \sin(\emptyset) \cos(\theta)\} \\ &= \omega_o - \omega_{inj} - \omega_{Lnew} (\sin(\theta - \emptyset)) \end{aligned} \quad (3.10)$$

Defining

$$\tan(\emptyset) = \frac{K_{vco}\gamma \cos(\omega_{inj}\Delta_o)}{\omega_L + K_{vco}\gamma \sin(\omega_{inj}\Delta_o)} \quad (3.11)$$

$$\omega_{Lnew} = \sqrt{K_{vco}^2 + \omega_L^2 + 2\omega_L K_{vco} \sin(\omega_{inj} \Delta_o)} \quad (3.12)$$

In locked state  $d\theta/dt = 0$ , so for a real solution,

$$\left| \frac{\omega_o - \omega_{inj}}{\omega_{Lnew}} \right| = |\sin(\theta - \phi)| \leq 1 \quad (3.13)$$

$$|\omega_o - \omega_{inj}| \leq |\omega_{Lnew}| \quad (3.14)$$

Thus the new effective locking range is  $\omega_{Lnew}$ . It can be inferred from (3.11) that for all values of  $\Delta_o$ , such that

$$\Delta_o < \frac{\pi}{\omega_{inj}} \quad (3.15)$$

$\omega_{Lnew}$  will be greater than  $\omega_L$ , and hence the improvement in locking range. For a maximum reference frequency of 18 GHz, the upper limit of  $\Delta_o$  is 27.7 ps.

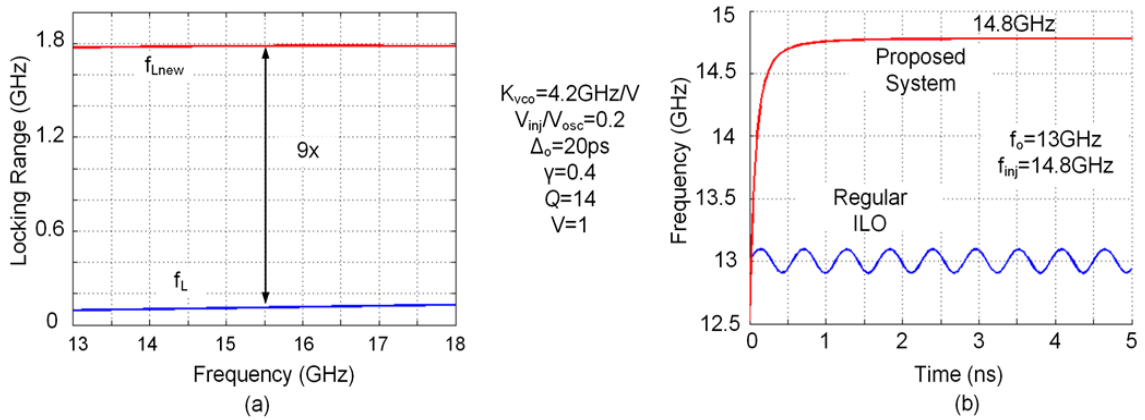


Figure 3.7: New locking range  $f_{Lnew}$  and regular locking range  $f_L$ . (b) Transient solutions to proposed system (3.7) and regular ILO (3.3).

Figure 3.7(a) shows a plot of the new locking range  $f_{Lnew}$  and the regular locking range  $f_L$  based on (3.12) and (3.4) respectively. It predicts an average new locking range of 1.8GHz which is a 9 fold improvement over that of a regular injection locked LC oscillator. To further examine the system, a simulink based behavioral model was designed. Using the same, transient solutions to (3.3) and (3.7) were calculated for the case where the oscillator natural frequency ( $f_o$ ) is 13GHz and injected frequency ( $f_{inj}$ ) is 14.8GHz. Figure 3.7(b) clearly shows that our proposed system

locks to the injected frequency because of its extended locking range whereas the regular ILO fails to do so as the injected frequency is well beyond its locking range.

Spectre based simulations reveal a single sided locking range ( $f_{L_{new}}$ ) of 1.7GHz, 1.8GHz and 2.1GHz for the reference frequencies 13GHz, 15GHz, and 17GHz respectively. Comparing the simulation results with the predictions of our mathematical model (Figure 3.7(a)) reveal a locking range mismatch of -0.1GHz, 0GHz, and 0.3GHz at 13GHz, 15GHz, and 17GHz respectively. Mismatch can be attributed to the fact that the simple mathematical model does not take into account the variation of parameters like  $K_{vco}$  and  $Q$  with frequency.

Figure 3.8 shows the behavior of  $f_{L_{new}}$  with variation in  $\Delta_o$ . Initially  $f_{L_{new}}$  increases as  $\Delta_o$  increases but as  $\Delta_o$  increases to 30ps,  $f_{L_{new}}$  starts decreasing. This clearly shows that there is an optimum  $\Delta_o$  for maximum locking range. We choose  $\Delta_o$  to be 20ps, to maximize the locking range.

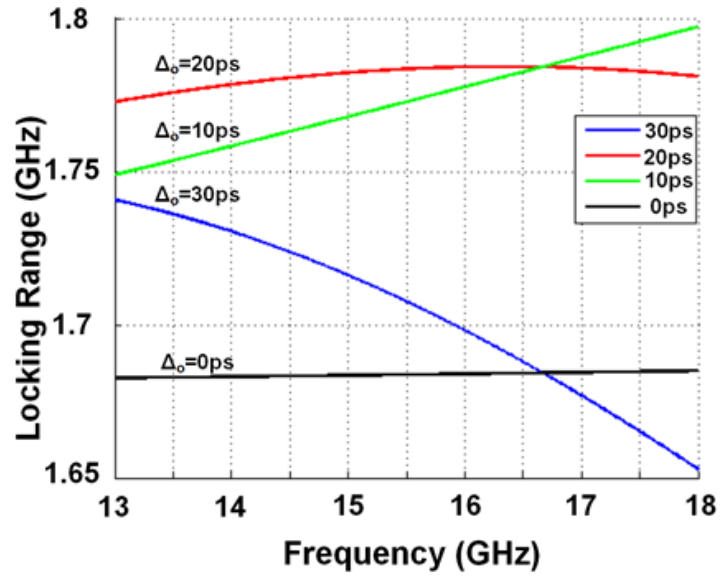


Figure 3.8: Variation of  $f_{L_{new}}$  with  $\Delta_o$ .

(3.10) suggests the dynamics of the proposed system are similar to those of the injection locked VCO only system, as described by Adler's equation (3.3). Jitter tracking bandwidth of a simple ILO is proportional to its locking range ( $\omega_L$ ), as derived in [24]:

$$BW = \omega_L \frac{K + \cos(\theta)}{(1 + K \cos(\theta))^2} \quad (3.16)$$

where  $K$  is the injection strength.

Thus the proposed system has a similar jitter transfer function to that of the usual ILO i.e. a first-order PLL [37]. However, due to its larger locking range ( $\omega_{Lnew}$ ), it has a higher tracking bandwidth than a conventional ILO for a given  $Q$  and injection strength (3.16). The jitter from the incident signal is filtered by the low-pass characteristic of the noise transfer function, and the output signal tracks the phase variations of the incident signal within the loop bandwidth. Measured results for jitter transfer show a first order behavior with -20dB/dec attenuation (Figure 3.12(a)).

The phase of the oscillator is fixed for a given frequency as shown in Figure 3.4(a). However, the phase of the replica oscillator can be changed by controlling the bias of the secondary varactors VarA and VarB. The replica oscillator is not the part of the feedback loop hence the de-skew relationship is described by (1). This would suggest a total de-skew range of  $180^\circ$ . However, measured results show an average de-skew range of  $140^\circ$  (Figure 3.14). This is due to the size of the secondary varactors which are not large enough to change the natural frequency of the oscillator for a full  $180^\circ$  phase shift.

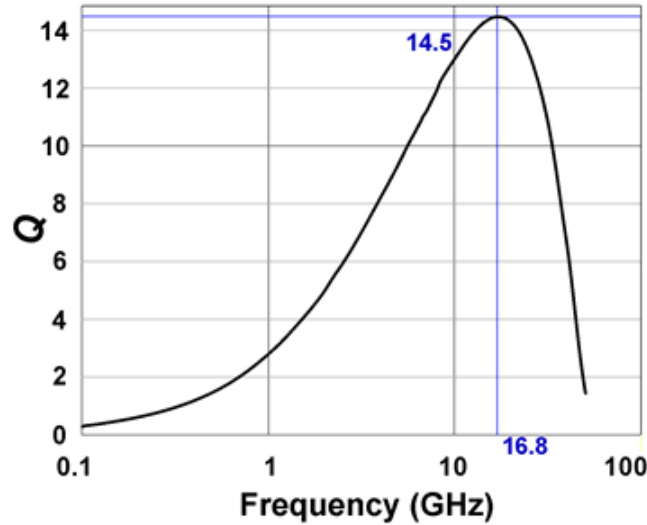


Figure 3.9: Simulated frequency behavior of  $Q$  of the inductor.

### 3.3 Measurement Results

A prototype has been designed and fabricated in 65nm CMOS technology, with a 1 V supply voltage. nMOS transistors in accumulation mode were used to implement the varactors with the control voltage applied to the drain/source. Spiral inductors of value 0.67 nH were designed to have simulated  $Q$  of over 14 in the frequency range of interest (Figure 3.9). They were constructed using thick, top two metal layers with added ground mesh for  $Q$  enhancement. The die micrograph (Figure 3.15) shows their octagonal structure each of size  $110 \times 110 \mu\text{m}^2$ . A high  $Q$  design was chosen to substantiate the efficacy of the proposed locking range extension technique as injection locking range is inversely proportional to  $Q$  in standard ILOs [41].

The key ILO parameters based on design methodology and simulation results are described in Figure 3.7.

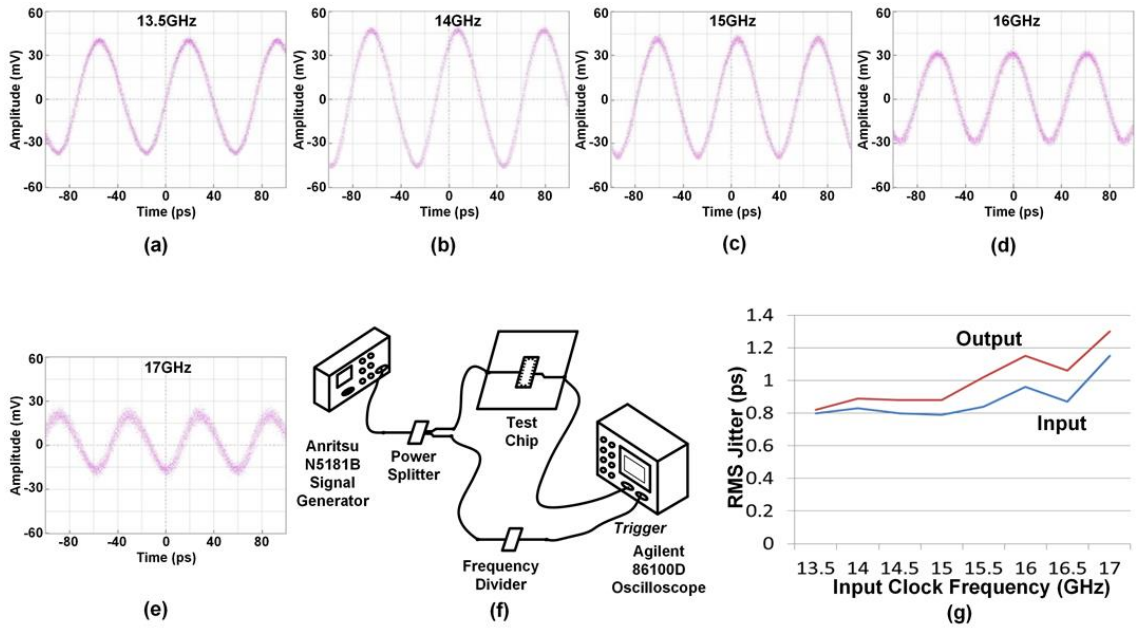


Figure 3.10: (a)-(e) Measured locked output signals at several reference frequencies. (f) Setup for locking range and RMS jitter measurement. (g) Measured input and output jitter at different reference frequencies.

#### 3.3.1 Locking Range and RMS Jitter

In our measurement setup (Figure 3.10(f)), an external signal generator is used to provide the reference clock used for injection. The frequency of the reference clock was varied and output

waveforms were observed on a sampling oscilloscope (Figure 3.10(a-e)). A locking range of 13.4 GHz – 17.2 GHz was measured, which translates to 24.8% around the center frequency. The achieved locking range is limited by the varactor tuning range. The power consumption depends on the frequency of operation and varies between 8.5 mW and 9.5 mW going from low to high frequencies. For comparison, a previous design [24] uses a low-Q (2.5) inductor to achieve a maximum locking range of 12% with strong injection while consuming 13.1 mW for a single injection locked LC oscillator.

The rms jitter of the reference and the output waveforms were also measured across several frequencies in the locking range and are plotted in Figure 3.10(g). A maximum RMS jitter addition of 0.15 ps is observed at 17 GHz, which is expected considering that the system output goes through several buffers to drive the output stage.

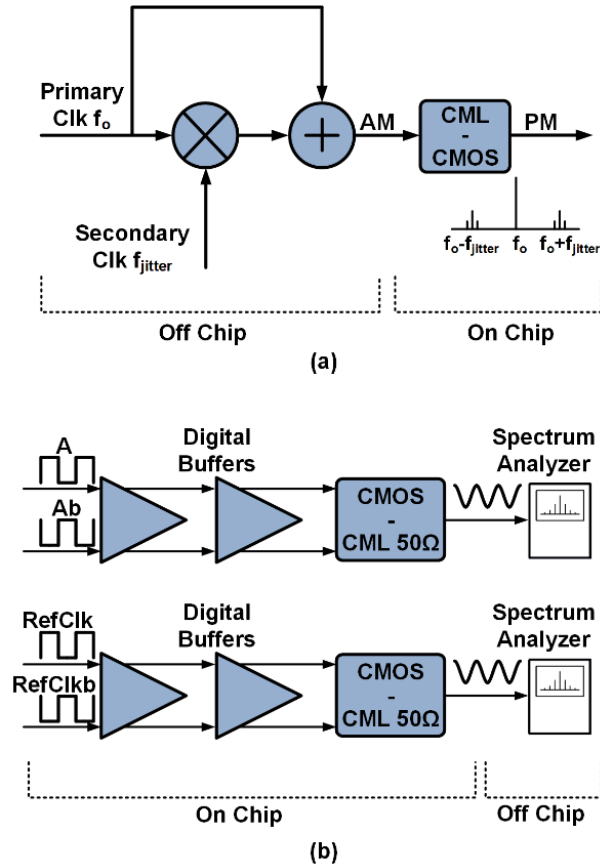


Figure 3.11: (a) Measurement setup for generating PM signal reference. (b) Setup for measuring the spectrum of reference and output signals

### 3.3.2 Jitter Transfer Function

The jitter transfer function was measured using the test setup shown in Figure 3.11. In this setup, a secondary clock ( $f_{\text{jitter}}$ ) was mixed with the primary clock ( $f_0$ ) to generate an amplitude modulated (AM) signal. This signal was transformed to a phase modulated (PM) signal by on-chip CML-CMOS converters. The PM signal was used as the new reference clock. The secondary clock frequency ( $f_{\text{jitter}}$ ) was varied from 10 MHz to 2 GHz for each  $f_0$  and the spectrum components of the output and the reference were measured at the carrier ( $f_0$ ) and sideband ( $f_{\text{jitter}}$ ) frequencies (Figure 3.11(b)) using a spectrum analyzer.

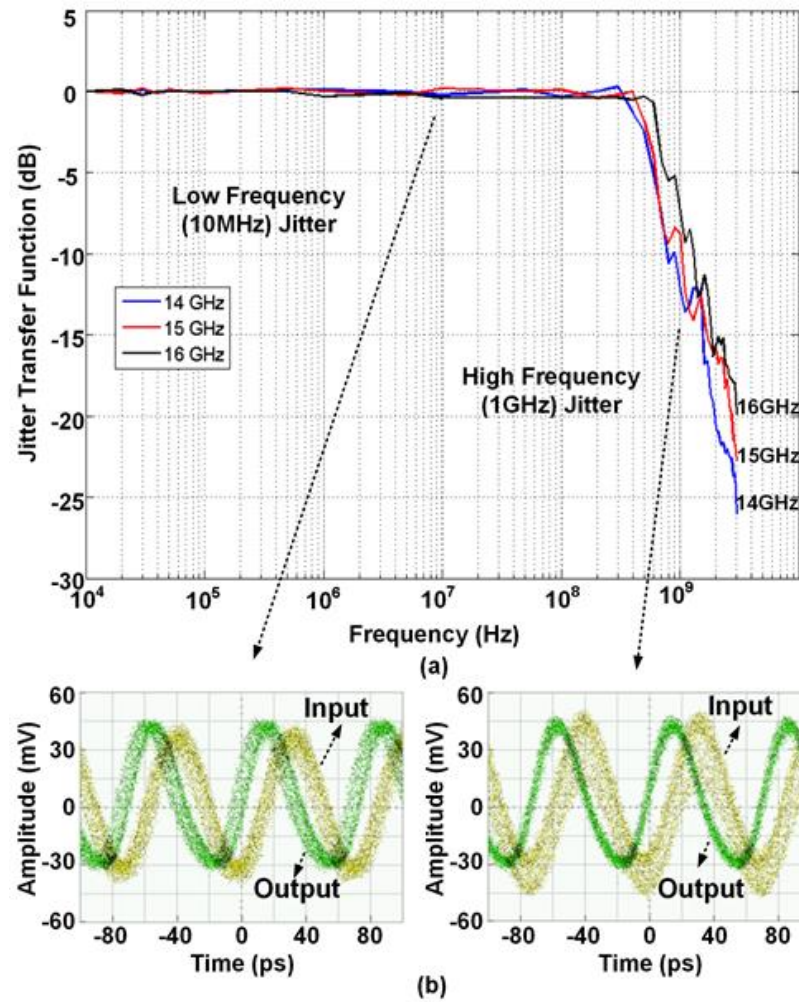


Figure 3.12: (a) Measured jitter transfer function for 14 GHz, 15 GHz and 16 GHz reference frequencies. (b) Response to low frequency (10 MHz) and high frequency (1 GHz) jitter.



Measurements were made (Figure 3.12(a)) for three reference frequencies (14 GHz, 15 GHz, and 16 GHz), and an average jitter tracking bandwidth (JTB) of 400 MHz was recorded. High JTB helps in retaining the low frequency jitter while eliminating high frequency jitter as depicted in Figure 3.12(b). It is important to retain the low frequency jitter in forwarded clock receivers as low frequency jitter is correlated with the data [17].

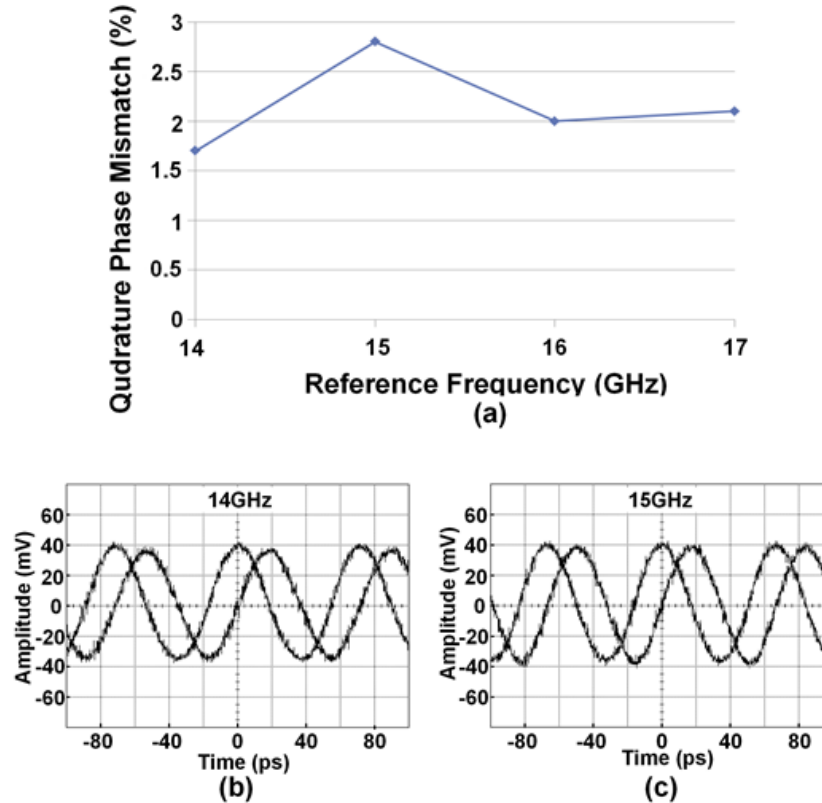


Figure 3.13: (a) Measured percentage quadrature phase error vs. reference frequency (b) Measured quadrature phase waveforms at 14 GHz (c) Measured quadrature phase waveforms at 15 GHz.

### 3.3.3 Quadrature Accuracy and Deskew

Quadrature phase accuracy was confirmed by measuring the phase difference between the outputs of the two oscillators after careful calibration of the measurement setup. A maximum offset of 2.8% (from 90°) is observed between the two phases at 15 GHz (Figure 3.13(a)). Bias to VarA and VarB (Figure 3.5) were fixed while making quadrature accuracy measurements. They were then varied from 0-V<sub>dd</sub> to measure the maximum phase shift of the replica oscillator (Figure 3.14).

Table 3.1 compares the performance of the proposed system with similar works. We achieve the best locking range compared to other injection locked systems and our high Q LC oscillator design allows us to achieve excellent jitter performance at a lower power consumption.

	This work [50] [51]	[24]	[25]	[17]	[52]
Injection arch.	PLL aided ILO	ILO	IL Divider	MILO- ILO	PILO
Oscillator arch.	LC	LC	LC	Ring	LC
Process technology	65nm CMOS	45nm CMOS	90nm CMOS	65nm CMOS	130nm CMOS
Injection range	24.8% (13.4GHz - 17.2GHz)	12% (12.6GHz - 14.3GHz)	18.1%	—	—
RMS jitter	0.82ps (at 13.5 GHz)	1.4ps (at 13.5 GHz)	—	1.4ps (at 3.2 GHz)	0.13ps (at 3.2 GHz)
Average jitter tracking BW	400 MHz	200 – 700MHz	—	25 – 300MHz	—
Active area	0.3 x 0.11mm <sup>2</sup>	0.15mm <sup>2</sup>	0.026mm <sup>2</sup>	0.03mm <sup>2</sup>	0.4mm <sup>2</sup>
Supply voltage	1 V	1.1 V	1.2 V	1 V	—
Average power consumption	9 mW (LC oscillators 65 % and buffers 35 %)	13.1 mW (for single LC osc.)	6.4 mW	6.8 mW (for entire Tx)	28.6 mW (single LC oscillator)
Average de-skew	140°	160°	NA	400°	—
Quadrature phase error	2.8% from 90° at 15GHz	NA	90° ± 1.8°	—	NA

Table 3.1: Performance comparison for wideband injection locked LC oscillator.

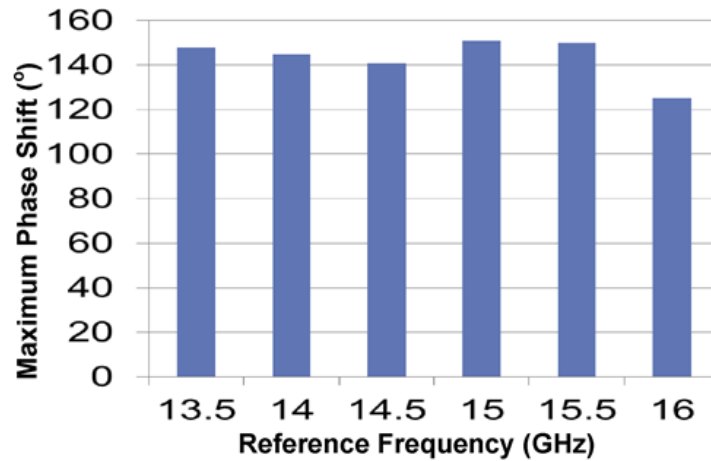


Figure 3.14: Measured maximum phase shift of the replica oscillator at different reference frequencies.

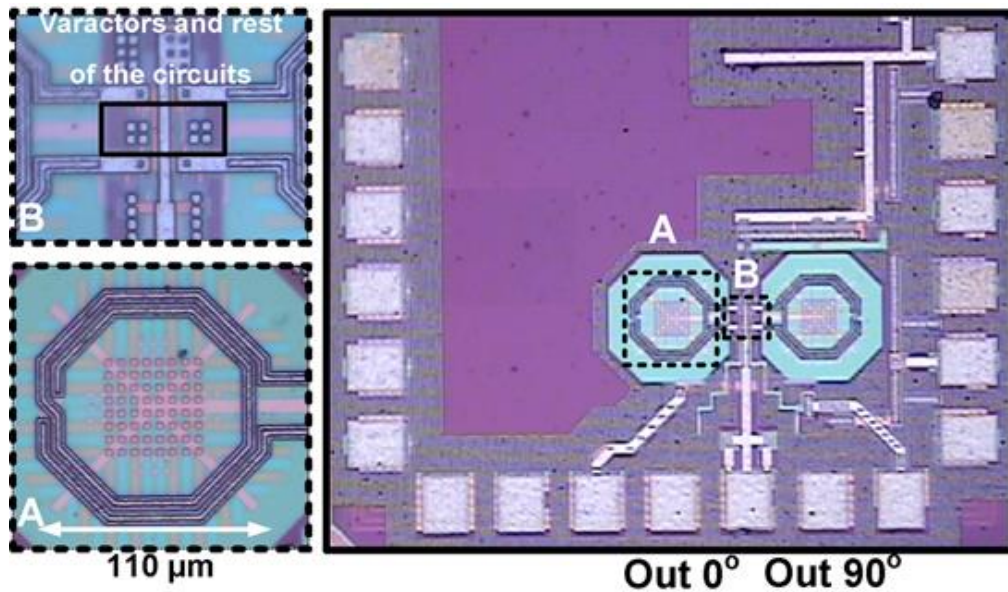


Figure 3.15: Die Micrograph. (A) shows the details of the high-Q inductor and (B) shows the placement of the varactors.

### 3.4 Summary

A new locking scheme for extended injection range in an LC oscillator was introduced and analyzed. The dynamics of the system were derived and the new locking range was proven to be better than that of a conventional ILO. The technique breaks the existing tradeoff between

power consumption and locking range in LC oscillators. The system requires only a single clock phase for operation. Quadrature phase generation was demonstrated by adding a secondary coupled oscillator to the system. This wide locking range of the proposed system eliminates the need for center-frequency adjustment.

Our work ensures that injection locking can be reliably used in a half-rate or quarter-rate forwarded clock I/O architecture with minimal power overhead and reduced clock jitter (higher  $Q$ ). Our approach is scalable because as data rates increase it becomes easier to have high  $Q$  inductors on chip.

# Chapter 4: Quadrature Locked Loop (QLL)

The rise in the aggregate bandwidth of microprocessors has led to an insatiable demand for massively parallel low-power links with high data rates. This has imposed stringent requirements on on-chip clock generation and distribution. Ring oscillator (RO) based injection-locked (IL) clocking has been used in the past [53] to provide a low-power, low-area and low-jitter solution. ROs are easily integrated in standard CMOS process and have smaller on-chip area compared to LC tank based oscillators making them suitable for dense parallel links. Ring based injection-locked oscillators (ILO) can also be used to generate quadrature phases from a reference clock [26] without frequency division, which is desirable for half-rate and quarter-rate CDR architectures.

However, ILO inherently has a small locking range [23] making it less suitable for wideband applications; for example the transceivers embedded in field-programmable gate arrays (FPGAs) [54]. In addition, drift in free running frequency due to process, voltage and temperature (PVT) variations may lead to poor jitter performance and locking failures [55]. Scaling worsens the situation as smaller feature size makes the ROs' free running frequency more susceptible to PVT variations. This fact is exemplified in Figure 4.1. It shows percentage change in natural frequency of a simple five stage ring oscillator with change in supply voltage for 28nm and 65nm technologies. The variation in 28nm can be about 20% for a 100mV change in  $V_{DD}$ . Figure 4.2 shows a simulated histogram of the change of a ring oscillator's  $f_0$  with process variation in 28nm technology. A  $3\sigma$  variation of 0.95GHz is observed around an oscillation frequency of 10GHz. For robust performance the locking range should be several times bigger than the variation in natural frequency but maximum locking range in ring based ILOs is only about 10% [23].

Adding a PLL to an ILO provides frequency tracking. However, PLL aided techniques have second order characteristics that lead to jitter peaking. They also add design complexity and power consumption [56]. A simple frequency-locked-loop (FLL) is not sufficient to compensate for the drift as the output of an injection-locked oscillator is always fixed at the desired frequency, and FLL only comes to action after system loses lock [55].

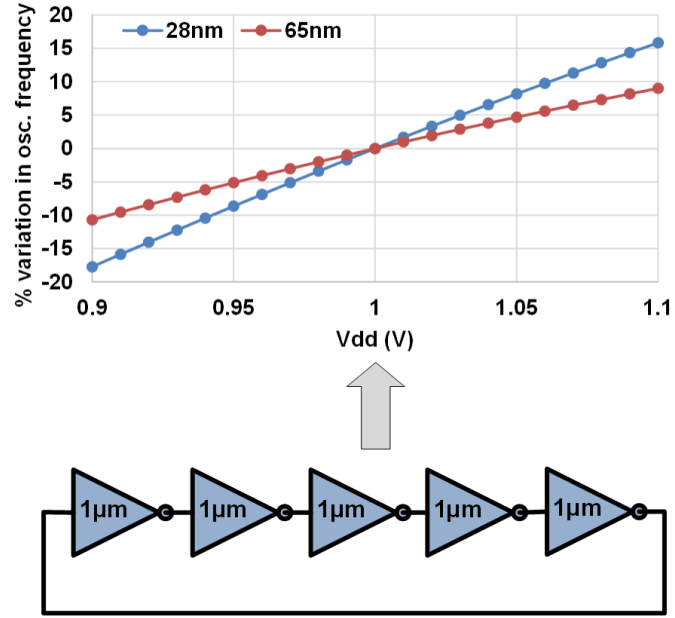


Figure 4.1: Simulated variation in oscillation frequency of a ring oscillator with change in supply voltage for 28nm and 65nm technologies.

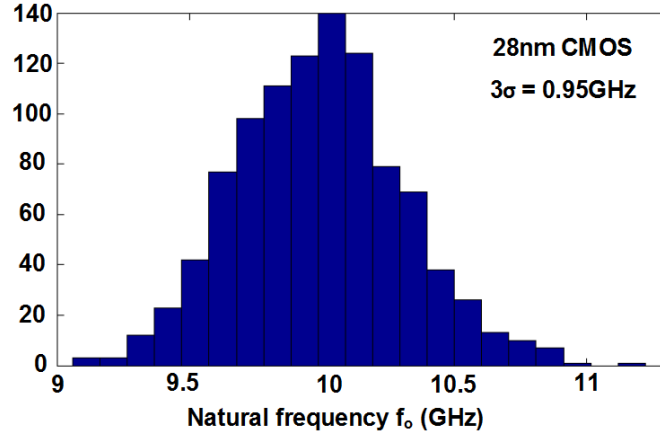


Figure 4.2: Histogram of change in  $f_0$  in a ring oscillator with process variation.

We present a novel frequency tracking method that exploits the dynamics of the injection locking process in a quadrature ring oscillator to increase the effective locking range. We also show that the resultant system is still a first order system, unlike an injection locked phase locked loop (IL PLL). Additionally, this system is used to generate accurate quadrature clock phases for a four channel quarter-rate optical receiver.

Generating quadrature phases at low area and power overhead from a reference clock is desirable for quarter-rate forwarded clock architectures. Both ring and LC based dividers have

been frequently used for quadrature phase generation. However, because they operate at twice the desired frequency they tend to be power inefficient. Quadrature phase generation through ring ILO's without frequency division leads to phase inaccuracies [23] (Figure 4.3). Previous works have tried to solve this issue with multiphase injection with RC-CR filters (Figure 4.4). This results in significant additional power consumption in the buffers driving the passive filter. Also poly-phase filters limit the locking range and only work with pure sin signals [26]. We propose a power efficient approach to accurate quadrature phase generation without frequency division.

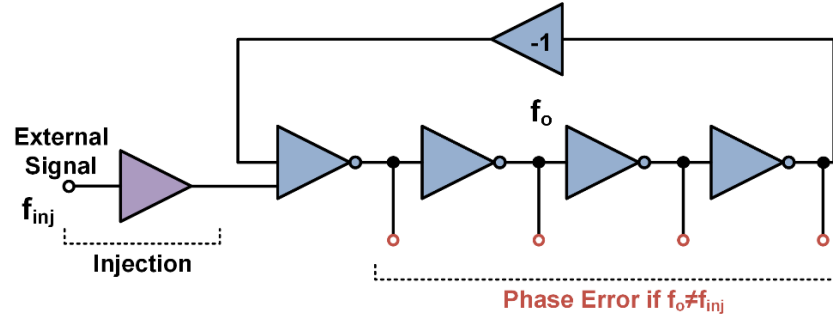


Figure 4.3: Phase error in a ring oscillator due to injection.

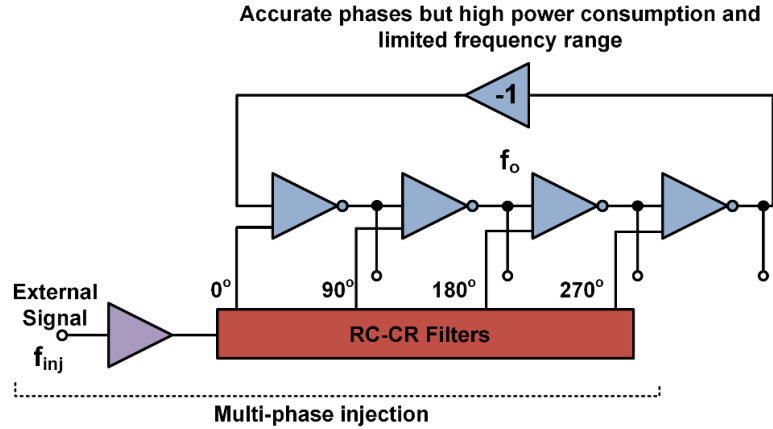


Figure 4.4: Multi-phase injection in a ring oscillator.

This chapter is organized as follows: Section I describes the system architecture. Section II presents a mathematical and behavioral analysis describing the dynamics of the system. Circuit implementation and clocking for four channel quarter-rate optical receiver are discussed in Sections III and IV respectively. Hardware measurement results are presented in Section V. Finally, Section VI summarizes the work and presents the conclusions.

## 4.1 Proposed Approach

We propose a novel frequency tracking method that exploits the dynamics of injection locking in a quadrature ring oscillator to increase the effective locking range and produce accurate quadrature phases. When a ring oscillator with natural frequency  $f_o$  is injected with an external signal with frequency  $f_{inj}$ , the outputs of the ring oscillator incur a phase mismatch error if  $f_o$  is not equal to  $f_{inj}$  [23]. We prove that the mean of this error, i.e., mean quadrature phase error (MQPE), contains information about the difference between the natural frequency of the oscillator and injected frequency (i.e.  $|f_{inj} - f_o|$ ) in both locked and unlocked states. A phase detector and a low pass filter is used to measure the MQPE. Their output is used in a negative feedback configuration to set the natural frequency of the ring oscillator there by nullifying the  $|f_{inj} - f_o|$  and quadrature phase error. This loop provides frequency tracking, thereby assuring wideband injection. We call this technique a quadrature locked loop, or QLL in short (Figure 4.9).

In this section we derive an expression for the MQPE. To do so we first quantify the phase error caused due to injection. Figure 4.5 shows a two stage differential ring oscillator with a natural frequency of  $f_o$ ; thus both delay stages have an inherent delay of  $1/4f_o$ . One of the delay stages (A) is injected with a signal at  $f_{inj}$ . Injection causes the delay of stage A to change to  $1/4f_o + \Delta$  and the oscillator oscillates at a frequency  $f$  (not necessarily a constant) instead of  $f_o$ . The delay of the other stage (B) stays the same, thus

$$Delay_{IQ}(t) = \frac{1}{4f_o} \quad (4.1)$$

But as the frequency of oscillation is  $f$ , phase delay can be expressed as

$$Delay_{IQ}(\theta) = \frac{1}{4f_o} \times 2\pi f = \frac{\pi}{2} \times \frac{f}{f_o} \quad (4.2)$$

Now from (4.2) we can calculate the quadrature error as

$$Quad. Error = Delay_{IQ}(\theta) - \frac{\pi}{2} = \frac{\pi}{2} \left( \frac{f}{f_o} - 1 \right) = \frac{\pi}{2} \left( \frac{\omega}{\omega_o} - 1 \right) \quad (4.3)$$



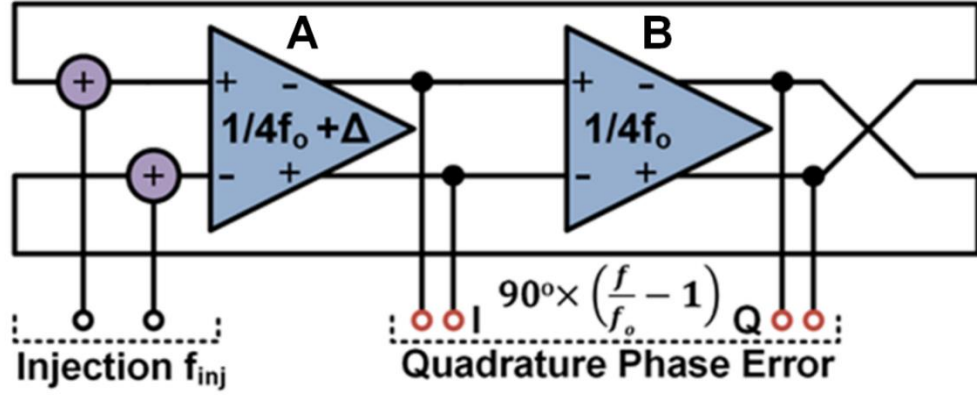


Figure 4.5: Deriving the quadrature phase error expression in a two stage ring oscillator

With this result (4.3) we can move ahead to calculating the MQPE. We do so by separately analyzing the locked and unlocked cases.

In the locked state  $f(t) = f_{inj}$  (a constant), hence

$$MQPE = \frac{\pi}{2} \left( \frac{f_{inj}}{f_o} - 1 \right) = \frac{\pi}{2} \left( \frac{\omega_{inj}}{\omega_o} - 1 \right) \quad (4.4)$$

To calculate the variation of quadrature phase error in the unlocked state, we need to calculate the variation of instantaneous frequency of the oscillator in the unlocked state. Given that  $\omega = \omega_{inj} + d\theta/dt$ . This is calculated easily by differentiating (2.7).

$$\omega = \omega_{inj} + \frac{\omega_b^2}{\omega_o - \omega_{inj}} \times \frac{\sec^2\left(\frac{\omega_b t}{2}\right)}{1 + \left(\frac{\omega_l}{\omega_o - \omega_{inj}} + \frac{\omega_b}{\omega_o - \omega_{inj}} \tan\left(\frac{\omega_b t}{2}\right)\right)^2} \quad (4.5)$$

where

$$\omega_b = \sqrt{(\omega_o - \omega_{inj})^2 - \omega_L^2} \quad (4.6)$$

(4.5) shows that in the unlocked state the instantaneous frequency ( $\omega$ ) beats with a frequency  $\omega_b$ . Thus, as suggested by (4.3), the quadrature phase error also varies beats with frequency  $\omega_b$  as shown in Figure 4.6. This periodicity allows us to calculate the MQPE in the unlocked state by integrating (4.3) from 0 to  $2\pi/\omega_b$ .

$$MQPE = \frac{1}{\frac{2\pi}{\omega_b}} \int_0^{\frac{2\pi}{\omega_b}} \frac{\pi}{2} \times \left( \frac{\omega(t)}{\omega_o} - 1 \right) dt \quad (4.7)$$

$$MQPE = \frac{\pi}{2} \left[ \frac{\omega_{inj}}{\omega_o} - 1 + \frac{\omega_b}{2\pi\omega_o} \left\{ \theta \left( \frac{2\pi}{\omega_b} \right) - \theta(0) \right\} \right] \quad (4.8)$$

$\theta$  varies by  $2\pi$  over one period (2.7) thus we have

$$MQPE = \frac{\pi}{2} \left[ \frac{\omega_{inj}}{\omega_o} + \frac{\omega_b}{\omega_o} - 1 \right] = \frac{\pi}{2} \left[ \frac{f_{inj}}{f_o} + \frac{f_b}{f_o} - 1 \right] \quad (4.9)$$

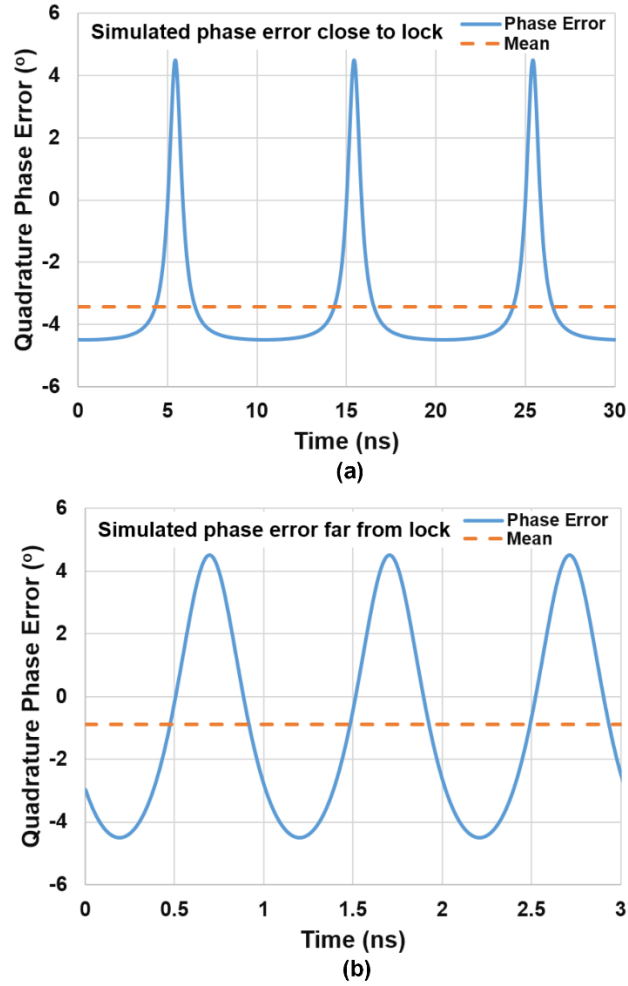


Figure 4.6: Quadrature error in unlocked case (a) close to lock (b) far from lock.

(4.3) and (4.9) form the cornerstones of the theory of QLL. Figure 4.7 shows the variation of MQPE with change in  $f_o$  for a fixed  $f_{inj}$  of 7GHz and injection strength ( $k$ ) of 0.05. It has two distinct regions, locked and unlocked. As expected, the MQPE is 0 for  $f_{inj}=f_o$ . In the locked state the MQPE increases (almost linearly) as  $|f_{inj} - f_o|$  increases. MQPE goes to zero asymptotically (never reaching it) as  $|f_{inj} - f_o|$  increases in the unlocked state. This suggests that the MQPE is a measure of the sign of  $f_{inj} - f_o$  in both locked and unlocked states. This in turn implies that a quadrature phase error detector can be used as a phase frequency detector (PFD) in an injection locking environment. Hence the quadrature error can be indeed used in a feedback system to set the natural frequency ( $f_o$ ) of the oscillator such that  $f_o=f_{inj}$ , thereby boosting the effective locking range.

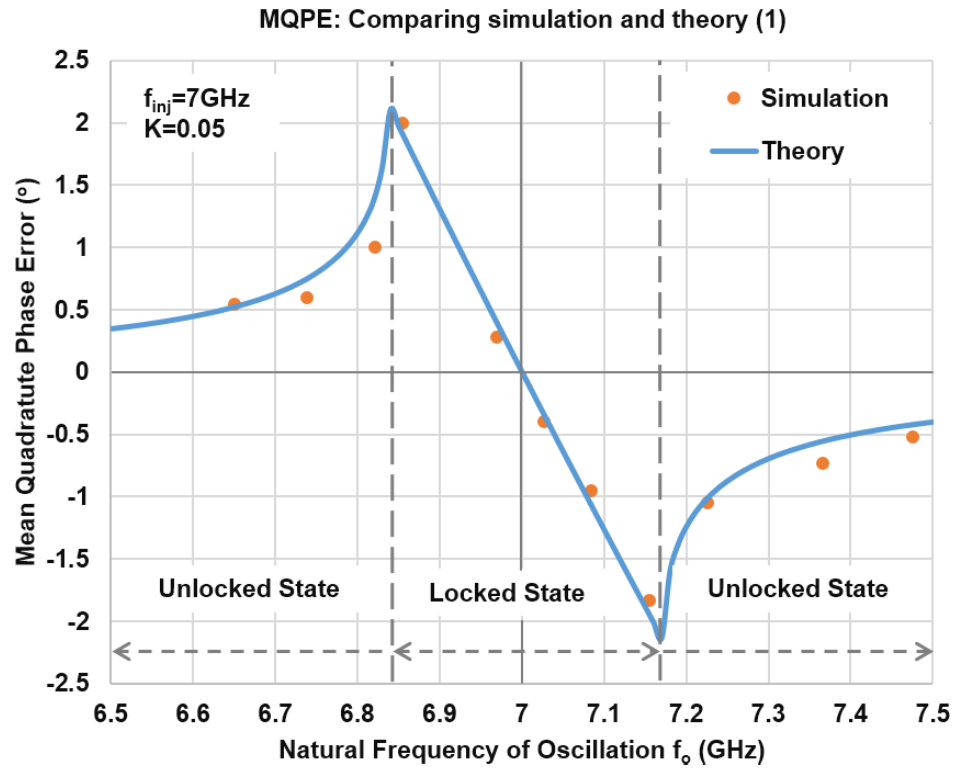


Figure 4.7: MQPE vs.  $f_o$  for a fixed  $f_{inj}$  of 7GHz

An interesting feature of this technique is that the MQPE itself can be controlled by changing the injection strength. As shown in Figure 4.8, increasing the injection strength ( $K$ ) increases the intrinsic locking range of the injection locked oscillator (2.5), hence widening the linear region. This fact proves useful as injection strength can be controlled externally, allowing off-chip control of the MQPE.

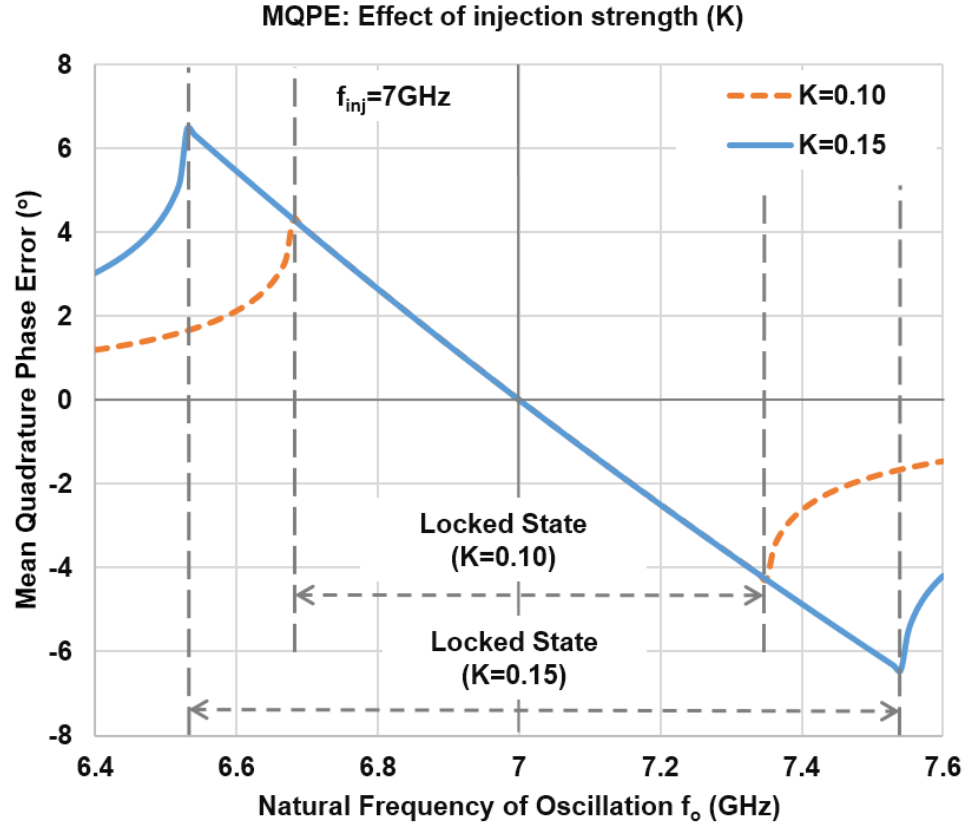


Figure 4.8: Effect of injection strength on MQPE

Figure 4.9 shows the block diagram of the proposed system. It consists of an injection locked two stage differential ring oscillator. Instantaneous quadrature error is measured by using a phase detector (PD), which takes the I and Q phases of the clock from an ILO as inputs. The error is averaged using a charge pump and a loop filter, and fed back to the oscillator's  $V_{ctrl}$  (Figure 4.9). The loop tracks the changes in the injected frequency and natural frequency of the oscillator until their difference  $|f_{inj} - f_o|$  is minimized, assuring a wide locking range.

This technique obviates the need for a phase frequency detector (PFD) and its speed limitations. Wide jitter tracking bandwidth inherent to IL helps in preserving the correlated low frequency jitter and suppressing the uncorrelated high frequency jitter. In addition, since the reference clock is not used by the PD, it does not need to be rail to rail. As described in the next sections, QLL has a first order response, assuring stability without jitter peaking.

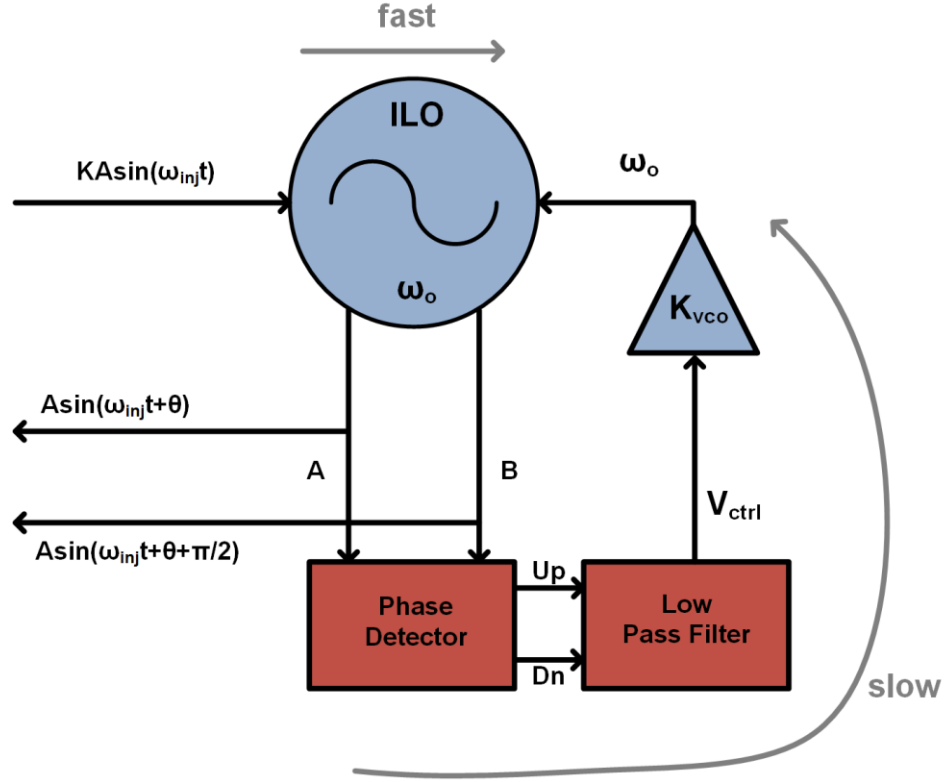


Figure 4.9: Block diagram of the proposed system (QLL)

## 4.2 Mathematical Analysis

In this section we propose a mathematical model of our system. We analyze the effect of the quadrature error correcting loop on the injection locking dynamics and derive the dynamics of the overall system. We show that the overall system can be designed to have a first order behavior, and bolster our claims with Simulink based behavior modelling and measured results.

The dynamics of the system is similar to those of normal injection locked oscillator (2.3) except for the fact that  $\omega_o$  is not fixed any more. The value of  $\omega_o$  is set by the loop as

$$\frac{d(\theta)}{dt} = \omega_o + K_{VCO}V_{ctrl} - \omega_{inj} - \omega_L \sin(\theta) \quad (4.10)$$

$V_{ctrl}$  is generated after low pass filtering the transient quadrature phase error by a loop filter 'H'. We therefore have

$$V_{ctrl}(t) = H \left( \frac{\omega_{inj} + \frac{d\theta}{dt}}{\omega_o + K_{VCO} V_{ctrl}} - 1 \right) \quad (4.11)$$

Using (4.10) we can simplify (4.11) to

$$V_{ctrl}(t) = H \left( \frac{-\omega_L \sin(\theta)}{\omega_o + K_{VCO} V_{ctrl}} \right) \quad (4.12)$$

At equilibrium  $d\theta/dt=0$  and  $\omega_o + K_{VCO} V_{ctrl} = \omega_{inj}$ . Substituting these values in (4.10) we get that in equilibrium,  $\theta=0$ .

The highly non-linear nature of (4.11) and (4.12) make it difficult to get a convenient close form solution. However, we can still gain some insight about how the loop behaves with regard to input noise by linearizing about the equilibrium point (i.e.  $\theta=0$ ). We replace  $\theta$  with  $\theta_n$ , given  $|\theta_n| \ll 1$  (small signal assumption)

$$\frac{d(\theta_n)}{dt} \approx K_{VCO} \Delta V_{ctrl} - \omega_L \theta_n \quad (4.13)$$

$$\Delta V_{ctrl} \approx H \left( \frac{-\omega_L \theta_n}{\omega_o} \right) \quad (4.14)$$

Substituting the value of  $\Delta V_{ctrl}$  from (4.13) in (4.12) we get

$$\frac{d(\theta_n)}{dt} \approx -K_{VCO} H \left( \frac{\omega_L \theta_n}{\omega_o} \right) - \omega_L \theta_n \quad (4.15)$$

where H denotes a low pass filter in frequency domain (Figure 4.10) with bandwidth  $\omega_{filter}$  such that  $\omega_{filter} \ll \omega_L$ .  $\omega_L$  is the locking range of the regular ILO as in (2.5).

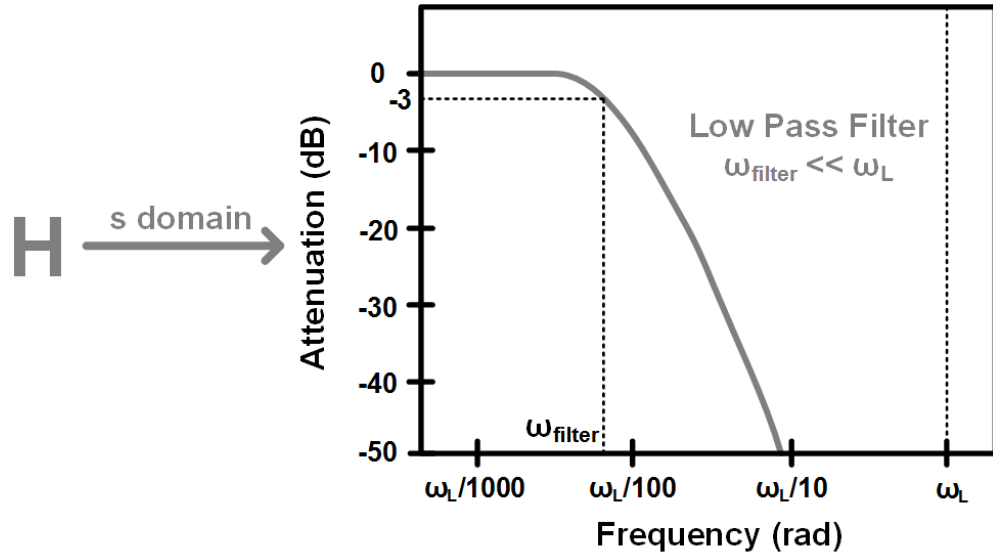


Figure 4.10: Design of the loop filter.

If  $\theta_n$  varies faster than  $\omega_{\text{filter}}$  then  $H\left(\frac{\omega_L \theta_n}{\omega_o}\right) \approx 0$  and we have

$$\frac{d(\theta_n)}{dt} = -\omega_L \theta_n \quad (4.16)$$

This is similar to a first order PLL response with bandwidth  $\omega_L$ , characteristic of an injection locked system (2.3).

If  $\theta_n$  varies slower than  $\omega_{\text{filter}}$  then  $H\left(\frac{\omega_L \theta_n}{\omega_o}\right) \approx \frac{\omega_L \theta_n}{\omega_o}$  and we have

$$\frac{d(\theta_n)}{dt} = -\left(\frac{K_{vco}}{\omega_o} + 1\right) \omega_L \theta_n \quad (4.17)$$

This is also a first order PLL response with a bandwidth higher than  $\omega_L$ . The exact bandwidth is not important in this case because the variation in  $\theta_n$  is much slower than  $\omega_L$ .

So overall the system allows all the variations in the  $\theta_n$  slower than  $\omega_L$  to go through, and attenuates all variations faster than  $\omega_L$  with, -20dB/dec (first order) slope. This is an important conclusion. It essentially means that allowing the quadrature error correction loop to run much slower than the injection locking loop ensures that the system has a first order response with bandwidth same as that of an ILO, i.e.,  $\omega_L$ .

We verify the accuracy of our derivations by simulating a more accurate behavioral model in Simulink. Actual chip measurement results will also be used to bolster the accuracy of our modeling.

### 4.2.1 Behavioral Modelling

In order to investigate the stability of the system with greater accuracy a behavioral model was constructed in Simulink by implementing (4.11) and (4.12) as shown in Figure 4.12. The model is initialized to set  $f_o$  to 5GHz and  $f_{inj}$  to 7GHz. The ILO's inherent locking range ( $f_L$ ) was set to 175MHz. Figure 4.11 shows the transient response of QLL Simulink model for two different loop bandwidths. The first with loop bandwidth of 100kHz ( $\ll f_L$ ) and second with loop bandwidth of 20MHz (comparable to  $f_L$ ). In both cases the system attains the same final locked state, i.e.,  $\theta = 2n\pi$  and  $f=7$ GHz. However, there are some important differences. In the first case the transient has a first order response with no overshoot whereas the second case has significant ringing in its transient response and is thus farther from stability.

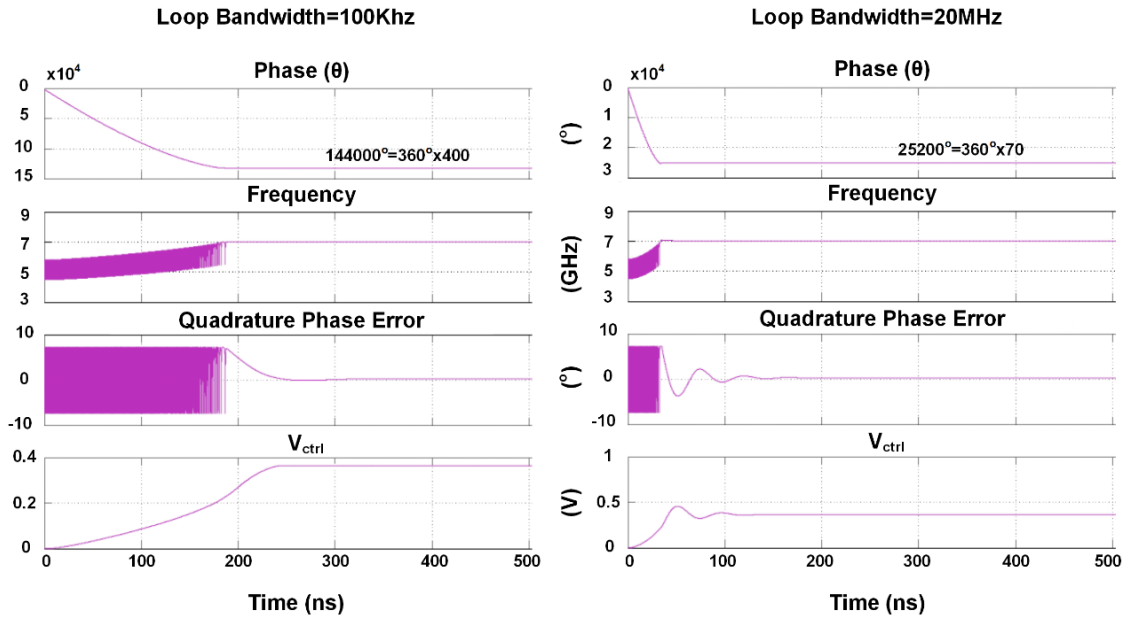
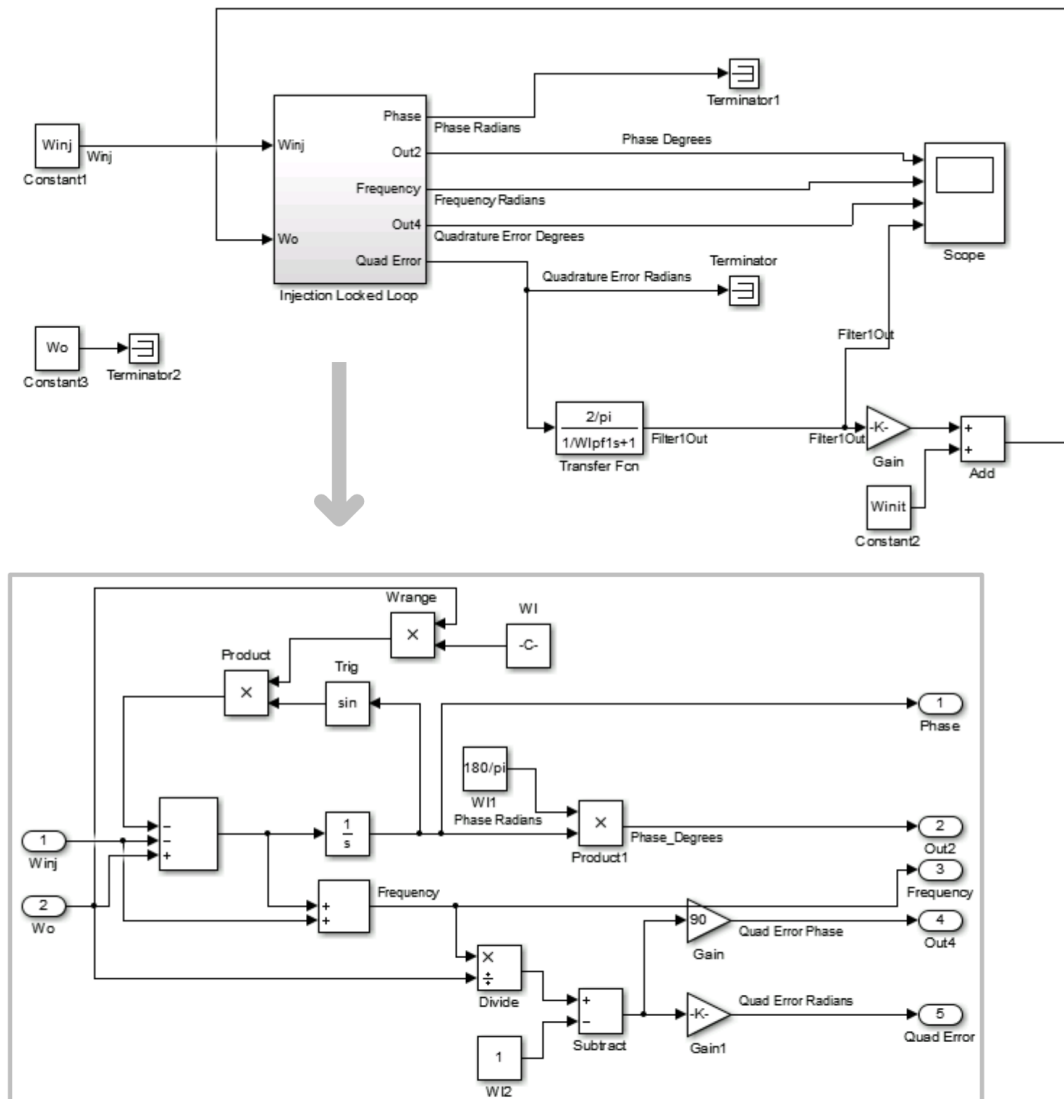


Figure 4.11: Transient locking characteristics of Simulink model of QLL for two different loop filters.





```

[xe,ue,ye,dxe]=trim('InjectionLock_QuadLoop_Model',[],1);
[A,B,C,D]=linmod('InjectionLock_QuadLoop_Model',xe,ue);
sys=ss(A,B,C,D);
G=tf(sys);
stepplot(G);grid on;
[y,t,x]=step(G,10e-9);
figure(2);
[a,p,f]=bode(sys);
semilogx(f/(2*pi), 20*log10(a(:,,:))'); grid on; xlim ([100e3 1.5e9]);

```

Figure 4.12: Simulink model of QLL (top) and Matlab code to extract the linear state-space model around the operating point.

To further analyze the stability of the QLL model, we linearized the Simulink model around the equilibrium point and by using the Matlab's "linmod" function. Once the state-space model

was determined the step response and system transfer were calculated for different quadrature error correction bandwidths.

Once again the inherent locking range ( $f_L$ ) of the ILO was fixed to 175MHz and we simulated the linearized model for two different loop bandwidths. The first with loop bandwidth of 100kHz such that it was  $\ll f_L$ . A first order response step response observed. There was no overshoot in the step response and no peaking in the system transfer function (Figure 4.13) with -20dB/dec decay.

In the second case we set the loop bandwidth to 20MHz which is much closer to  $\omega_L$ . We observed ringing in the step response and system transfer function had some peaking and had a second order (-40dB/dec) decay. We used this modelling insight in our circuit design.

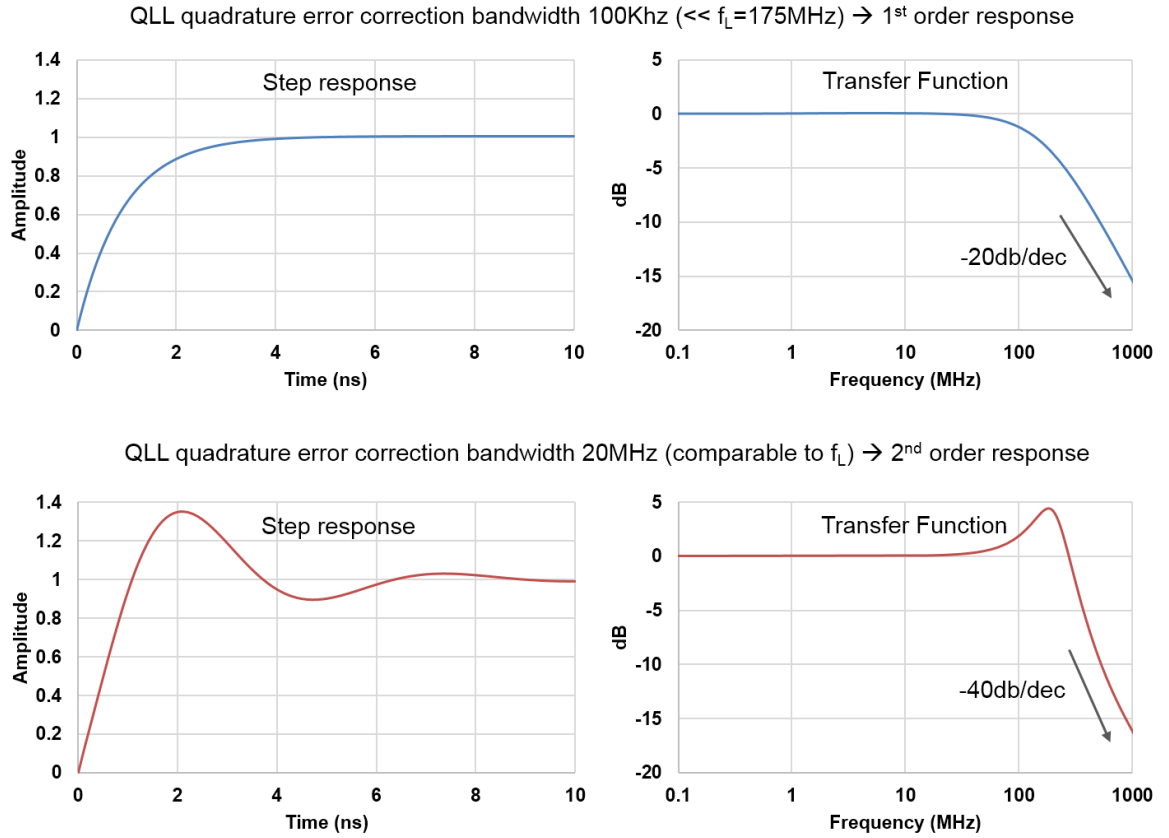


Figure 4.13: Step response and transfer function of linearized QLL Simulink model for different loop bandwidths (Small signal behavior).

The model suggests that in order for the system to be stable the secondary loop needs to run much slower than the bandwidth of the injection locking itself. If the above condition is assured

then the bandwidth of the system is the bandwidth of the ILO ( $f_L$ ). This is similar to our theoretical analysis in the previous section.

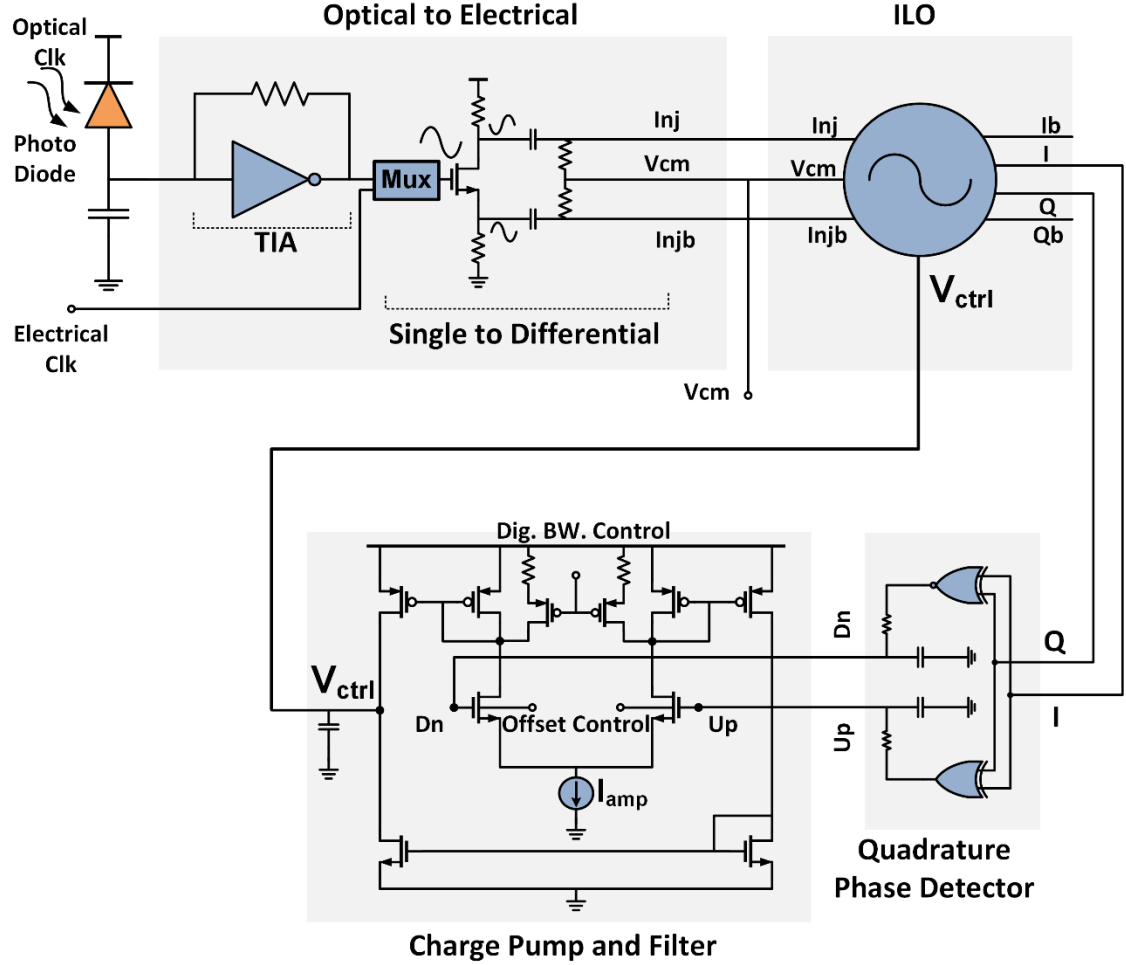


Figure 4.14: Circuit architecture of QLL.

### 4.3 Circuit Implementation

Figure 4.14 shows the circuit diagram of the major sections of the QLL. The reference clock can be injected both electrically and optically. A trans-impedance amplifier (TIA) based optical front-end is used in the latter case. The TIA consists of an inverter with a resistor of value  $4k\Omega$ , connected in feedback. The bandwidth of the TIA is more than 10GHz. The TIA's output voltage amplitude (150 mV) is sufficient for the IL architecture because of its high voltage gain

[53]. The electrical input is provided directly by an on-chip  $50\Omega$  transmission line. An analog multiplexor is used to select between the electrical and optical (from TIA) inputs. The selected input is fed to the single to differential convertor. It consists of an NMOS with symmetrical drain and source loads. The differential outputs from the drain and source are  $180^\circ$  apart within an 11GHz bandwidth. Outputs from the single to differential convertor are ac coupled to the ILO injection ports.

Each ILO (Figure 4.15) consists of a V/I converter and a two-stage, cross-coupled, pseudo differential current-starved ring oscillator. A two-stage ring oscillator architecture is chosen to minimize power consumption. The bias circuit is designed such that current starvation is achieved in both PMOS and NMOS in the invertors of the ring oscillator for a 50% duty cycle. Current injection is achieved by NMOS differential V/I converters without resistive loading which helps in mitigating the interaction with the DC bias at the injection point [23]. The sizes of the NMOS differential pair are chosen to reduce the parasitic loading while fully steering the current source.

A simple XOR-XNOR based phase detector takes the I and Q phases of the clock from the ILO as inputs. It generates Up and Dn signals containing the instantaneous quadrature error information. The error is averaged using a simple charge pump and a loop filter consisting of a capacitor of value 1pF. The charge pump consists of an amplifier with an NMOS differential pair and diode connected PMOS loads. The differential output of the amplifiers is converted to a single ended output by current mirroring. The body biases of the NMOS differential pair in the charge pump is used for externally calibrating for the current mismatch in the charge pump. The bandwidth of the charge pump filter is digitally controllable, by altering the load on the differential pair. The output of the charge pump and loop filter is fed back to the oscillator's  $V_{ctrl}$ , thereby completing the loop.

### 4.3.1 Transient Simulation

Figure 4.16 (a) shows the transient locking characteristics (frequency and  $V_{ctrl}$ ) of the proposed QLL. For the simulation, the injected frequency was fixed to 7GHz and the initial frequency of the oscillator was 7.7GHz, such that system was outside its locking range.

The locking takes place in three different stages. When the system is in the unlocked state the loop brings the frequency of the oscillator close to the injected frequency. When the

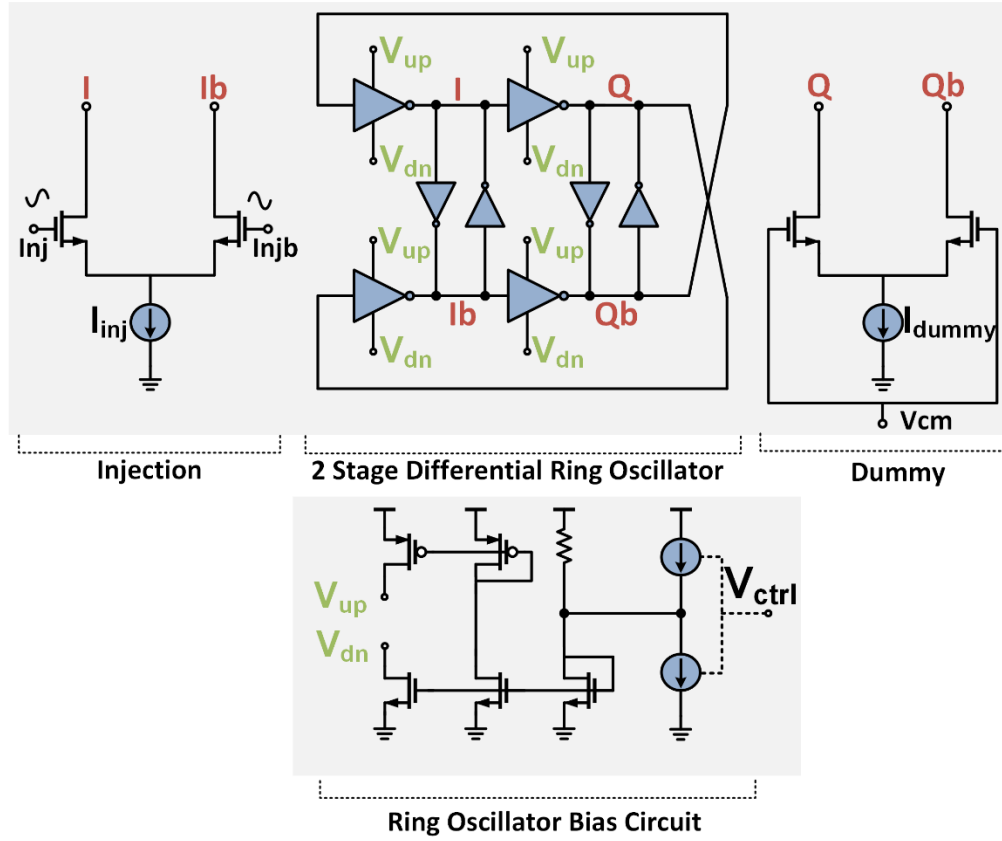


Figure 4.15: Ring oscillator based ILO circuit schematic.

frequency of the oscillator comes within the injection locking range of the ILO, frequency lock is achieved. However, the phase still keeps changing. The loop changes the  $V_{ctrl}$  of the oscillator until the quadrature error is nullified i.e. when  $f_o = f_{inj}$ . This negative feedback loop ensures that  $f_o = f_{inj}$  and there is no phase error in the outputs. Figure 4.16 (b) shows ring oscillator's frequency vs. control voltage characteristics. In the final locked state the  $V_{ctrl}$  settles to 0.61mV such that the natural frequency of the ring oscillator is equal to 7GHz (Figure 4.16 (b)).

Transient simulations were repeated to show that the QLL has inherent frequency detection in both directions as shown in Figure 4.17. The injected frequency was kept at 7GHz and the initial frequency was kept at 7.75GHz ( $>7\text{GHz}$ ) in one case and at 6.65GHz ( $<7\text{GHz}$ ) in the other. The system locks, in both cases, to the injected frequency. Difference in locking times because of the dependence of is dependent on MQPE on  $f_o$  (4.4).

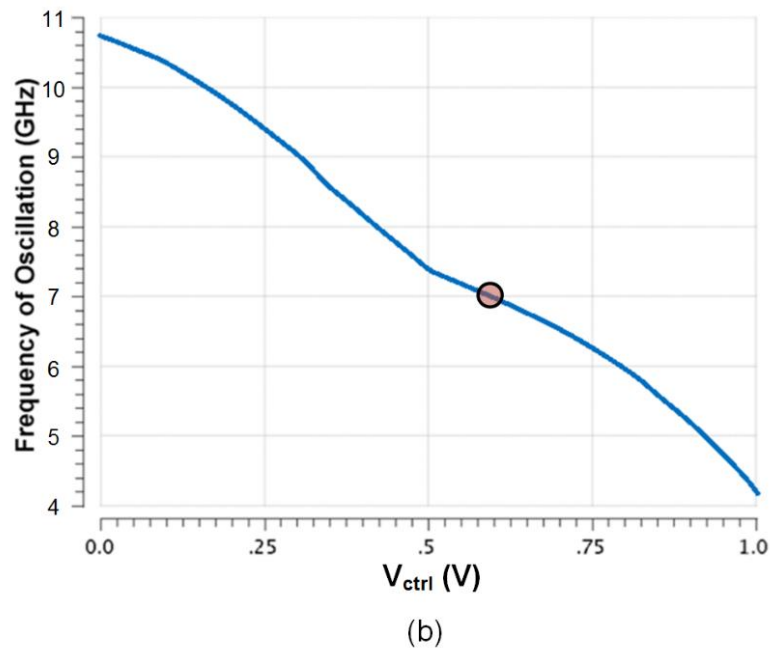
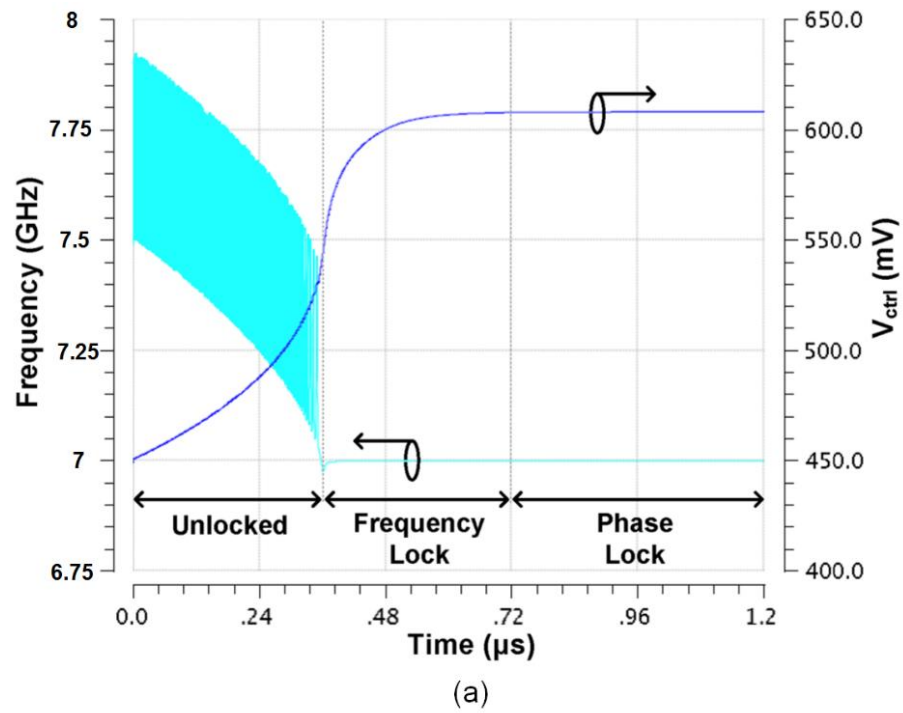


Figure 4.16: (a) Transient locking characteristics of QLL. (b) Ring oscillator characteristics.

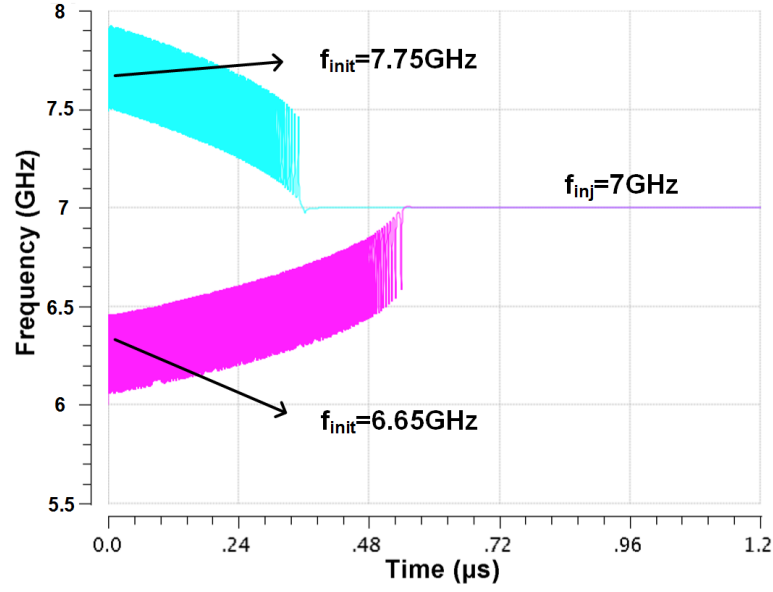


Figure 4.17: Locking transient for two different initial conditions

## 4.4 QLL Based Clocking

To validate the QLL as a robust building block, QLL based ultra-low-power clocking is demonstrated for a four channel, quarter-rate optical receiver (Figure 5.1).

The QLL is used to generate accurate quadrature clock phases from a single phase of electrical/optical clock input. The four phases are distributed without any repeaters and sent to local ring oscillators, which are placed near the clocked optical receivers. The local ring oscillators are injection locked to the global clock and frequency of oscillation is varied to control the phase of, local ring oscillator's output (deskew). The data receivers have a quarter-rate architecture hence require accurate quadrature phases. Symmetric injection with four clock phases ensure that quadrature accuracy is maintained even with deskew. The optical receiver uses the inherent frequency-to-voltage conversion provided by the QLL to dynamically body bias its devices. The details of QLL based clocking will be described in greater detail in the next chapter.

## 4.5 Hardware Measurements

The test chip for the QLL was fabricated in a 28nm FD SOI CMOS process. The die micrograph and core detail are presented in Figure 4.18. Core area is  $60\mu\text{m} \times 50\mu\text{m}$ , in a  $5\text{mm} \times 1.1\text{mm}$  die. The top metal layers are designed to be compatible with copper-pillar flip-chip bonding as well as bond-wire.

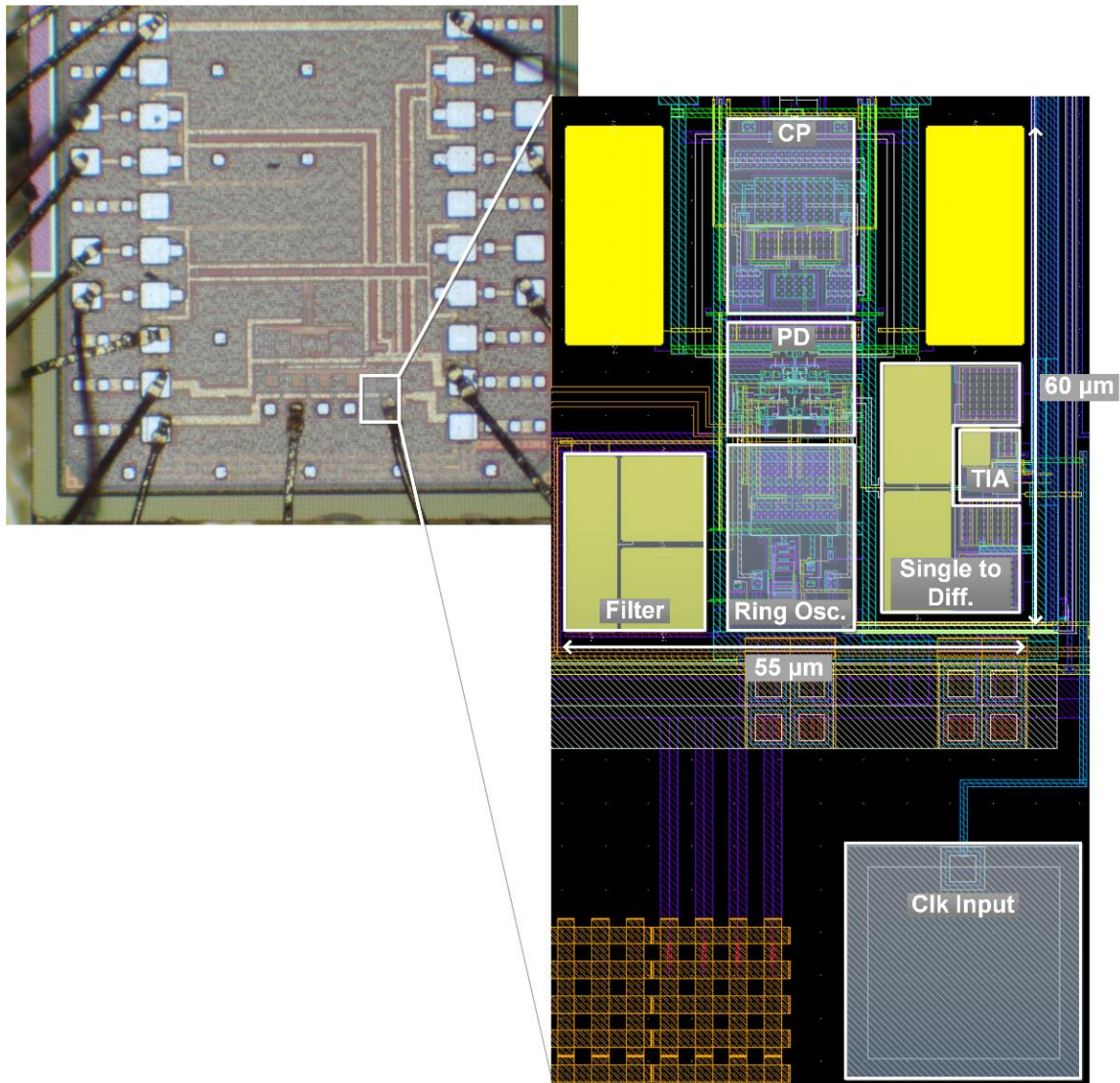


Figure 4.18: Die micrograph and layout details.



### 4.5.1 Locking Range and Integrated Jitter

In our measurement setup, an external signal generator (Anritsu N5181B) is used to provide the reference clock used for injection. The frequency of the reference clock was varied and output waveforms were observed on an Agilent 86100D sampling oscilloscope. To demonstrate the increase in locking range we disable the loop and set the  $V_{ctrl}$  (Figure 4.9) of the ILO at  $V_{DD}/2$ . Without the quadrature phase error tracking, a locking range of 7-7.4GHz (5%) is observed at

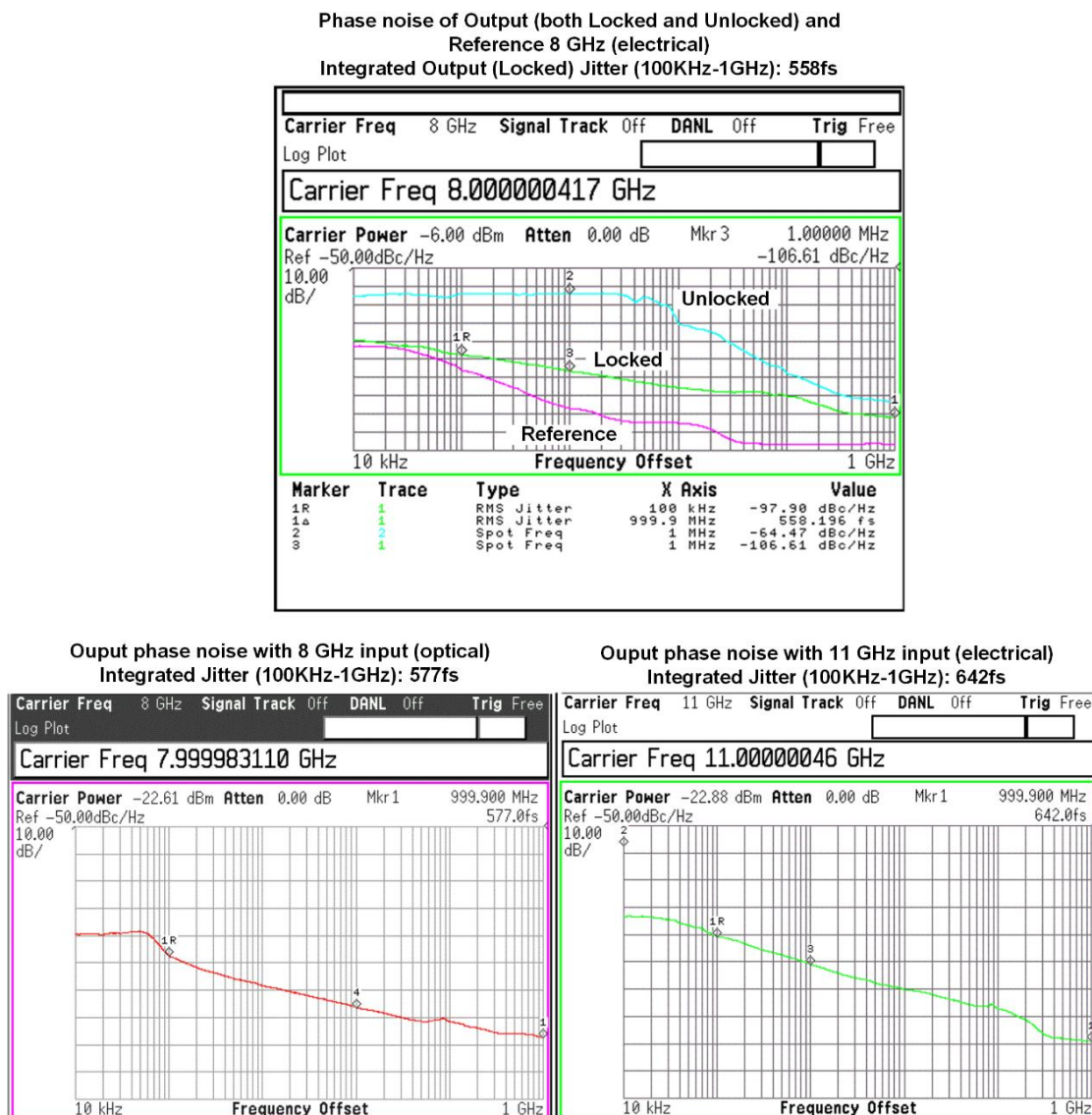


Figure 4.19: Phase noise and integrated jitter measurements for 8GHz (electrical and optical) and 11GHz (electrical).

an injection strength (K) of 0.05. With the loop activated the locking range improves to 4-11GHz (90%). The achieved locking range is limited by the tuning range of the ring oscillator. In order to measure the response of the QLL to fast changes in frequency, the frequency of the reference clock was changed in steps of 2GHz with each step having a time duration of 1ms (equipment limited). The large bandwidth of the QLL allows it to sustain 2GHz frequency step changes in frequency without losing lock.

Figure 4.19 shows the measured phase noise of the output of the QLL in both locked and unlocked states at 8GHz. A -40dBc/Hz improvement is observed at 1MHz offset, between the locked and unlocked states. Integrated output jitter (100kHz-1GHz) of 558fs and 577fs are measured at 8GHz for electrical and optical inputs respectively. At the highest locking frequency (11GHz) the integrated output jitter is 642fs. Figure 4.20 shows the measured phase noise (at 10MHz offset) of the locked QLL across the entire locking range. A phase noise variation of only 6dBc/Hz is observed as the frequency is varied from 4GHz to 11GHz. Thus, QLL maintains low phase noise performance across its entire locking range.

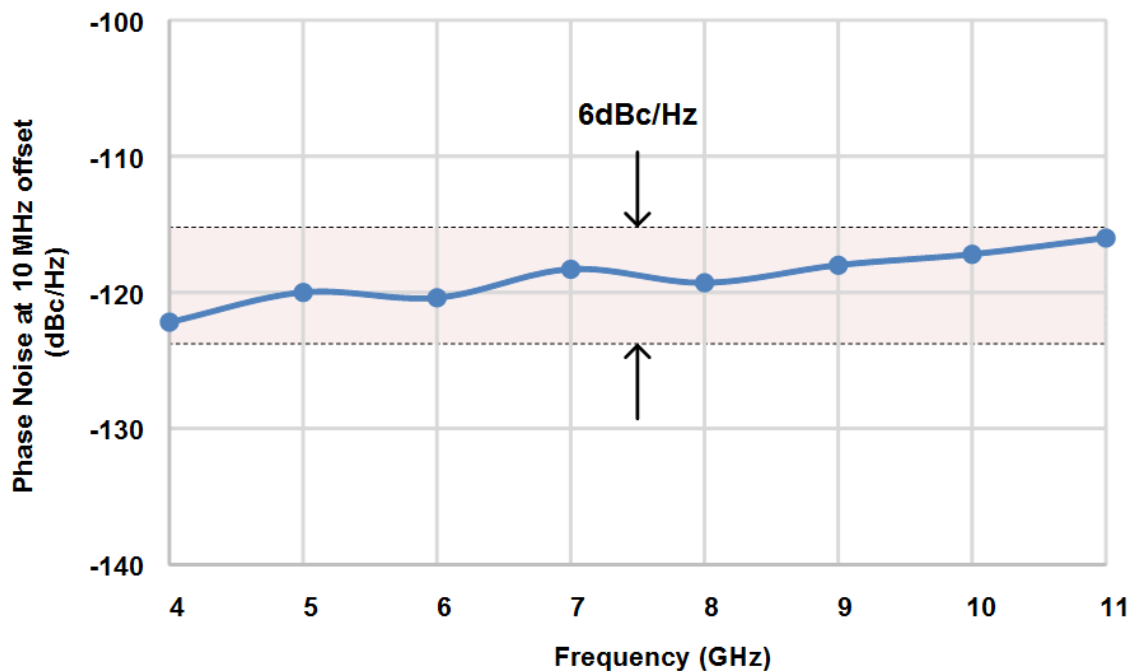


Figure 4.20: Measured phase noise of the locked QLL output across the entire locking range.

### 4.5.2 Reference and Supply Noise Filtering

The jitter transfer function is measured using the test setup shown in Figure 4.21. In this setup, a secondary clock ( $f_{\text{jitter}}$ ) is mixed with the  $90^\circ$  phase shifted primary clock ( $f_o$ ). This signal is transformed to a narrowband FM signal by summing it with a non-phase shifted primary clock. The resultant FM signal is used as the new reference clock. The secondary clock frequency ( $f_{\text{jitter}}$ ) is varied from 1kHz to 1.2GHz for each  $f_o$  and the spectrum components of the output and the reference are measured at the carrier ( $f_o$ ) and sideband ( $f_{\text{jitter}}$ ) frequencies (Figure 4.21) using an Agilent E4440A spectrum analyzer.

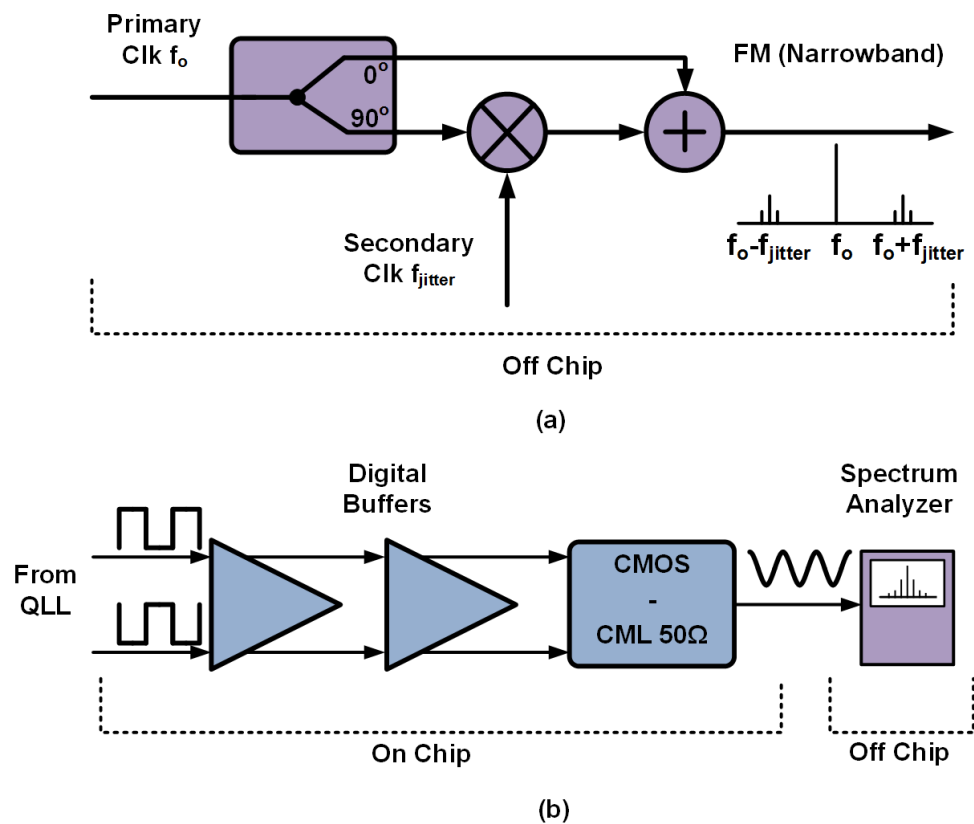


Figure 4.21: Measurement setup for generating FM signal reference. (b) Setup for measuring the spectrum of output signals.

Figure 4.22 (a) shows the measured jitter transfer function of the system for a reference frequency of 8GHz. It has a low-pass characteristic with a jitter tracking bandwidth (JTB) of 150MHz and a -20dB/dec attenuation, suggestive of a first-order system. High JTB helps in retaining the low frequency jitter while eliminating high frequency jitter as depicted in Figure

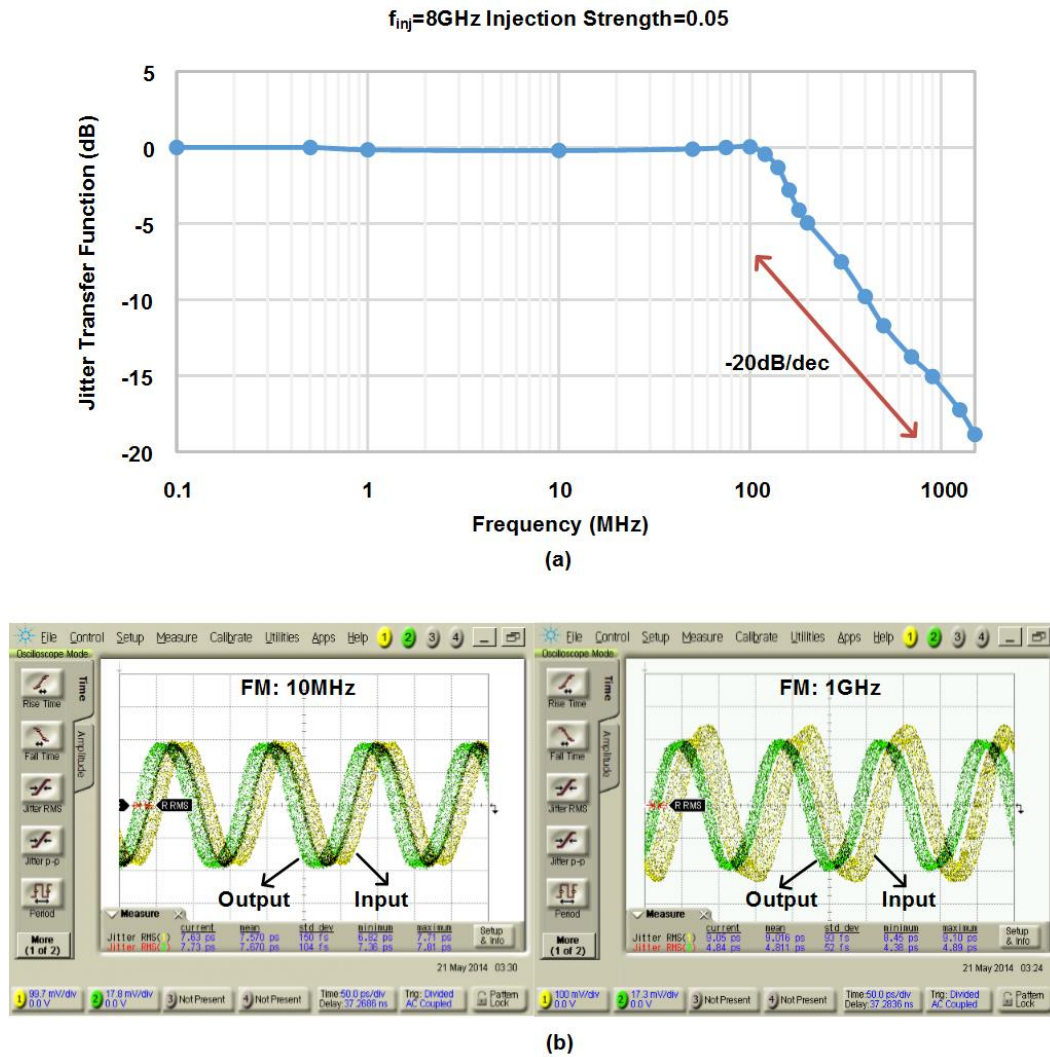


Figure 4.22: (a) Measured Jitter transfer function for 8GHz reference. (b) Response to low frequency (10 MHz) and high frequency (1 GHz) jitter.

4.22 (b). It is important to retain the low frequency jitter in forwarded clock receivers as low frequency jitter is correlated with the data [17].

Ring oscillators are susceptible to power supply variations [57]. Power supply variations directly translate into phase noise and jitter in the ring oscillators' output as their oscillation frequency is inversely proportional to  $V_{DD}$  (Figure 4.1). Substrate noise also directly affects the total oscillator jitter and is found to be strongly correlated to supply variations [57]. High frequency noise on the supply can be reduced adding bypass capacitors. However, low frequency  $V_{DD}$  noise is more difficult to eliminate with bypass capacitors because of significant area penalty. Injection locking helps in suppressing low frequency  $V_{DD}$  noise as shown in Figure 4.23.  $V_{DD}$

noise transfer has a high pass transfer function with a bandwidth of 150MHz and a -20dB/dec attenuation. This is complementary to the jitter transfer function measurement (Figure 4.23) and characteristic of a first order injection locked system as predicted by (2.14) and (2.15). The measurement is made by adding sinusoidal noise ranging from 10MHz to 1GHz on the  $V_{DD}$  using a bias tee and then measuring the relative frequency sidebands on the output in unlocked and locked cases (Figure 4.23).

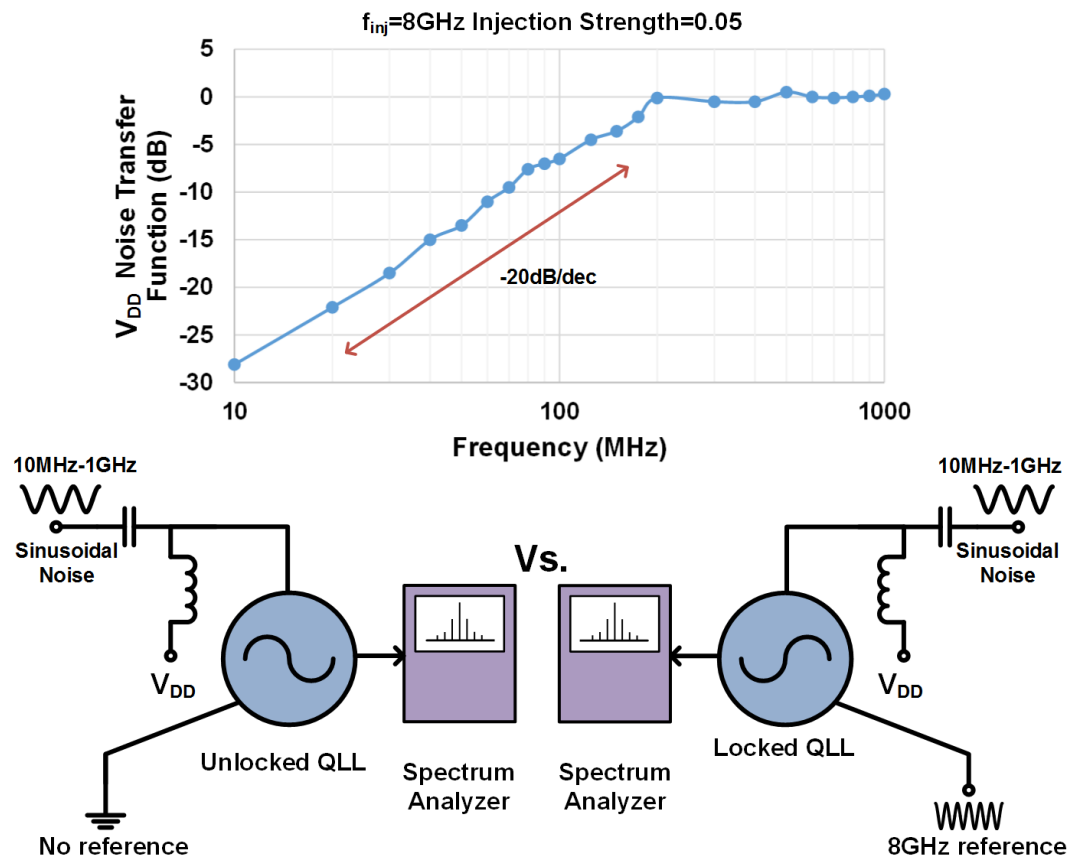


Figure 4.23: QLL response to supply noise compared to unlocked (no reference) case.

### 4.5.3 Quadrature Accuracy

Quadrature phase accuracy between the phases of the QLL outputs is confirmed by measuring their phase difference. The quadrature output phases (I and Q) of the QLL are selected using an on-chip digital multiplexor. Quadrature error is measured in a two-step process. First, the 'I' phase is selected and its phase difference with the input reference is measured. Then the digital

bit to the multiplexer is altered to select the 'Q' phase and its phase difference with the input reference is measured. The difference between the two measured values provides the quadrature phase error. This multiplexing allows the I and Q phases to have the same signal paths and hence a more accurate measurement can be made. Figure 4.24 shows the measured quadrature accuracy across 4-11GHz and the corresponding  $3\sigma$  error margins. An average offset of  $1.5^\circ$  (from  $90^\circ$ ) is observed between the two phases across the entire locking range.

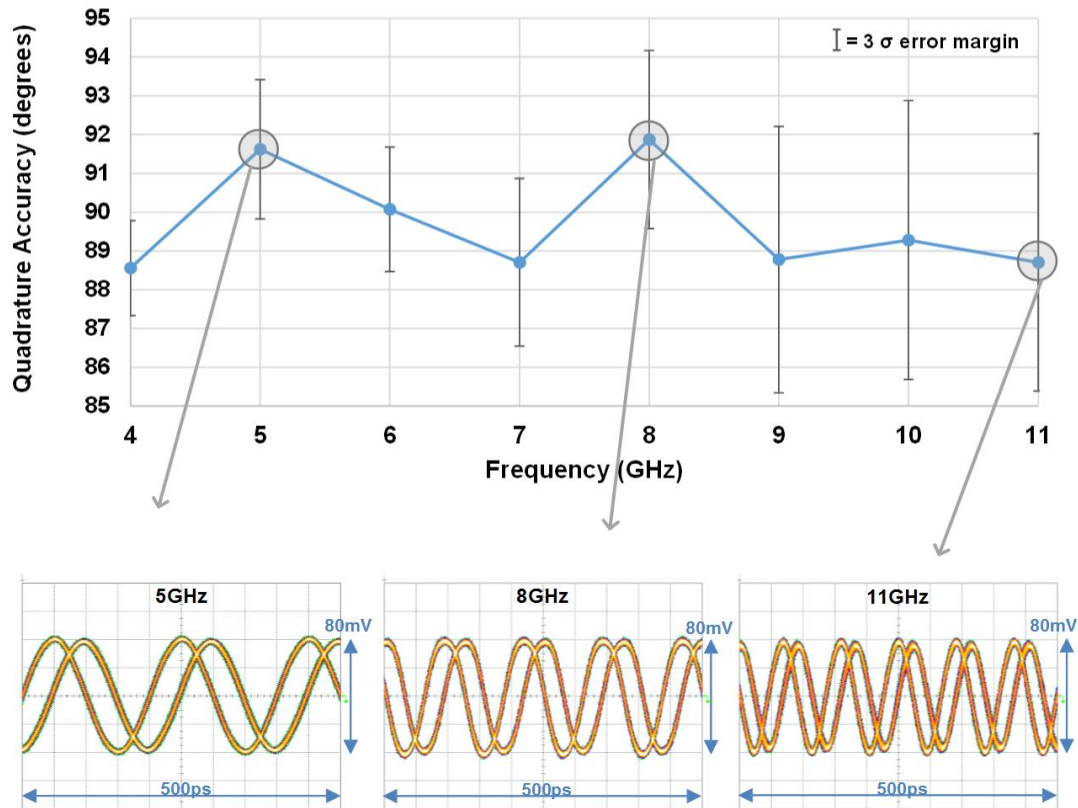


Figure 4.24: Measured quadrature phase error vs. reference frequency and measured quadrature phase waveforms at 5, 8 and 11GHz.

#### 4.5.4 Power Consumption

A power efficient two-stage ring oscillator and simplicity of injection locking ensures that the QLL circuit only consumes 2-2.8mW for 4-11GHz operation. As shown in Figure 4.25 (a), the power consumption increases with operation frequency. This is due to the digital nature of the ring oscillator. The power efficiency (Figure 4.25 (b)) decreases as frequency increases making it suitable for high-speed applications.

### 4.5.5 Comparison with Prior Art

	This work [58] [59]	[26]	[23]	[55]	[56]
Architecture	QLL	ILO	ILO	IL-PLL	PPM IL
Oscillator	CMOS Ring	CMOS Ring	CMOS Ring	CMOS Ring	CMOS Ring
Technology	28nm FD SOI	250nm BiCMOS	90nm CMOS	65nm CMOS	20nm CMOS
Locking range	4GHz - 11GHz	340MHz	203MHz	—	—
Output Integrated Jitter ( $\sigma$ )	558fs -577fs* (at 8GHz) 642fs (at 11GHz) (100kHz-1GHz)	—	<1.5ps (RMS Jitter at 2.5GHz)	0.7ps at 1.2GHz(1 0kHz- 40MHz)	434fs/268 fs at 15GHz (100kHz- 1GHz)
I/Q error	1.5°	0.7°**	4.5°	NA	NA
Active Area	0.003mm <sup>2</sup>	0.09mm <sup>2</sup>	0.026mm <sup>2</sup>	0.022mm <sup>2</sup>	0.044mm <sup>2</sup>
Supply	1V	3V	1.2V	—	1.25/1.1V
Power Diss. (P) at (F)	2.77mW at 11GHz	15mW at 2.7GHz	1.3mW at 2GHz	0.97mW at 1.2GHz	46.2mW at 15GHz
Figure of Merit (FOM)	-250dB	—	-238dB	-244dB	-247dB

\* Optical clock input \*\*Not measured directly

Table 4.1: Performance comparison of the QLL

Table 4.1 compares the QLL with prior art. The QLL based frequency tracking technique allows us to achieve the best locking range and robust I/Q performance compared to other works. Our jitter and power performance is comparable with the state-of-the-art. We achieve the best figure of merit (FOM) which was defined as

$$FOM = 10 \log \left[ \left( \frac{\sigma}{1s} \right)^2 \cdot \frac{P}{1mW} \cdot \frac{1GHz}{F} \right] \quad (4.18)$$

where  $\sigma$  is the RMS integrated jitter, P is the power consumption and F is the frequency of operation. Thus the lowest FOM will be achieved by a system with lowest jitter and power consumption at the highest frequency of operation.

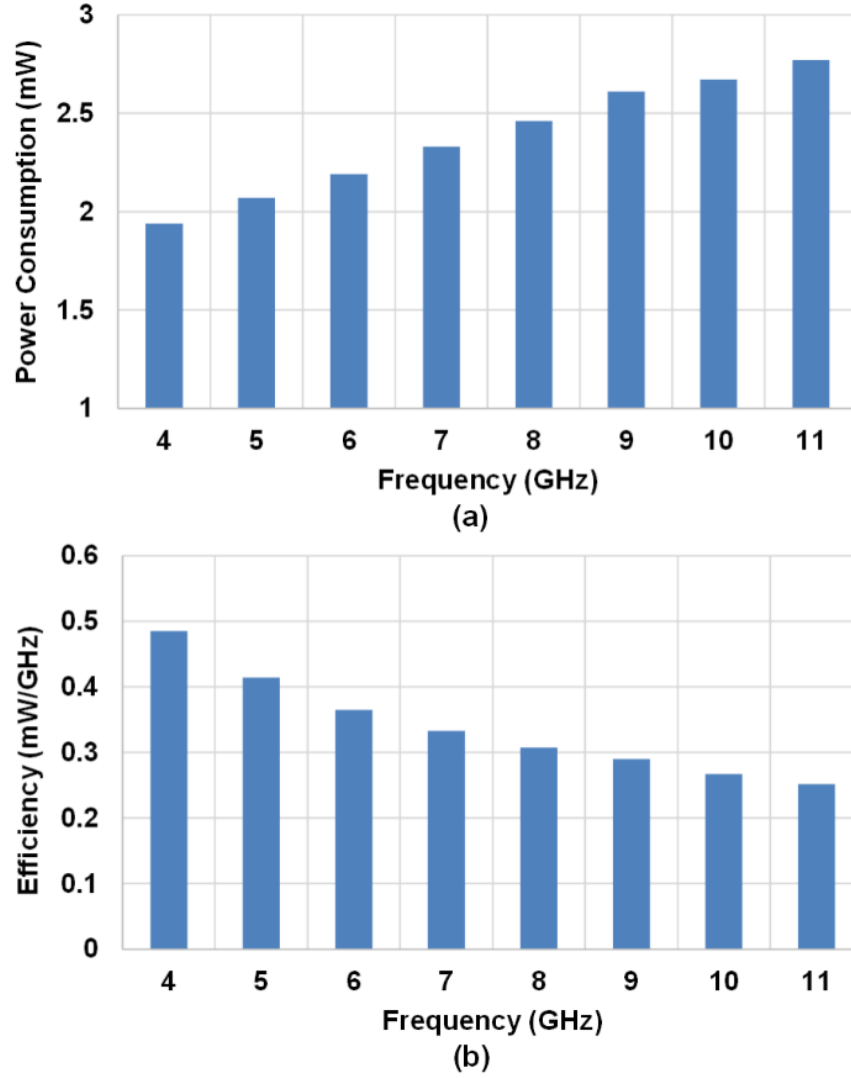


Figure 4.25: (a) Power consumption of the QLL vs. frequency. (b) Power efficiency of the QLL vs. frequency.



## 4.6 Summary

A new frequency tracking technique based on the quadrature phase error cancellation in an injection locked ring oscillator was introduced and analyzed. The technique improves the ILOs' locking range from 5.5% (7-7.4GHz) to 90% (4-11GHz) without using a phase frequency detector (PFD). The dynamics of the system were derived and were shown to have first order characteristics. This guarantees stability without peaking, unlike a second order injection locked PLL. The system was used to generate accurate quadrature phases, without any frequency division, from a single phase of reference clock input, supplied electrically or optically. A power efficient two stage ring oscillator, combined with the low jitter performance of the ILO, allows us to achieve the best FOM.

The theory of the QLL also applies to subharmonic and superharmonic injection locked quadrature ring oscillators. And because the phase detector used in the QLL loop only uses the phases from the ILO for comparison; this technique could be easily extended to be used for wideband injection in injection locking based frequency multipliers [17] and CDR [39].

# Chapter 5: QLL Based Clocking for a Four Channel Quarter-Rate Optical Receiver

As discussed in Chapter 1, integrated circuit scaling has enabled a huge growth in processing capability, which necessitates a corresponding increase in inter-chip communication bandwidth. This trend is expected to continue, requiring both an increase in the per-pin data rate and the I/O pins.

While I/O circuit performance benefits from technology scaling, the bandwidth of electrical channels does not scale with the same trend. Especially as the data rate increases, they exhibit excessive frequency-dependent loss, which results in significant inter-symbol interference (ISI). In order to continue scaling data rates, equalization techniques can be employed to compensate for the ISI. However, the power and area overhead associated with equalization make it difficult to achieve target bandwidth with a realistic power budget.

A promising solution to the I/O bandwidth problem is the use of optical inter-chip communication links. The negligible frequency dependent loss of optical channels provides the potential for optical link designs to fully utilize increased data rates provided through CMOS technology scaling without excessive equalization complexity. Optics also allow very high information density through wavelength division multiplexing (WDM). Hybrid integration of optical devices with electronics has been demonstrated to achieve high performance [60] and recent advances in silicon photonics have led to fully integrated optical signaling [61]. These approaches pave the way for massively parallel optical communications. In order for optical interconnects to become viable alternatives to established electrical links, they must be low cost and have competitive energy and area efficiency metrics. Dense arrays of optical detectors require very low-power, sensitive, and compact optical receiver circuits. Existing designs for the input receiver, such as TIA, require large power consumption to achieve high bandwidth and low noise, and can occupy large area due to bandwidth enhancement inductors. In addition to

receiver circuits, the clocking circuit also needs to be more power efficient. In conventional clocking schemes that employ a global PLL-locked reference and a digitally distributed clock through buffer chains and clock grids, the power required to constantly switch the large capacitive loads can consume 40% of the chip's total power budget [15]. In recent years, injection-locked clocking has been proposed as a solution for reducing power consumption of the clock network [53]. Also, as discussed in Chapter 1, ILOs are well suited for forwarded clock receivers because of their high bandwidth jitter filtering properties [17] and easy deskewing. However, ILOs are plagued by their small locking range making them susceptible to PVT variations and unsuitable for wideband receivers.

In the previous chapter we introduced the quadrature locked loop (QLL); a frequency tracking technique to increase the locking range of the ring based quadrature injection locked oscillator. This technique was used to generate the accurate quadrature phase from a single phase of electrical/optical clock without any frequency division. In this chapter, we use QLL based clocking for a four channel, quarter-rate, forwarded clock, optical receiver. QLL is used to generate accurate clock phases for a four channel optical receiver using a forwarded clock at quarter-rate. The QLL drives an ILO at each channel, without any repeaters for local quadrature clock generation, ensuring low power clocking. Each local ILO has deskew capability for phase alignment. The wide locking range of the QLL ensures reliable operation across wide data rates. A compact low-power optical receiver [62] maintains per-bit energy consumption across 16Gb/s-32Gb/s by adaptive Body Biasing (BB), using the  $V_{ctrl}$  generated by the QLL.

This chapter is organized as follows: Section I describes the system architecture of the optical receiver and adaptive body biasing. In Section II we describe the QLL based deskewing technique. Hardware measurement results for the optical receiver are presented in Section III. Section VI summarizes the work and presents conclusions. Finally, in Section V, we propose an extra dimension to the QLL idea that will be useful for future applications.

## 5.1 System Architecture

The clocking structure is shown in Figure 5.1. The optical receiver has four optical data inputs and one forwarded clock (electrical/optical) input. The optical clock is converted to an electrical clock using a TIA as mentioned in the previous chapter. The electrical clock is then sent to a global QLL circuit. The QLL generates four quadrature phases. The four phases are distributed

without any repeaters and sent to local ring oscillators, which are placed near the clocked optical receivers. The local ring oscillators are injection locked to the global clock and frequency of oscillation is varied to control the phase of the local ring oscillator's output (deskew). The data receivers have a quarter rate architecture and hence require accurate quadrature phases. Symmetric injection with four clock phases ensure that quadrature accuracy is maintained even with deskew. The details of the same will be described in later sections.

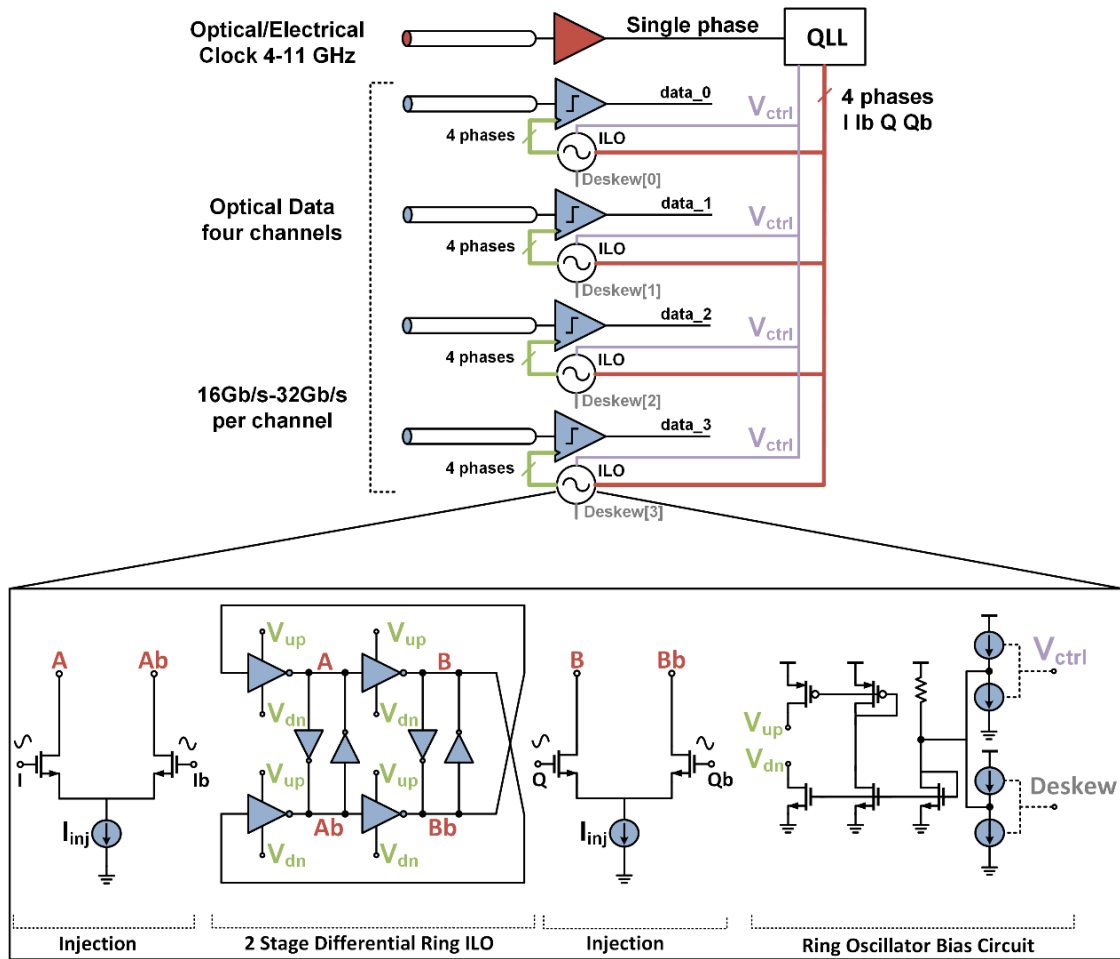


Figure 5.1: QLL based clock distribution architecture for a 4 channel optical receiver

### 5.1.1 Optical Receiver

An optical receiver uses a photodiode to convert an incoming optical signal to electrical current. If a simple resistor is used to convert the current of a photodiode to a voltage, for a target signal-

to-noise ratio (SNR) and a given photodiode capacitance, the input time constant ( $RC$ ) severely limits the bandwidth and data rate of the receiver. In order to increase the  $RC$  bandwidth while maintaining the same gain, transimpedance amplifiers (TIAs) are commonly employed. The overall bandwidth of conventional TIAs is chosen to be  $(RC)^{-1}$ .

Such high-bandwidth TIAs are highly analog, power hungry, and do not scale well with technology. A more recent approach uses an integrating front-end and a resistor termination with a time constant that is much larger than the bit interval ( $RC \gg T_b$ ) [14]. Dynamic offset modulation is then used to provide a constant voltage at its input regardless of the data sequence.

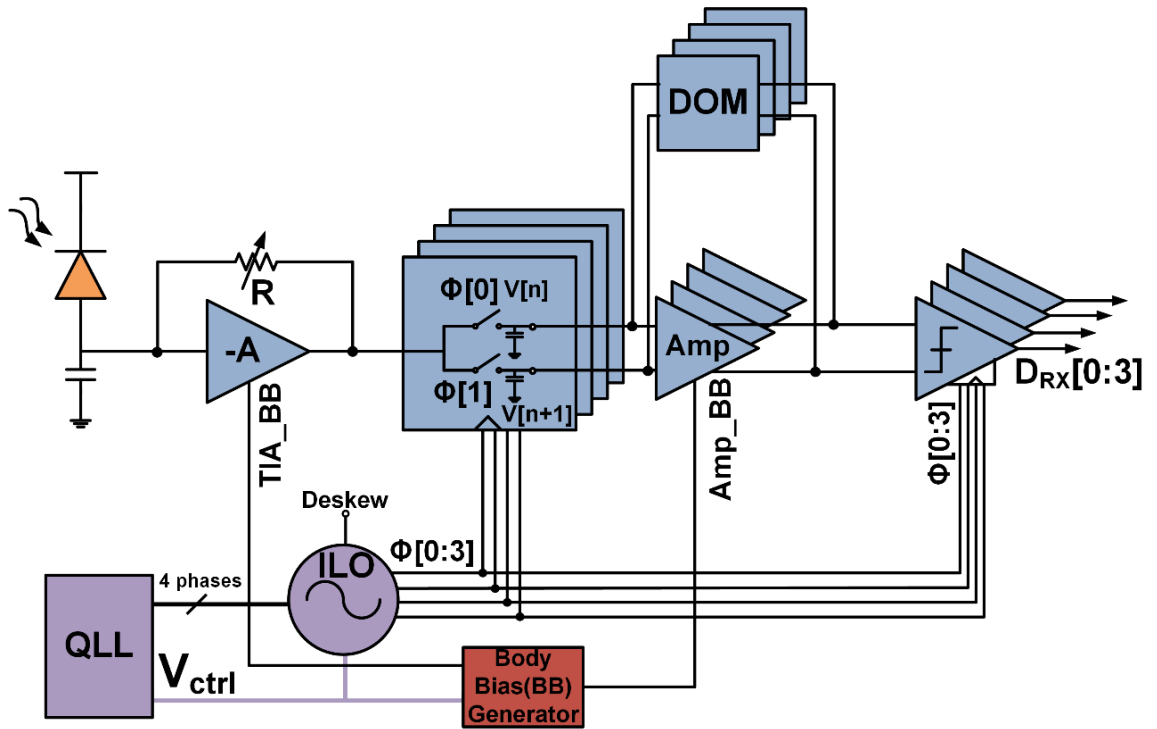


Figure 5.2: Single channel quarter-rate receiver.

Figure 5.2 shows the top-level architecture of the adaptive receiver (single channel) with dynamic BB using  $V_{ctrl}$  of the QLL. The first stage of the receiver is a low-power TIA with  $3k\Omega$  feedback resistor. The TIA's output is sampled at the end of two consecutive bits ( $V_n$ ,  $V_{n+1}$ ) and these samples are compared to resolve each bit. The TIA provides isolation between PD's capacitor and sampling capacitors, which reduces charge-sharing effect and enables use of ultra-low capacitance photodetectors in scaled silicon photonic technologies. Besides, for a given PD capacitance, S/H capacitors can be chosen to be bigger (even comparable to PD's capacitance)

to relieve  $KT/C$  noise. This had been an important bottleneck in double sampling optical receivers in the past [14], [63]. Sampling capacitors are followed by an amplifier, which also provides isolation between sampling nodes and sense-amp to minimize kickback. The dynamic offset modulation employed at the output of the amplifier introduces an offset so that the sense-amp differential input is always constant regardless of the previous bit. The sense-amp is followed by an SR-latch to retrieve the NRZ data. Similar to [62], dynamic offset modulation provides a constant voltage at sense-amp's input regardless of the bit sequence. De-multiplexing factor of four is achieved immediately after the TIA using quarter-rate clocked samplers.

The quarter-rate architecture of the receiver, necessitates accurate quadrature clocks. In addition, due to the multiple channels there is a need for per channel deskewing to align the clock to the data. We explain the details of accurate quadrature phase generation and deskewing in next sections.

### 5.1.2 Adaptive Body Biasing

The optical receiver implementation shown in Figure 5.2 has analog building blocks with bias currents. These are biased to provide the maximum bandwidth and gain for operation at the highest data rates, thus consuming maximum power. For operation at lower data rates a high bandwidth is not required. However, since the bandwidth of the analog components do not change with data rates, power is 'wasted'. This leads to degradation of the power efficiency (the energy per-bit) of the optical receiver at lower data-rates [14], [63], [62].

It is advantageous to bias the circuits adaptively so as to reduce the bias current (and hence power) of the analog components at lower data rates. This requires information about the data rate and a method to use this information to change the bias currents of the analog components. The former is provided by the QLL as it generates the  $V_{ctrl}$  (Figure 5.4) which is dependent on the input clock frequency, hence the data rate. The latter is achieved by taking advantage of the FD SOI (fully depleted silicon on insulator) technology as described below.

The prototype chip is fabricated in 28nm FD SOI CMOS. In the FD SOI CMOS process, the channel forms in an ultra-thin (7nm) layer of intrinsic silicon over a layer of buried oxide (BOX) (Figure 5.3 (a)). Given the extreme thinness of the buried oxide layer (25nm) and the conducting layer under the BOX, effect of body biasing (BB) is improved compared with standard CMOS process. By connecting the transistor bodies to a bias network in the circuit layout rather than to power or supply,  $V_{th}$  of the transistors can be tuned by 80mV per 1V

modulation of  $V_{BB}$  (Figure 5.3 (b)). This proves crucial in adaptively body biasing the critical devices in the amplifier and the TIA.

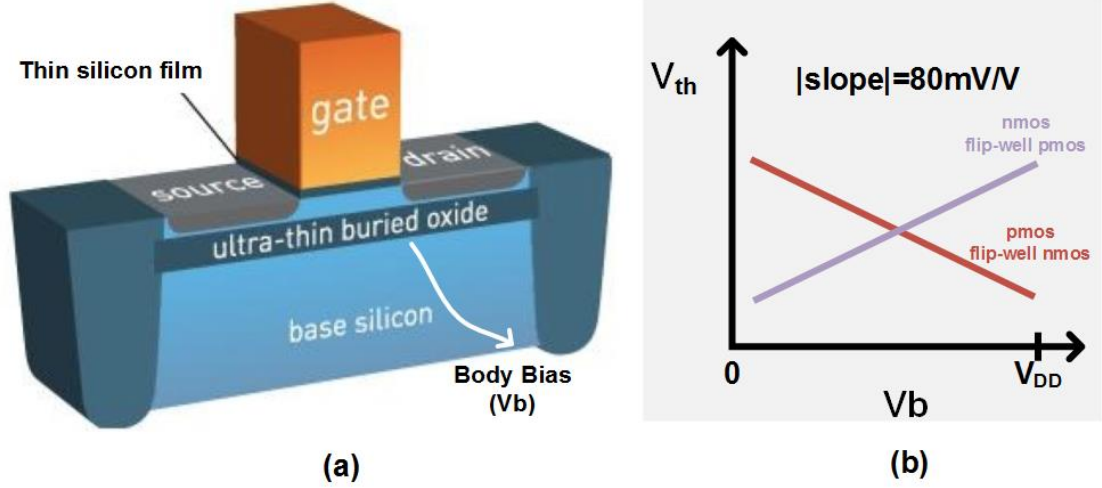


Figure 5.3: (a) FD SOI MOS structure (b) Threshold voltage ( $V_{th}$ ) variation with back bias ( $V_b$ )

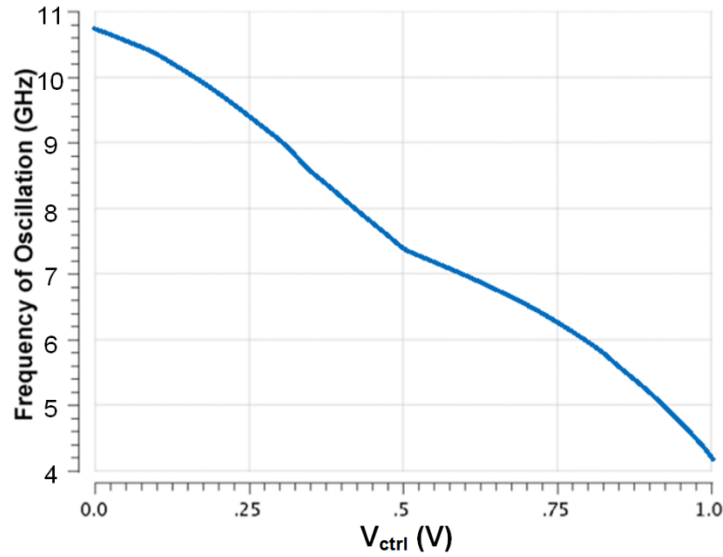


Figure 5.4: Simulated ring oscillator characteristics.

The  $V_{ctrl}$  generated by the QLL follows the ring oscillator's characteristics as shown in Figure 5.4, i.e. as the reference frequency increases the  $V_{ctrl}$  decreases from 1 to 0. The body bias generator is designed so that the transfer function from  $V_{ctrl}$  of the QLL to  $V_{BB}$  generator outputs,

is such that, receiver's building blocks optimally work at any given data-rate. By fitting the transfer function of the body bias generator from  $V_{ctrl}$  of QLL to body bias of respective blocks, the gain-bandwidth product of the TIA and Amp's gain are adaptively set to be proportional to the data-rate. The optical receiver and body bias generator were designed by Saman Saeedi.

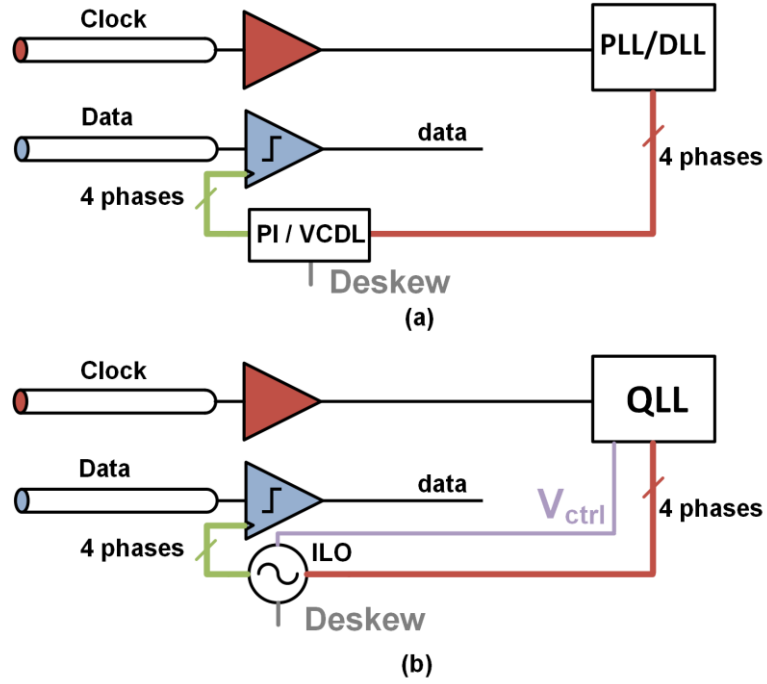


Figure 5.5: Deskewing in forwarded clock links; (a) conventional (b) proposed.

## 5.2 Deskew

We have used a forwarded clock (FC) architecture for the four channel optical receiver. At multi-Gb/s speeds each data channel may have phase mismatch or skew with respect to the reference clock. This necessitates a per channel phase shift or “deskewing”. The conventional approach to achieving this is to use a PLL/DLL followed by a phase interpolator (PI) or a voltage controlled delay line (VCDL) [64] (Figure 5.5 (a)). As discussed in Chapter 1, PLL based systems generally have second order characteristics which may lead to jitter peaking. Also, their small jitter tracking bandwidth leads to filtering of useful correlated (with data) jitter. DLLs, on the other hand, have an all pass characteristic, which allows the high frequency uncorrelated jitter to pass thorough. Injection locking based systems, (Figure 5.5 (b)), on the other hand have a first



order characteristics with a high tracking bandwidth, which do not filter out the useful correlated jitter and suppress the uncorrelated high frequency jitter. Figure 5.6 summarizes the properties of PLL, DLL and ILO. Compared to traditional VCDL or PI based approaches, ILO-based deskew provides a better supply noise rejection (Figure 4.23) and lower power [29] .

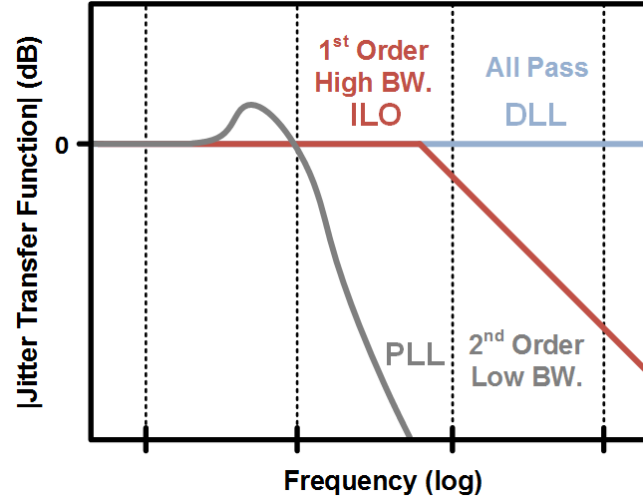


Figure 5.6: Jitter transfer function characteristics of PLL, DLL and ILO.

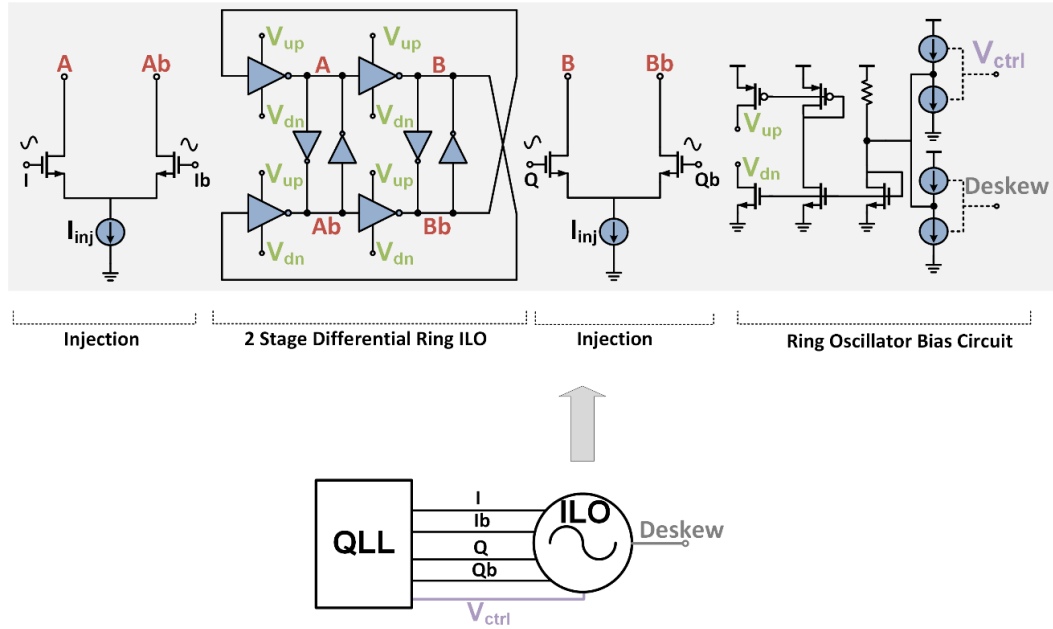


Figure 5.7: QLL based deskewing architecture (single channel).

Figure 5.7 (b) shows the architecture of the QLL based clocking for a single channel. The QLL is used to generate accurate clock phases for a four channel optical receiver using a forwarded clock at quarter-rate. The QLL drives an ILO at each channel, without any repeaters, for local quadrature clock generation for the quarter rate receiver. Due to their high sensitivity [15], ILOs can operate with very small input amplitude (100mV); this allows the reference clock to be distributed without repeaters, with low power. Figure 5.7 shows the structure of the local ILO. It has the same two stage pseudo differential architecture as the ring oscillator used in the QLL (Figure 4.15). The  $V_{ctrl}$  generated by the QLL is also distributed to the local ILOs. This is used to set the natural frequency of the ILO ( $f_o$ ) same as that of the injected frequency ( $f_{inj}$ ). It ensures that the local ILOs do not go out of lock as the data rate changes. To invoke deskew, the ( $f_o$ ) of the local ILO is varied externally (Figure 5.7). All four phases of clock generated by the QLL are distributed and used for symmetric injection in the local ILOs. This ensures no quadrature mismatches even with deskew. This is described in a greater detail in the next section.

### 5.2.1 Symmetric Injection

As described earlier in Chapter 2, deskew in an ILO (locked at  $f_{inj}$ ) can be performed by varying the natural frequency of oscillation ( $f_o$ ) of the oscillator. The amount of deskew is given by

$$deskew = \sin^{-1} \left( \frac{f_o - f_{inj}}{f_l} \right) \quad (5.1)$$

where  $f_l$  is the locking range of the ILO.

If the input clock is injected in only one of the delay stages, the asymmetry between the effective delay of the delay stages leads to quadrature phase mismatch between I and Q phases of the oscillator. As derived in Chapter 4, it is given by

$$Quad. Error = \frac{\pi}{2} \left( \frac{f_{inj}}{f_o} - 1 \right) \quad (5.2)$$

Combining (5.1) and (5.2) we get

$$Quad. Error = \frac{\pi}{2} \left( \frac{-f_l \sin(deskew)}{f_l \sin(deskew) + f_{inj}} \right) \quad (5.3)$$

(5.3) suggests that as the deskew increases so does the magnitude of the quadrature error. So as  $f_o$  is varied to invoke deskew, the I and Q phases of the ILO don't shift by an equal amount. Inaccuracies in the quadrature phases may lead to increased BER in the quarter rate receiver.

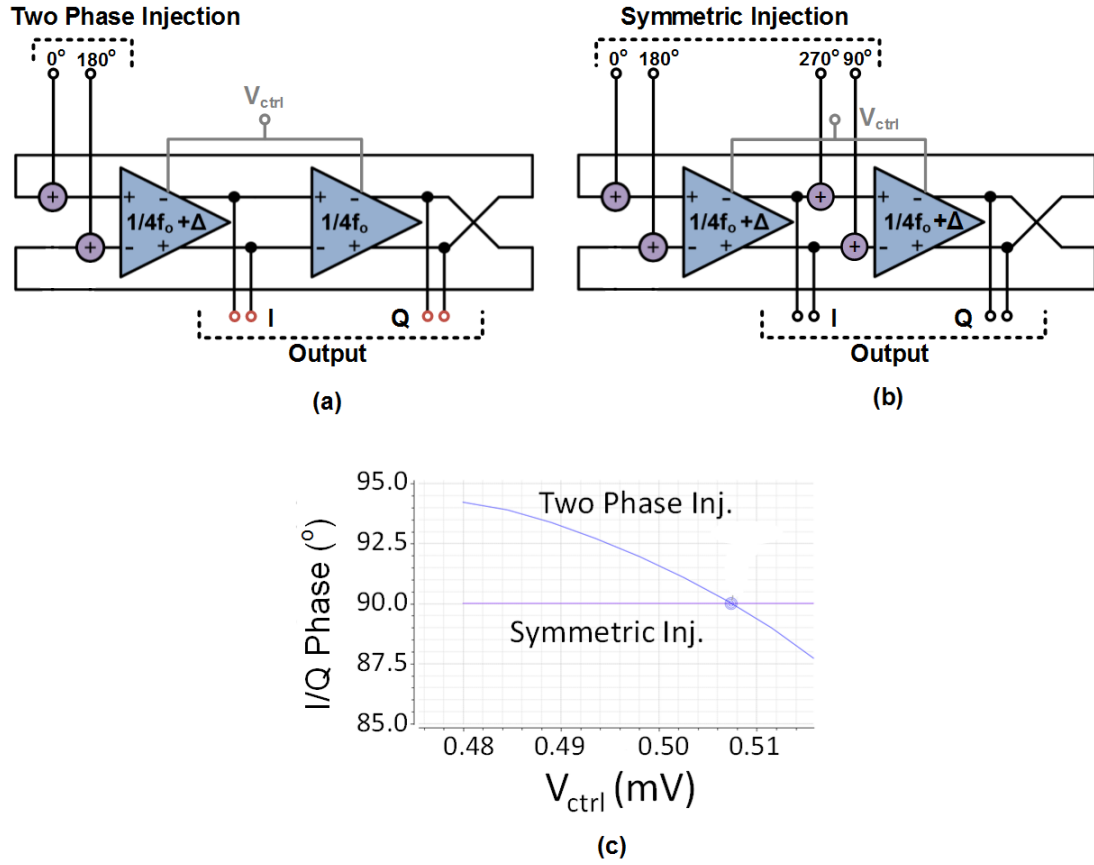


Figure 5.8: Symmetric vs. two phase injection. (a) Two phase injection architecture. (b) Symmetric injection architecture. (c) Simulation based comparison of two phase and symmetric injection.

The trade-off between deskew and quadrature error is broken by injecting all four phases of clock generated by the QLL into both the delay elements of the ILO (Figure 5.8 (b)). This symmetric injection of clock allows the variation of the delay of both the delay elements by equal amount. Thus, even when the  $f_o$  of the ILO is varied, the inherent symmetry in the delay elements allows the phase relationship between the I and Q phases to be constant, resulting in

no quadrature error. This fact is exemplified in the simulation of ILO's with two phases (clock and clock bar) and symmetric injection, as shown in Figure 5.8 (c). The  $V_{ctrl}$  of the two ILOs is varied to change their  $f_o$ . This leads to quadrature error in the former cases whereas in the latter the phase relationship between the I and Q phases remains  $90^\circ$ .

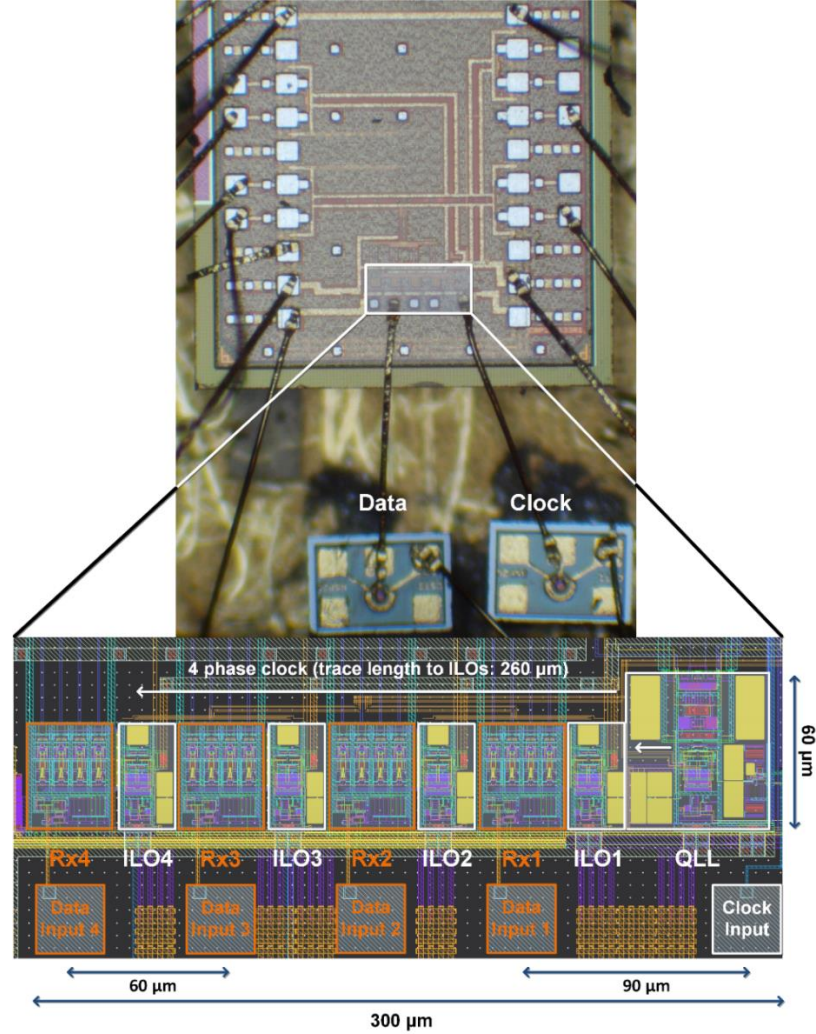


Figure 5.9: Chip micrograph and layout details.

## 5.3 Hardware Measurements

The test chip is fabricated in a 28nm FD SOI CMOS process. The die micrograph and core detail are presented in Figure 5.9. The core area is  $300\mu\text{m} \times 60\mu\text{m}$ , in a  $5\text{mm} \times 1.1\text{mm}$  die. The top metal layers are designed to be compatible with copper-pillar flip-chip bonding as well as bond-

wire. The clock output from the QLL is symmetrically distributed to all four local ILOs with a total trace length  $260\mu\text{m}$  (Figure 5.9).

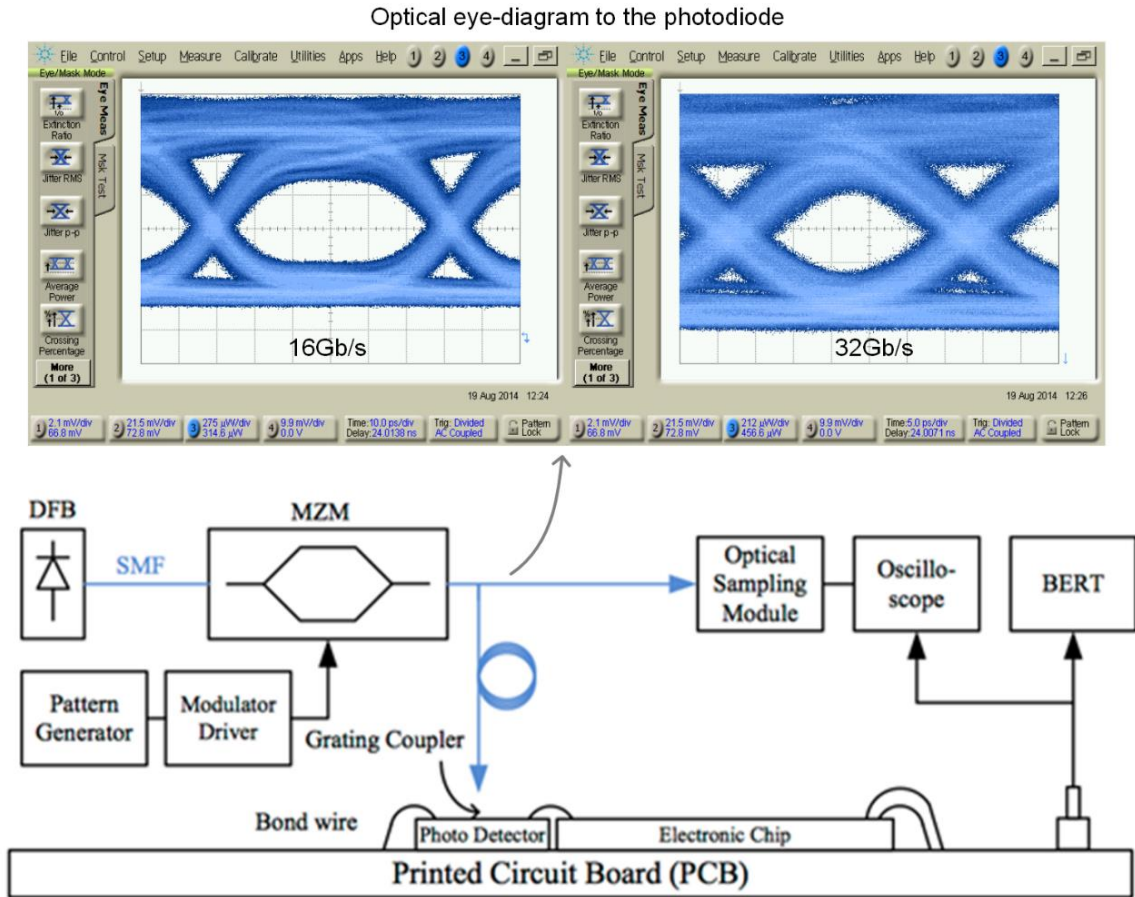
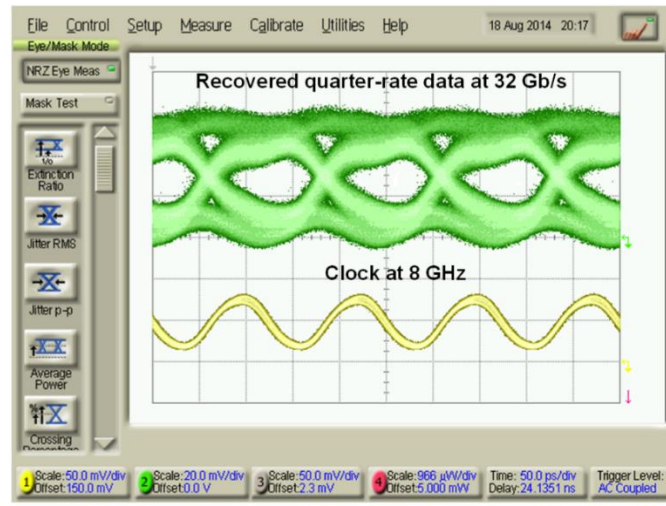


Figure 5.10: Test setup for optical receiver.

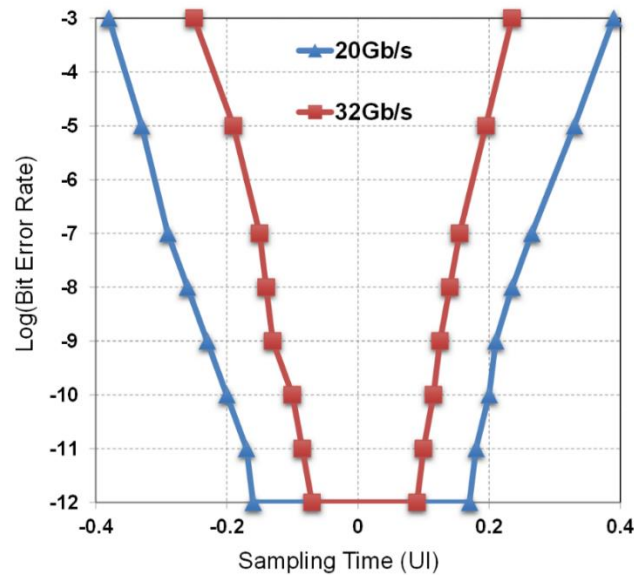
### 5.3.1 Test Setup

The optical test setup is shown in Figure 5.10. For optical testing, the receiver is bonded to a photodiode with responsivity of  $0.9\text{A/W}$  (Figure 5.9). The total capacitance at the input node was estimated to be  $120\text{fF}$ . The optical beam from a  $1550\text{nm}$  distributed feedback (DFB) laser is modulated by a high speed Mach-Zender modulator (MZM) and coupled to the photodiode with a single-mode fiber. The optical fiber is placed close to the photodiode aperture using a micro-positioner (butt coupling). As the beam has a Gaussian profile, the gap between the fiber tip and the photodetector causes optical intensity loss. Combined optical loss due to the optical coupling and optical connector is measured to be  $2.8\text{dB}$ . Quarter-rate clock generated by the

pattern generator was used as (electrical) reference for the QLL.



(a)



(b)

Figure 5.11: Measured eye diagram (a) and BER (b) with PRBS 15 optical data at 32Gb/s.

### 5.3.2 Receiver BER Measurements

The functionality of the receiver is validated using the PRBS-7, 9, 15 sequences generated by the pattern generator (Figure 5.10). Each of the four channels are tested separately. Figure 5.11 (a) shows the recovered quarter-rate data eye diagram for 32Gb/s optical data, for one of the

channels. Figure 5.11 (b) shows the bath curves for 32Gb/s and 20Gb/s. Error free ( $\text{BER}=10^{-12}$ ) operation is shown for 0.16UI and 0.33UI for 32 and 16Gb/s respectively. The maximum achievable data-rate (32Gb/s) is limited by the maximum data-rate of the external pseudo random bit sequence (PRBS) generator.

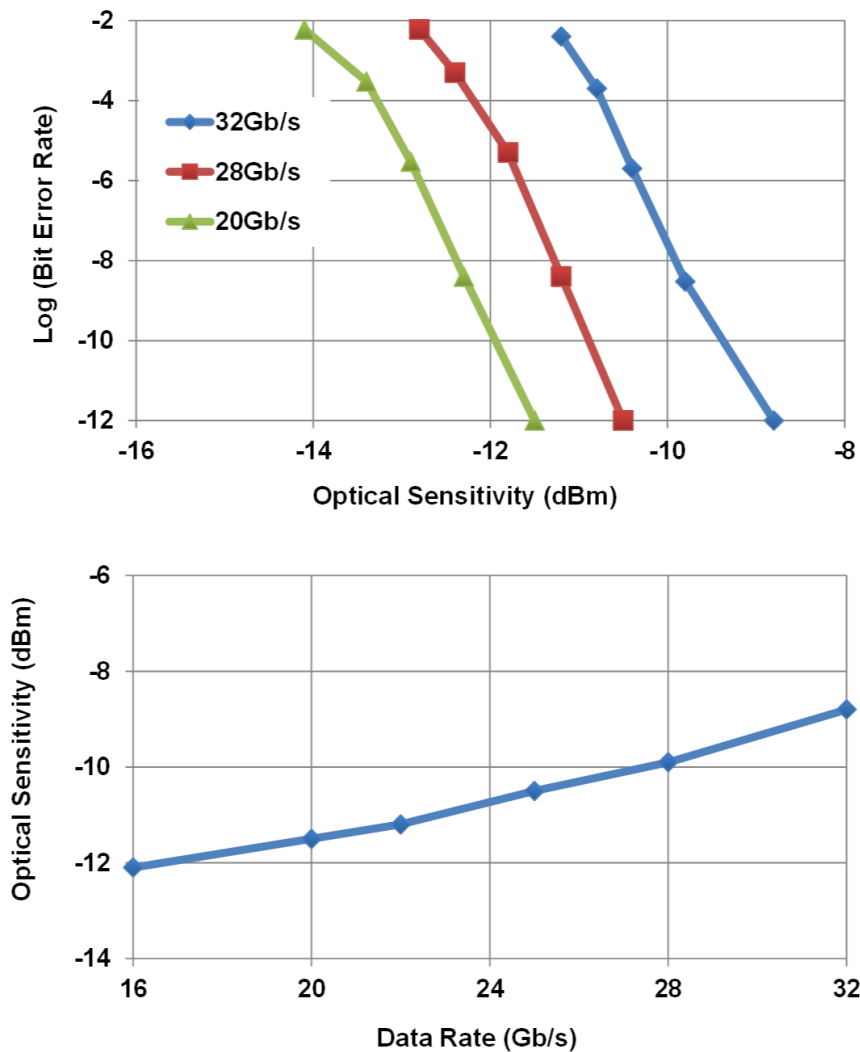


Figure 5.12: BER vs. optical power (receiver sensitivity) at different data-rates (top). Optical sensitivity vs. data rate (bottom).

Optical receiver sensitivity is defined as the minimum optical power that a receiver needs to operate reliably with error free ( $\text{BER}=10^{-12}$ ) operation. Figure 5.12 shows the measured BER as the optical power is varied for different data rates. From this information we derive the optical



sensitivity as shown in Figure 5.12. The receiver achieves more than -12dBm of sensitivity at 16Gb/s, which reduces to -10dBm at 28Gb/s and -8.8dBm at 32Gb/s. Sensitivity degradation with increased data rate is mainly due to reduced bit interval and integration time.

### 5.3.3 Deskew Range

The amount of phase shift allowed by the local ILO is measured by varying the deskew (shown in Figure 5.7) from 0 to  $V_{DD}$  at 8GHz for 32Gb/s operation. Agilent 86100D sampling oscilloscope is used to record the ILO waveforms for different values of the  $V_{ctrl}$ . A total deskew range of  $137^\circ$  is measured. The optical receiver needs a maximum deskew range of  $90^\circ$  because of its quarter-rate architecture, so a measured deskew range greater than  $90^\circ$  proves sufficient.

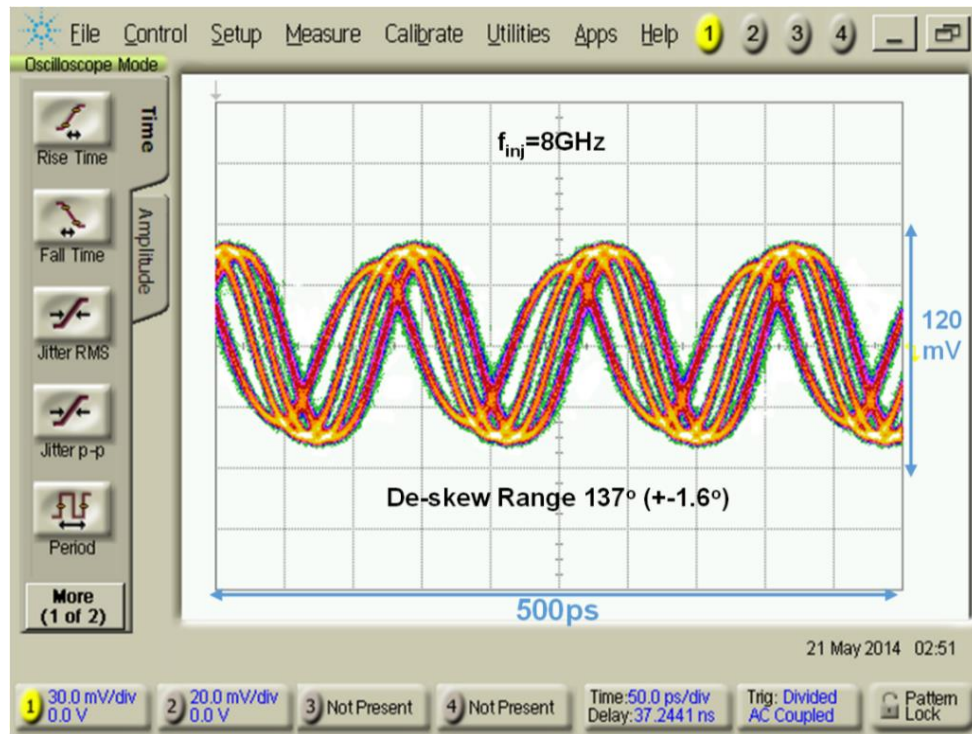


Figure 5.13: Measured deskewed waveform for 32Gb/s data.

### 5.3.4 Power Consumption

The receiver's power breakdown and power efficiency (energy per-bit) are shown in Figure 5.14. Total power consumption per channel at the highest data rate (32Gb/s) is 4.87mW. The QLL and local ILOs consume a third of the total power.



To show the efficacy of the adaptive body biasing scheme, two sets of measurements are done with the adaptive  $V_{BB}$  generator on and off (Figure 5.14). When adaptive  $V_{BB}$  generator is active, the per-bit energy efficiency improves from 103fJ/b at 32Gb/s to 94fJ/b at 16Gb/s. Without the body bias the per-bit energy efficiency at 16Gb/s is 160fJ/b.

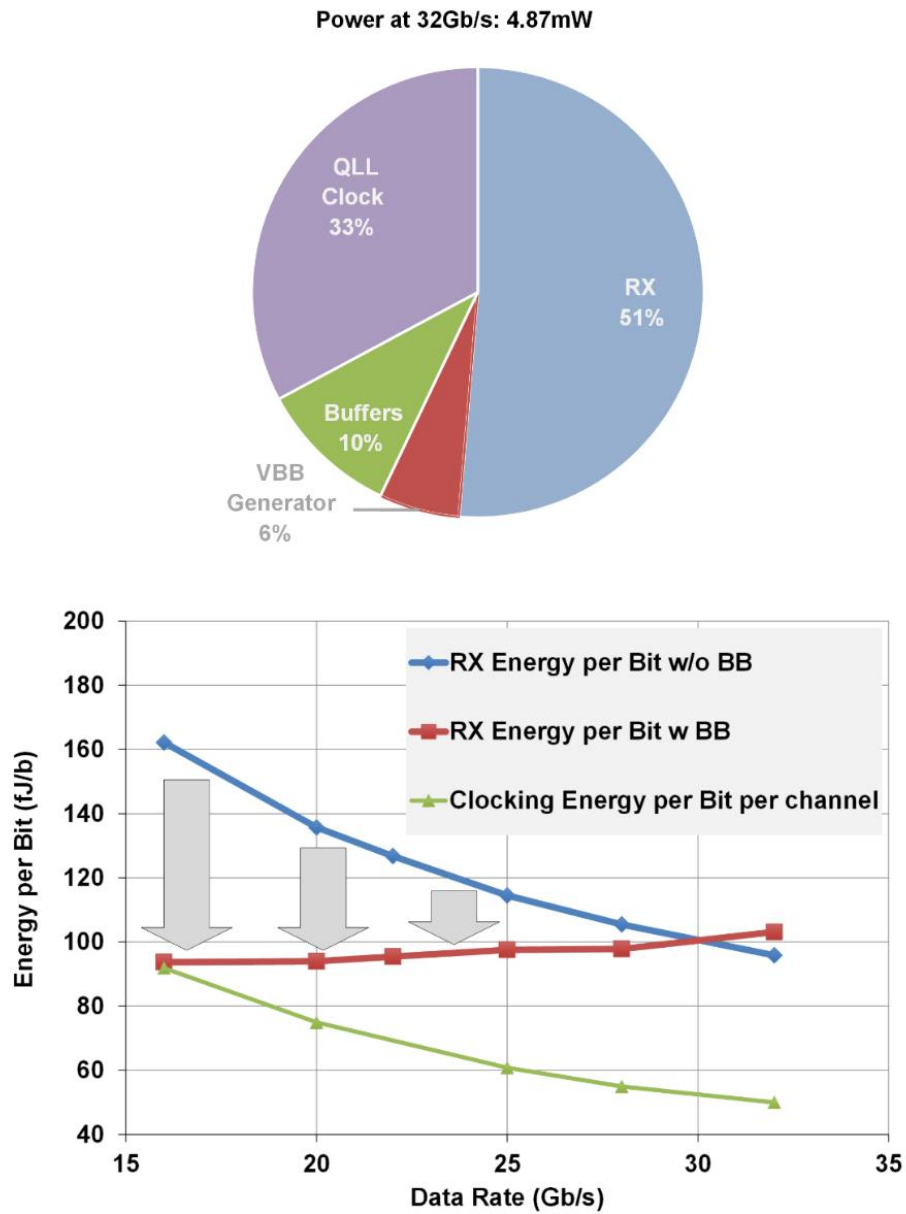


Figure 5.14: Power consumption breakdown at 32Gb/s (top) and energy efficiency per bit across different data rates.

### 5.3.5 Comparison with Prior Art

	This work [58]	[62]	[65]	[66]
Technology	28nm FD SOI	28nm CMOS	65nm CMOS	28nm CMOS
Data-Rate	32Gb/s	25Gb/s	28Gb/s	28Gb/s
Efficiency	103fJ/bit data and 50fJ/bit clock	170fJ/bit*	3.25pJ/bit	1.03pJ/bit
Active area	0.3x0.06mm <sup>2</sup> (4 channel)	0.0018mm <sup>2</sup>	3.25mm <sup>2</sup>	0.318mm <sup>2</sup>
Sensitivity (Optical)	-8.8dBm at 32Gb/s	-6.8dBm at 25Gb/s	-9.7dBm at 25Gb/s	-6dBm at 10Gb/s

\* Excludes clocking.

Table 5.1: Performance comparison of the optical receiver.

Table 5.1 compares the optical receiver with prior art. Low power QLL based clocking and body biasing helps achieve the highest efficiency compared to the state-of-the art. Ring oscillator based clock distribution helps achieve a very compact design, smallest compared to other works.

## 5.4 Summary

In the previous chapter we introduced the idea of the quadrature locked loop (QLL); a frequency tracking technique to increase the locking range of the ring based quadrature injection locked oscillator. This technique was used to generate accurate quadrature phases from a single phase of electrical/optical clock without any frequency division. In this chapter, we introduced QLL based clocking for a four channel quarter-rate optical receiver. It validated the QLL as a robust building block for future designs.

The system was implemented in 28nm FD SOI CMOS and supports up to 32Gb/s of data-rate. The unique properties of the FD SOI technology were used in synchronization with the QLL and optical receiver to achieve an ultra-low power consumption of 153fJ/bit. Experimental results validated the feasibility of the QLL and the optical receiver for ultra-low-power, high-data-rate, and highly parallel optical links.

## 5.5 QLL: Future Work

In this last section we explore an additional dimension to the QLL circuit that can be used by future IC designers. In the previous parts of this chapter we explained how a combination of QLL and ILO's could be used for deskewing. While this yields a more power efficient solution for parallel links, a standalone QLL based deskewing would more suitable for single channel forwarded clock receivers (Figure 5.15).

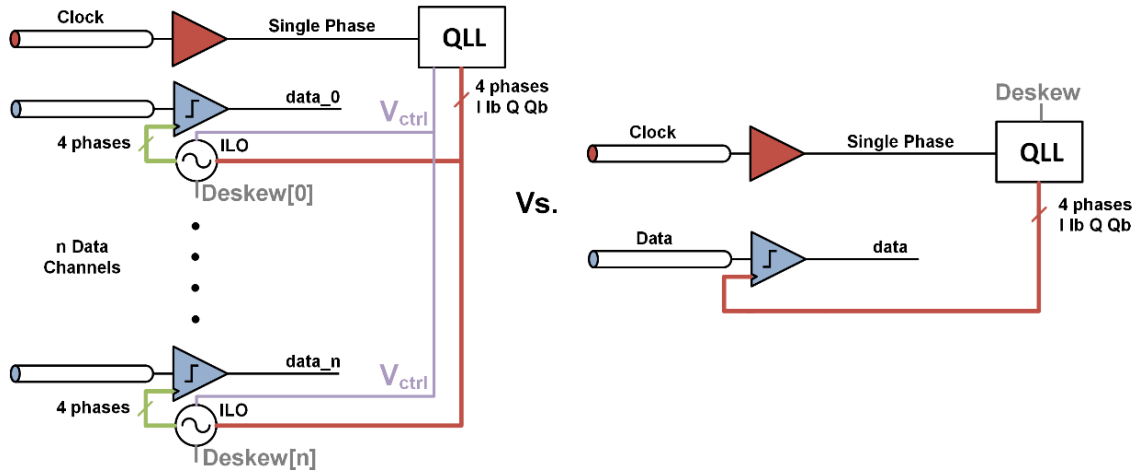


Figure 5.15: QLL based clocking for an n-channel forwarded clock receiver (left).  
Proposed clocking scheme for a single channel forwarded clock receiver (right).

In the conventional QLL architecture (Figure 5.16 (a)), the  $V_{ctrl}$  generated by the phase detector and the low pass filter is used to set delay of both the delay elements (A and B). A simple but crucial change can allow us to add deskew capability in the QLL. Instead of using the  $V_{ctrl}$  to control the delay of both the delay elements, we use it only for only one of the elements (Figure 5.16 (b)). The delay of the other delay element is kept outside the QLL loop and controlled externally. The external control over the delay of one of the delay elements is used to add asymmetry to the delay of the two delay elements. So instead of having a delay of  $d$  each as in Figure 5.16 (a), they have a delay  $d_1$  and  $d_2$ . This forced asymmetry in delays is used for deskewing. In the stable state in the conventional QLL architecture, the oscillator is locked to  $f_{inj}$  and quadrature error reaches zero (4.4), i.e.  $f_o = f_{inj}$ . Combining this with (2.3) suggests that in this case the phase difference between the injected and the locked output signal ' $\theta$ ' is zero, so there is no deskew in this case. However, in the modified QLL structure the locked state is different,

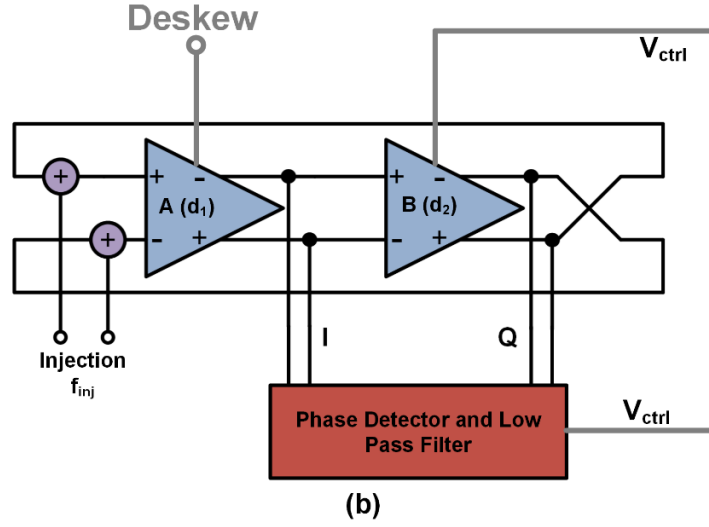
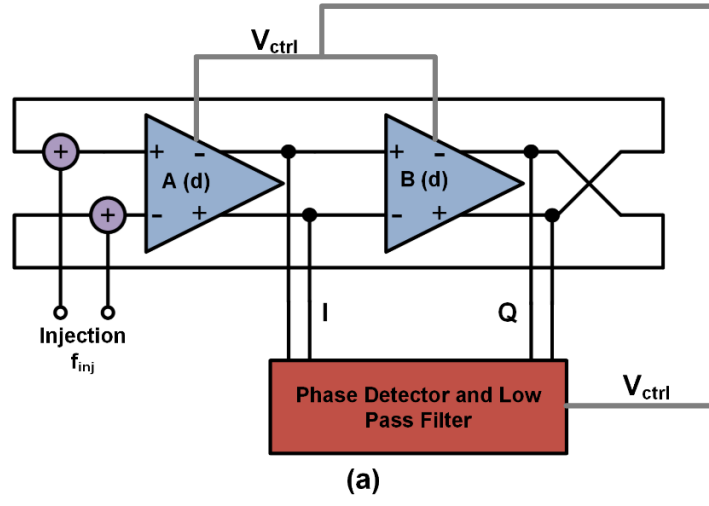


Figure 5.16 (a) Conventional QLL architecture. (b) Modified QLL architecture to add deskew.

due to asymmetry in the delay stages. Again, the oscillator is locked to  $f_{inj}$  and the quadrature error reaches zero. To ensure zero quadrature error the phase delay across the delay element, B must be  $\pi/2$ . In time domain this implies

$$d_2 = \frac{\pi}{2} \times \frac{1}{2\pi f_{inj}} = \frac{1}{4f_{inj}} \quad (5.5)$$

Thus we can alter (5.5) to

$$f_{inj} = \frac{1}{4d_2} \quad (5.6)$$

The natural frequency of oscillation ( $f_o$ ) is dependent on the total delay of A and B (Figure 5.16 (b))

$$f_o = \frac{1}{2(d_1 + d_2)} \quad (5.3)$$

Thus from (5.2) and (5.3) we infer that  $f_o \neq f_{inj}$  if  $d_1 \neq d_2$ , thus we have the deskew angle from (2.4) as

$$deskew = \sin^{-1} \left( \frac{f_o - f_{inj}}{f_l} \right) \quad (5.6)$$

Independent control over  $d_1$  allows us to vary  $f_o$  (5.5) thus control deskew (5.6). It is also instructive to calculate the MQPE in this modified QLL architecture, and

$$Delay_{IQ}(\theta) = d_2 \times 2\pi f \quad (5.7)$$

Using (5.7) and defining  $m = d_2/(d_1 + d_2)$ , we have

$$Delay_{IQ}(\theta) = \frac{\pi}{2} \times 2m \times \frac{f}{f_o} \quad (5.8)$$

Using the same steps as in Chapter 4, we can derive the MQPE in the locked state as

$$MQPE = \frac{\pi}{2} \left[ 2m \times \frac{f_{inj}}{f_o} - 1 \right] \quad (5.9)$$

And in the unlocked state as

$$MQPE = \frac{\pi}{2} \left[ 2m \times \left( \frac{f_{inj}}{f_o} + \frac{f_b}{f_o} \right) - 1 \right] \quad (5.10)$$

where  $f_b$  is same as in (4.6). It should be noted that (5.9) and (5.10) reduce to (4.4) and (4.9) for  $d_1=d_2$ , i.e.,  $m=1/2$ . Figure 5.17 shows a plot of MQPE vs.  $f_o$  for the regular (no deskew) and modified QLL (with deskew). The modified QLL has the familiar locked and unlocked regions like those of the regular version, but there are some marked differences. In the locked region the slope of the linear line is higher for the modified QLL, and in the unlocked region, instead of

going asymptotically to zero, the MQPE keeps increasing as  $|f_o - f_{inj}|$ . This is expected, because for the modified QLL  $f_o$  is varied by only changing  $d_2$ , while keeping  $d_1$  fixed at  $1/(4f_{inj})$ . So as  $|f_o - f_{inj}|$  increases in the locked region, the MQPE increases both due to injection locking dynamics and increased asymmetry between  $d_1$  and  $d_2$  which is taken into account by  $m$  in (5.9). Thus leads to an increased slope to that of the regular QLL. In the unlocked case the injection locking dynamics cause MQPE to reduce as  $|f_o - f_{inj}|$  increases. However, the inherent asymmetry increases further with increased  $|f_o - f_{inj}|$ , and overshadows the decrease in MQPE due to injection. As in the locked case, the inherent asymmetry is represented by  $m$  in (5.10).

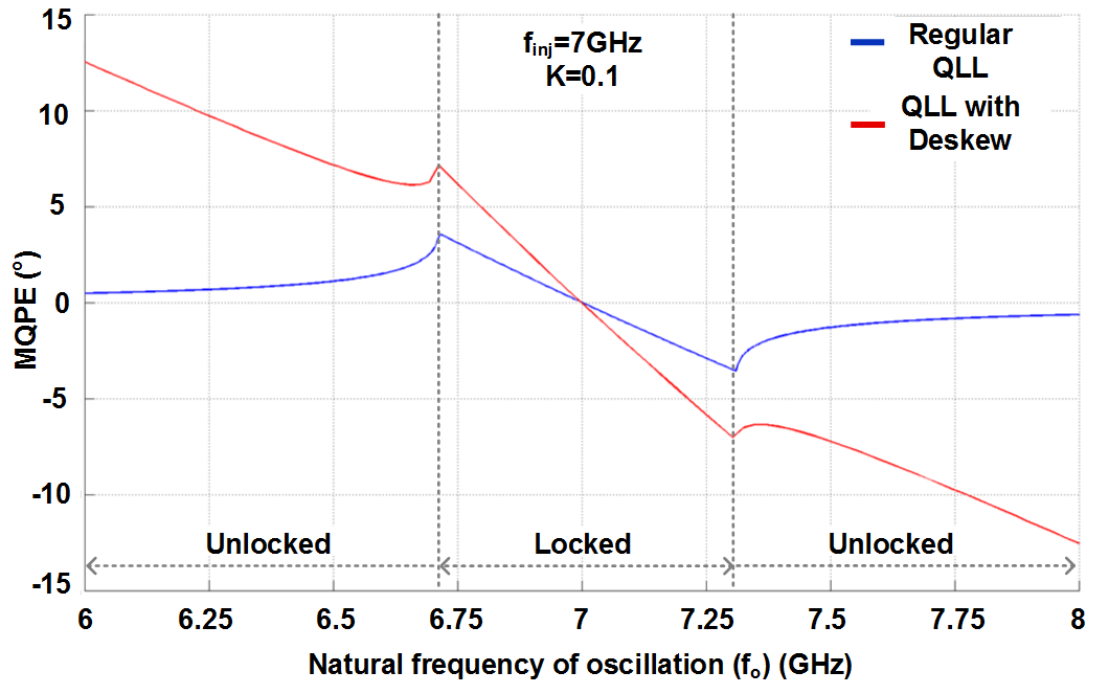


Figure 5.17: MQPE for the QLL without deskew and with deskew.

The increased MQPE in the modified QLL is further exemplified in transient simulations. As shown in Figure 5.18, the modified QLL locks faster than the regular QLL for the same initial states. The injected frequency was set at 7GHz, and in case (a) the initial frequency ( $f_{init}$ ) was set to 5.75GHz and in the second case it was set to 8.4 GHz. In both cases the QLL with deskew locks faster than the regular QLL.

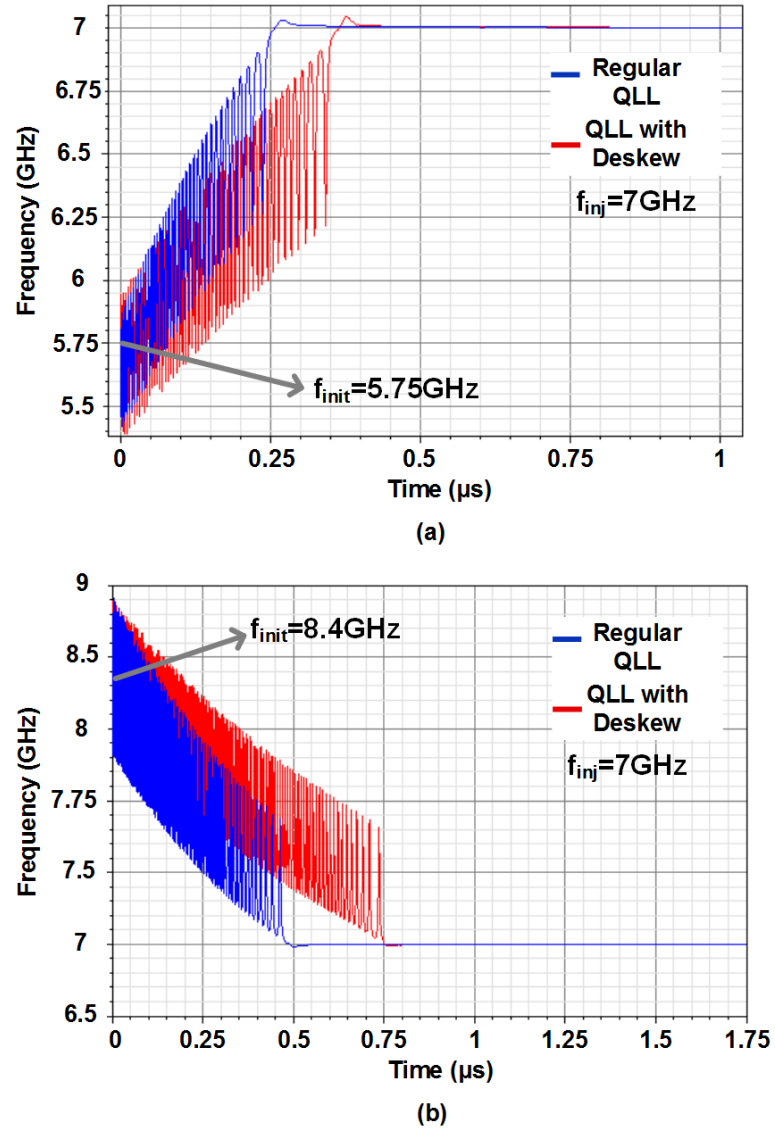


Figure 5.18: Transient locking characteristics of the modified QLL and regular QLL. (a) Initial frequency ( $f_{init}$ )=5.75GHz (b)  $f_{init}$ =8.4GHz

As shown in Figure 5.19, once the modified QLL reaches the stable state (A), deskew can be performed by varying  $d_1$ . If  $d_1$  is decreased,  $f_0$  increases and the new equilibrium with zero quadrature error is achieved at point B, leading to both I and Q phases having a positive phase shift. Similarly, to initiate a negative skew,  $d_1$  is increased. An important advantage of QLL based deskewing compared to deskewing in a simple ILO is that, in the latter case, there is quadrature mismatch in the I and Q phases with deskewing, but in the former, the loop nullifies the quadrature mismatch, thus the I and Q phases move together.

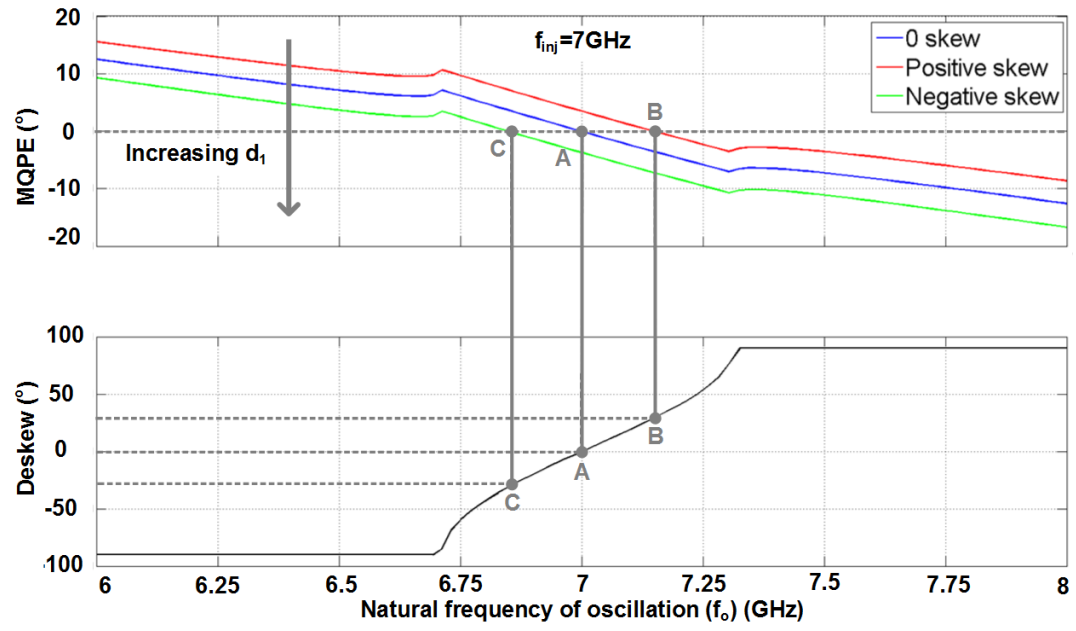


Figure 5.19: Deskewing by changing  $d_1$ , in the modified QLL.



# Chapter 6: VCSEL Modelling and Equalization

## 6.1 Background

As the bandwidth demand for traditionally electrical wireline interconnects has accelerated, optics has become an increasingly attractive alternative for interconnects within computing systems. Multi-Gb/s optical links exclusively use coherent laser light due to its low divergence and narrow wavelength range. Modulation of this laser light is possible by directly modulating the laser intensity through changing the laser's electrical drive current (Figure 6.2). A popular coherent laser light source used in optical transmitters is the Vertical-Cavity Surface-Emitting Laser (VCSEL).

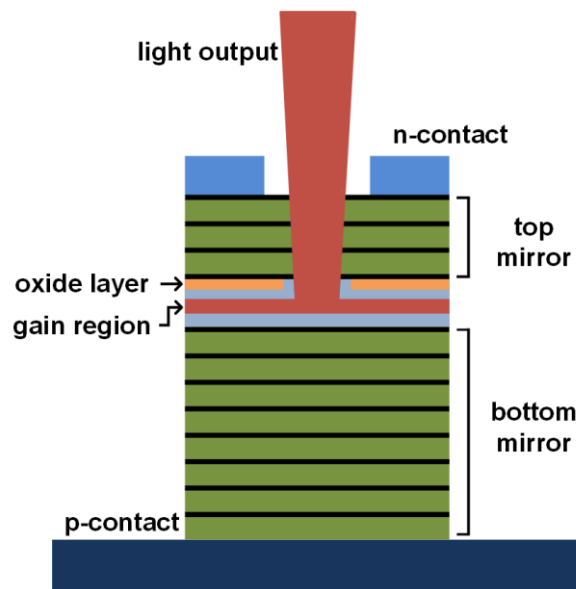


Figure 6.1: Cross-section of a VCSEL

A VCSEL is a semiconductor laser diode which emits light perpendicular from its top surface (Figure 6.1). VCSELs have important practical advantages compared with edge-emitting

semiconductor lasers. They can be tested and characterized directly after growth, i.e. before the wafer is cleaved. Furthermore, it is possible to combine a VCSEL wafer with an array of optical elements (like collimator lenses) and then dice the composite wafer instead of mounting the optical elements individually for each VCSEL. This allows for low cost mass production of laser products. The most common emission wavelengths of VCSELs are in the range of 750-980nm [33] [34], as obtained with the GaAs/AlGaAs material system. While VCSELs appear to be the ideal source due to their ability to both generate and modulate light, serious inherent bandwidth limitations do exist. As data-rates scale, designers have begun to implement transmitter equalization circuitry to compensate for VCSEL bandwidth constraints. However, traditional equalization techniques do not take into account the non-linearity in the VCSEL's response, leading to suboptimal performance. A VCSEL modelling and equalization technique that takes into account the inherent non-linearity in its high speed response is introduced.

This chapter is organized as follows: Section II describes the speed limitations in the VCSEL. In Section III we describe the proposed VCSEL modelling technique. Section IV evaluates the model for accuracy. A new VCSEL equalization methodology that takes into account the inherent non-linearity of the VCSEL is presented in Section V. Section VI discusses the simulated improvement based on the equalization technique. The circuit implementation for the VCSEL transmitter is presented in Section VII. Hardware measurement results for the optical transmitter are presented in Section VIII. Finally, the chapter is concluded in Section IX.

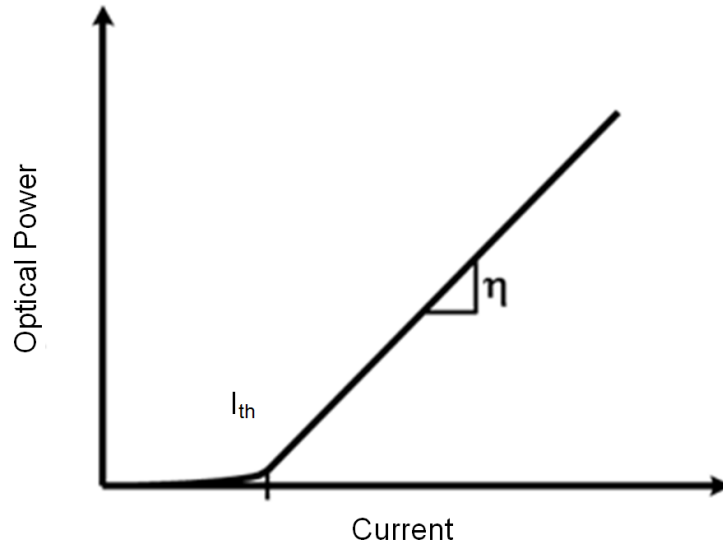


Figure 6.2: VCSEL L-I curve

## 6.2 Speed Limitations

VCSEL bandwidth is limited by a combination of electrical parasitics and the electron-photon interaction described by a set of second-order rate equations.

VCSEL optical bandwidth is regulated by two coupled differential equations which describe the interaction of the electron density,  $N$ , and the photon density,  $N_p$  [67]. The rate of the electron density change is set by the number of carriers injected into the laser cavity volume,  $V$ , via the device current  $I$ , and the number of carriers lost via desired stimulated and non-desired spontaneous and non-radiative recombination:

$$\frac{dN}{dt} = \frac{I}{qV} - \frac{N}{\tau_{sp}} - GNN_p \quad (6.1)$$

where  $\tau_{sp}$  is the non-radiative and spontaneous emission lifetime and  $G$  is the stimulated emission coefficient. Photon density change is governed by the number of photons generated by stimulated and spontaneous emission and the number of photons lost due to optical absorption and scattering:

$$\frac{dN_p}{dt} = GNN_p + \beta_{sp} \frac{N}{\tau_{sp}} - \frac{N_p}{\tau_p} \quad (6.2)$$

where  $\beta_{sp}$  is the spontaneous emission coefficient and  $\tau_p$  is the photon lifetime. Combining the two rate equations and performing the Laplace transform yields the following second-order low-pass transfer function of optical power  $P_{opt}$  for a given input current:

$$\frac{P_{opt}(s)}{I(s)} = \frac{h\nu v_g \alpha_m}{q} \times \frac{GN_p}{s^2 + s \left( GN_p + \frac{1}{\tau_{sp}} \right) + \frac{GN_p}{\tau_p}} \quad (6.3)$$

where  $v_g$  is the light group velocity and  $\alpha_m$  is the VCSEL mirror loss coefficient. Rewriting (6.3) in terms of empirical parameters and defining  $H(f) = P_{opt}(jf)/I(jf)$  we have:

$$H(f) = \text{const} \times \frac{f_r^2}{f_r^2 - f^2 + j(\frac{f}{2\pi})\gamma} \quad (6.4)$$

(6.4) is a second-order low-pass transfer function with peaking. The VCSEL relaxation oscillation frequency  $f_r$ , which is related to the effective bandwidth, is equal to:

$$f_r = \frac{1}{2\pi} \sqrt{\frac{GN_p}{\tau_p}} \quad (6.5)$$

The photon density ( $N_p$ ) is directly proportional to the amount of injected current above threshold [67], thus:

$$f_r = D\sqrt{I - I_{th}} \quad (6.6)$$

In (6.6)  $D$  (also called  $D$ -factor) denotes the rate at which the resonance frequency increases with bias current ( $I$ ) [67]. The damping factor ( $\gamma$ ) is proportional to the square of the resonance frequency [67]:

$$\gamma = Kf_r^2 + \gamma_o \quad (6.7)$$

The  $K$  in (6.6) is called the  $K$ -factor. It sets the maximum intrinsic modulation bandwidth of the VCSEL.  $\gamma_o$  is called the damping factor offset. From (6.6) and (6.7), it is evident that, with increasing bias current, there is an associated increase of the resonance frequency and therefore also of the damping factor. Initially, the modulation bandwidth increases with current, but eventually, the damping factor becomes large and the system becomes critically damped, which sets an upper limit to the modulation bandwidth (Figure 6.8 (b)). In addition to the intrinsic limitation of the VCSEL modulation bandwidth due to damping, there are extrinsic limitations. One such limit is the thermal limit caused by the heating of the active region induced by the bias current passing through the resistive elements of the VCSEL, which causes the output power to saturate [68].

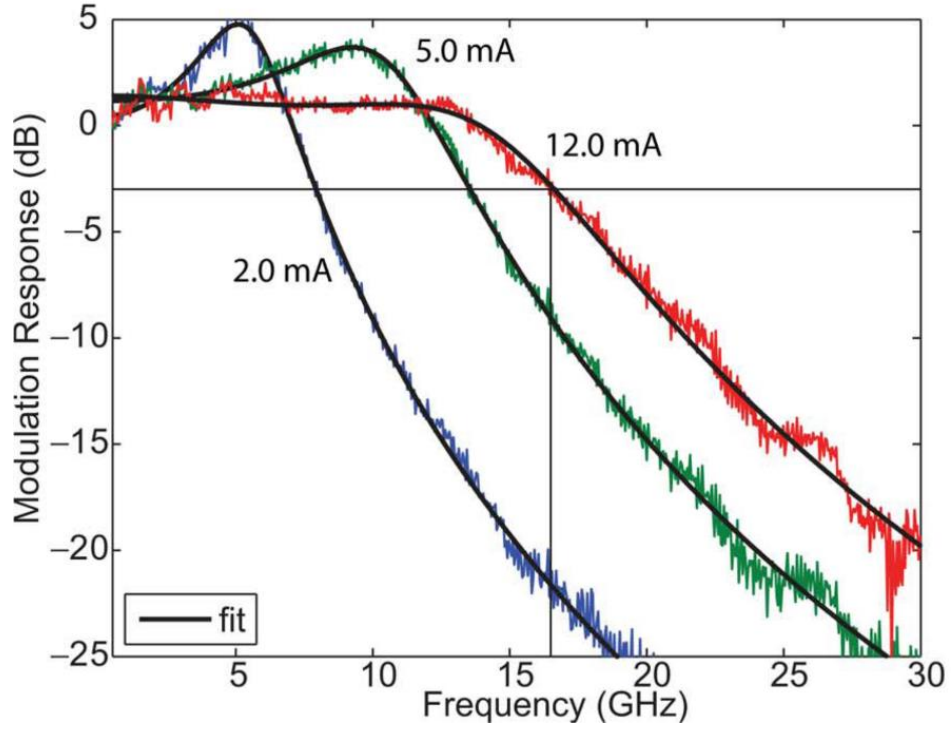


Figure 6.3: VCSEL small signal AC characteristics [45].

Another extrinsic bandwidth limitation comes from the capacitance of the VCSEL, which in combination with the series resistance (which is mainly determined by the resistance of the DBRs), forms a low-pass RC filter that shunts the modulation current outside the active region at frequencies above the bandwidth of the filter. We can account for the effect of the low pass parasitic by adding a pole at  $f_p$  in (6.4):

$$H(f) = \text{const} \times \frac{f_r^2}{f_r^2 - f^2 + j\left(\frac{f}{2\pi}\right)\gamma} \times \frac{1}{1 + j\left(\frac{f}{f_p}\right)} \quad (6.8)$$

Dependence of resonance frequency ( $f_r$ ) and damping factor ( $\gamma$ ) on the bias current ( $I$ ) (Figure 6.3) makes the effective frequency response of the VCSEL non-linear when used for data modulation. Due to large change in  $I$  between the zero ( $I_0$ ) and one ( $I_1$ ) values (of data), the small signal assumption breaks down and the bandwidth of the VCSEL instead of being fixed, varies according to the data sequence. Thus the VCSEL, ceases to be a linear time invariant (LTI) system.

## 6.3 VCSEL Modelling for Simulation

In order to aid the design process, exact modelling of the non-linearity of the VCSEL's response is essential. Previous approaches have used the small signal assumption, in which the modulation response for a particular bias current is used for both ones and zeros [69]. However, this linearization leads to inaccuracies for large extinction ratios (i.e. large  $I_1/I_0$ ). At the other end of the spectrum, exact rate equation based VCSEL modelling [70], although accurate, is difficult to simulate. A dynamic model based on (6.4-6.8), which takes into account the variation in bias current proves most efficient.

### 6.3.1 Simplified Approach

An intuitive (but not exact) approach to understanding the effect of non-linearity in the VCSEL response is shown in Figure 6.4. Suppose the VCSEL is modulated with a data sequence with  $I_0$  and  $I_1$  being the bias currents at the zero and one levels, respectively. We also assume that rising and falling edges of the data sequence are infinitely fast. In this case, due to the finite response time of the VCSEL each rising edge will "see" a modulation response ( $H_0(f)$ ) given by (6.8) with  $I$  set to  $I_0$ . Similarly, each falling edge will see a modulation response ( $H_1(f)$ ) given by (6.8) with  $I$  set to  $I_1$ . With this assumption the response for the rising step ( $R'(t)$ ) and falling steps ( $F'(t)$ ) can be calculated. The incoming data stream ( $D(t)$ ) can be expressed in terms of the summation of the rising ( $R(t)$ ) and falling ( $F(t)$ ) steps separated in time:

$$D(t) = \sum B(n)R(t - nT_b) + (1 - B(n))F(t - nT_b) \quad (6.9)$$

In (6.9),  $B(n)$  represents the value of the  $n^{\text{th}}$  bit (0 or 1) and  $T_b$  is the bit period. Assuming the response of  $R(t)$  is  $R^*(t)$  and that of  $F(t)$  is  $F^*(t)$ , the total VCSEL response to the input data sequence  $D(t)$  can be calculated simply as

$$D^*(t) = \sum B(n)R^*(t - nT_b) + (1 - B(n))F^*(t - nT_b) \quad (6.10)$$

This simplified approach, although intuitive, is not practical as actual data sequences have finite rise and fall times and the assumption of infinite slope does not hold.

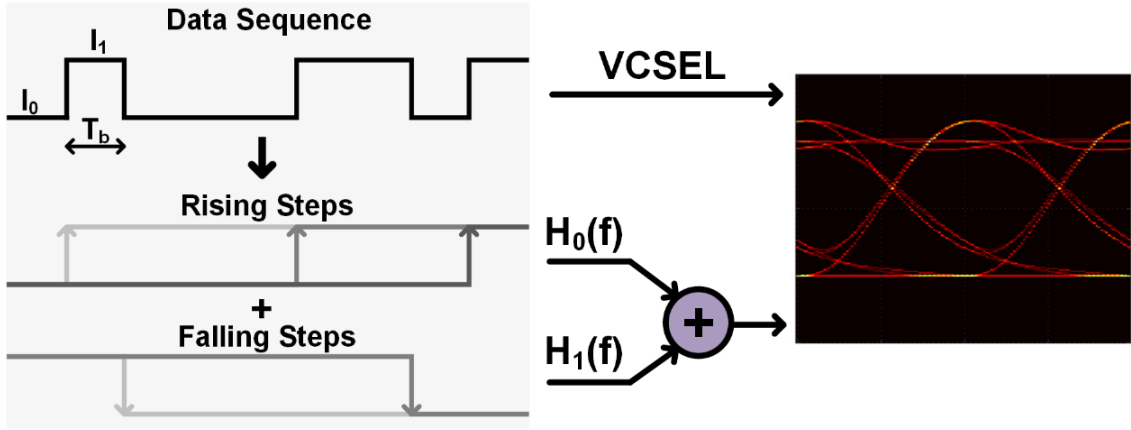


Figure 6.4: Simplified, non-linear VCSEL modeling.

### 6.3.2 Electrical Model

For accurate modelling of VCSEL characteristics, we separate the intrinsic optical dynamics and extrinsic electrical parasitics. Figure 6.5 shows the electrical model of the VCSEL.  $C_j$  and  $R_j$  represent the junction capacitance and resistance, respectively. In addition to the junction resistance, there is also a significant series resistance due to the large number of distributed Bragg reflector (DBR) mirrors used for high reflectivity. This is represented by  $R_s$  in Figure 6.5.  $C_p$  and  $R_p$  represent the pad capacitance and resistance formed between the p-bond pad and the conducting n-side. In Figure 6.5, some of the total current ( $I$ ) gets diverted to the parasitic capacitors  $C_j$  and  $C_p$ ; the actual amount of useful current is represented by the current flowing into the junction resistance ( $I_{R_j}$ ). The typical values of these parameters in modern VCSELs [44] are listed below:

Parameter	Value
Junction Capacitance ( $C_j$ )	110-117fF
Junction Resistance ( $R_j$ )	180-150 $\Omega$
DBR Resistance ( $R_s$ )	50 $\Omega$
Pad Capacitance ( $C_p$ )	10fF
Pad Resistance ( $R_p$ )	1 $\Omega$

Table 6.1: Typical VCSEL electrical parasitics values [44].

The values of the junction capacitance ( $C_j$ ) and junction resistance ( $R_j$ ) are bias dependent but due to their small variation range (Table 6.1), their average values are used in the model.

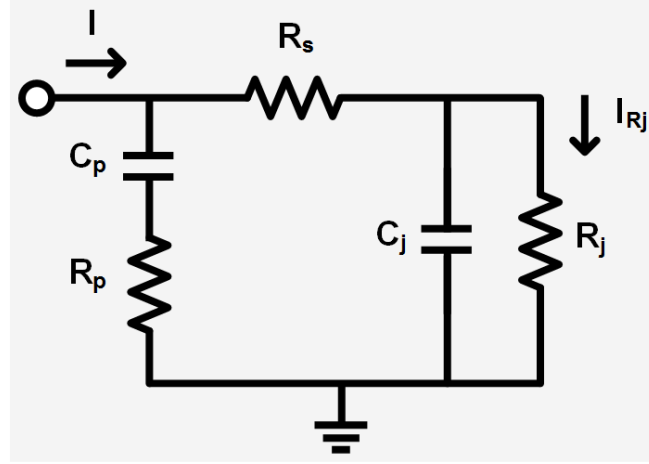


Figure 6.5: VCSEL electrical parasitics.

### 6.3.3 Optical Model

The second order nature of the VCSEL optical dynamics (6.4) allows us to model them as a series RLC circuit [71]. However, unlike [71], we make our model dynamic such that it takes into account the non-linearity inherent in (6.6) and (6.7). Figure 6.6 shows the proposed optical model consisting of a series RLC ( $R_{VL}$ ,  $L_{VL}$  and  $C_{VL}$ ) circuit and driven by voltage source of value  $\eta(I - I_{th})$ , with  $\eta$  representing the slope efficiency and  $I_{th}$  the threshold current of the VCSEL. The voltage of the capacitor ( $C_{VL}$ ) is used as the output ( $P_{out}$ ). The transfer function from the voltage source and the output can be easily calculated (Figure 6.6):

$$\frac{P_{out}(f)}{\eta(I - I_{th})(f)} = \frac{1}{1 - L_{VL}C_{VL} \left(\frac{f}{2\pi}\right)^2 + j \left(\frac{f}{2\pi}\right) RC} \quad (6.11)$$

(6.4) has two independent variables and (6.11) has two, so we (arbitrarily) fix the value of  $C_{VL}$  to 100fF and calculate the values of  $L_{VL}$  and  $R_{VL}$  based on (6.4-6.7).  $L_{VL}$  and  $R_{VL}$  can be shown to be equal to  $1/\{4\pi^2 C_{VL} D^2 (I - I_{th})\}$  and  $(Kf_r^2 + \gamma_0)L_{VL}$ , respectively. As expected, the values of  $L_{VL}$  and  $R_{VL}$  are dependent on the bias current flowing through the VCSEL ( $I$ ). This takes into



account the inherent non linearity of the VCSEL. VerilogA based dynamic models of  $L_{VL}$  and  $R_{VL}$  are used in the simulation. The typical values of the constants in the expressions of  $L_{VL}$  and  $R_{VL}$ , in modern VCSELs [45] are tabulated below.

Parameter	Value
Threshold current ( $I_{th}$ )	0.6mA
Slope efficiency ( $\eta$ )	0.78mW/mA
D-factor (D)	7.6GHz/mA <sup>0.5</sup>
K-factor (K)	0.25ns
Damping factor offset ( $\gamma_o$ )	37ns <sup>-1</sup>

Table 6.2: Typical VCSEL optical modelling parameters [45].

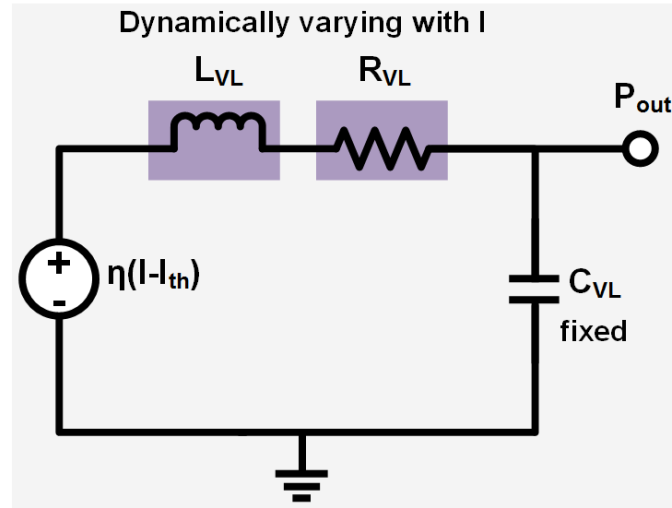


Figure 6.6: Optical model of a VCSEL.

### 6.3.4 Complete Model

The complete dynamic model of the VCSEL is shown in Figure 6.7. The electrical and optical models are combined by changing the voltage source of the optical model to a current dependent voltage source and replacing  $I$  with  $I_{Rj}$  (the current flowing in the junction resistance). To use this model in a circuit simulator, the modulated current is provided to the input of the electrical model and the output of the optical part generates the effective optical power ( $P_{out}$ ).

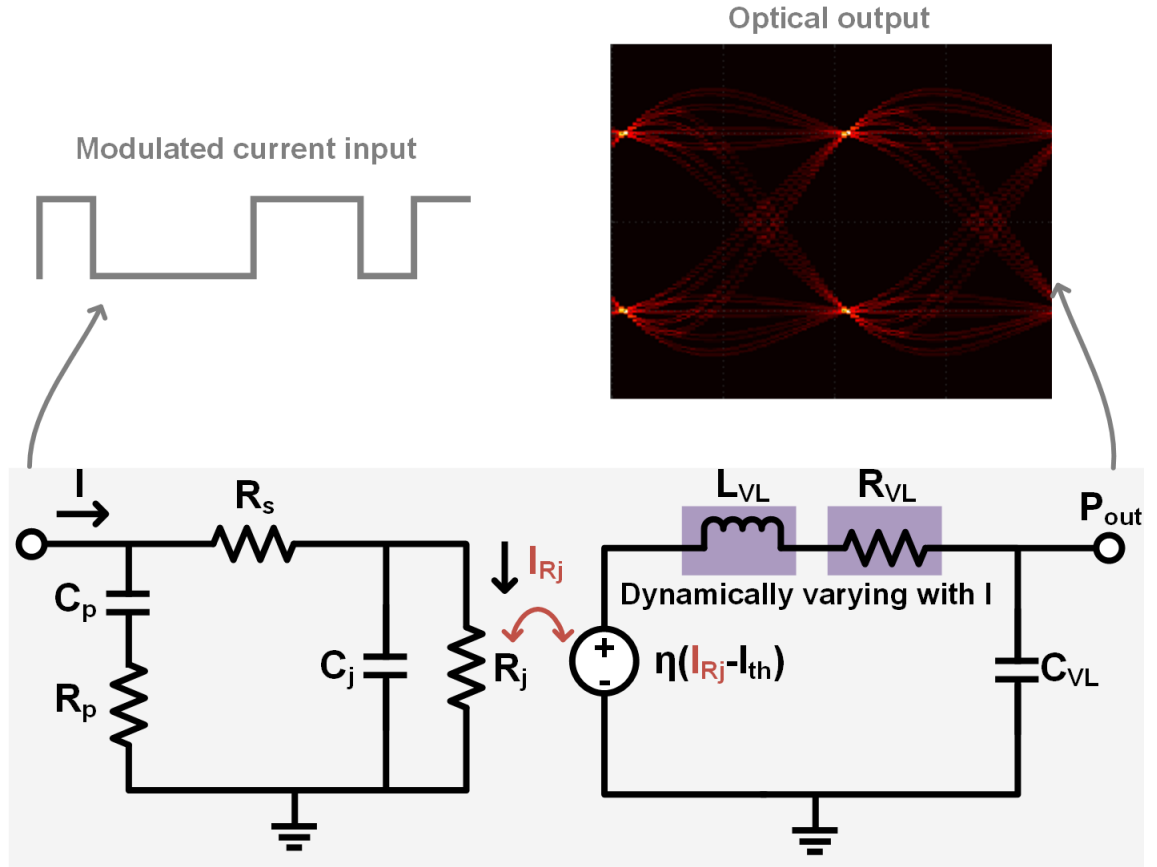


Figure 6.7: Combined model for simulating a VCSEL.

## 6.4 Model Evaluation

We built our model based on the VCSEL parameters listed in Table 6.1 and 6.2. To evaluate the accuracy of our VCSEL modelling we generated the modulation response ( $H(f)$ ) for different bias currents and compared it against the measured modulation response from [45]. As shown in Figure 6.8, the simulated modulation response matches closely with the shape and bandwidth of the measured response for different bias currents. For example, the measured bandwidth for a 11.5mA bias current is 20GHz and that predicted by the model is 19.89GHz.

In addition, the measured results in [45] suggest that the maximum bandwidth is achieved at 11.5mA and then bandwidth diminishes as current increases. To verify if the model also predicts the same we plotted the bandwidth, based on simulation of the model, for different bias currents. As shown in Figure 6.9 the bandwidth reaches a maximum of 19.89GHz at 11.5mA and then

decreases as current is increased further. This behavior is also in line with the discussion in section 6.2.

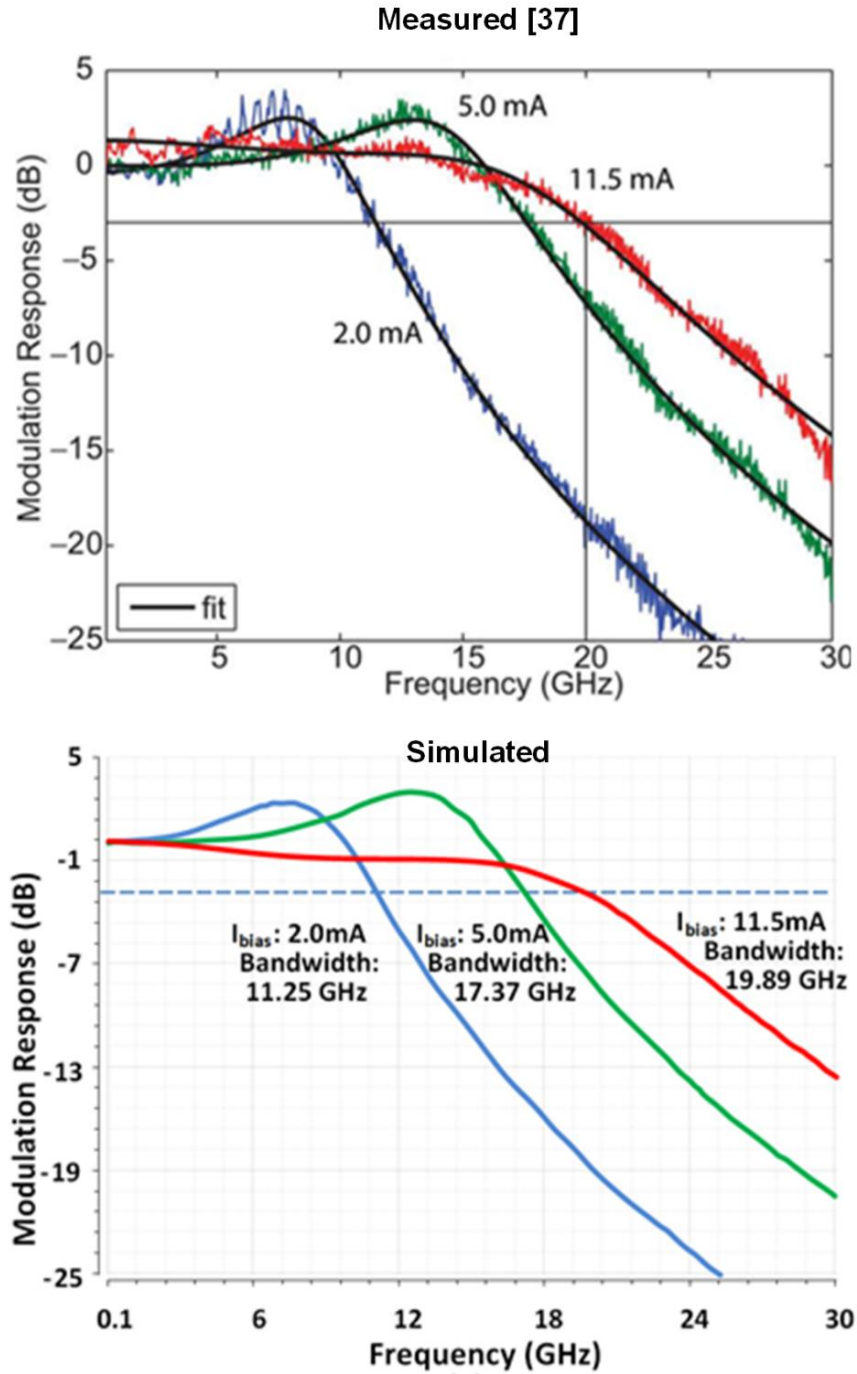


Figure 6.8: VCSEL modelling: comparing the measured (top) and simulated (bottom).

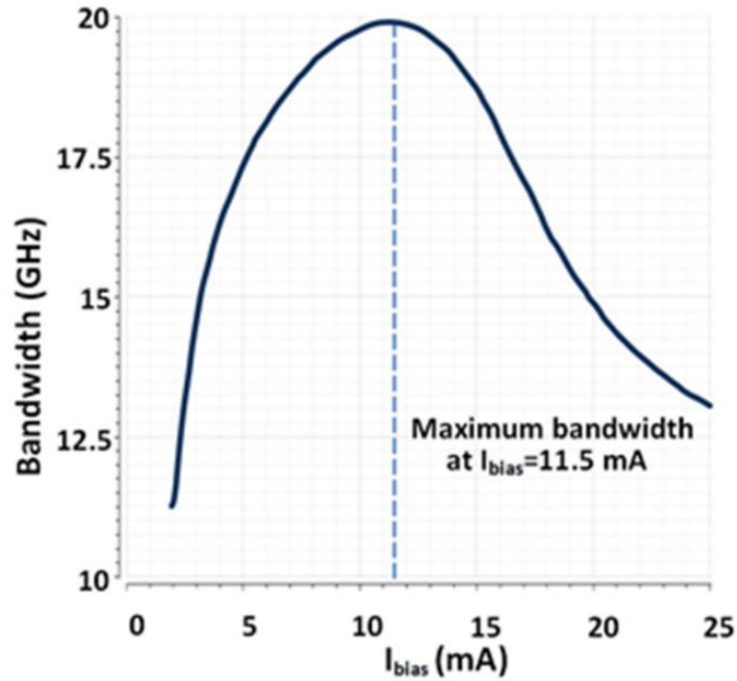


Figure 6.9: Simulated modulation bandwidth variation with bias current.

## 6.5 VCSEL Equalization Methodology

Bandwidth limitations in the VCSEL's optical response limits the speed of optical transmitters. In addition, better power efficiency (Figure 6.8) and mean time to failure (MTTF) [72] demands the biasing of the current at a lower bias current and thus, lower bandwidth. As data rates scale, there is an increased need to have equalization circuitry to compensate for the VCSEL bandwidth restrictions. Previous designers have relied on established electrical transmitter equalization techniques [63], [73]; for example, finite impulse response (FIR) based pre-emphasis.

### 6.5.1 Conventional FIR-Based Pre-Emphasis

Equalization eliminates the problem of frequency-dependent attenuation by filtering the transmitted or received waveform so that the overall system exhibits a flat frequency response. For instance, in a transmitter equalizer, if the transfer characteristics of the channel is expressed

by  $A(z)$ , the transmitter equalization transfer function,  $P(z)$ , should be designed such that  $A(z) \times P(z) = 1$  or  $P(z) = 1/A(z)$ , as shown in Figure 6.10. Often times it is not possible to implement the exact required  $P(z)$ ; however, there are techniques to closely approximate the target transfer function. Transversal filters (FIR filters) are mainly used to perform the transmitter equalization [74]. The transfer function,  $H(z)$  can be written as

$$H(z) = 1 + a_1 z^{-1} + \dots + a_n z^{-n} \quad (6.12)$$

where  $a_i$ 's are called the tap coefficients (or taps in short) and  $n$  is the total number of equalization taps.  $N$  determines how well  $H(z)$  matches the target transfer function  $P(z)$ . The larger the number of taps in the equalizer, the better the approximation of  $P(z)$  is achieved. Figure 6.11 illustrates how an FIR-based transmitter reduces ISI. This technique is very well suited for digital communication techniques, in which generating a delay is very straightforward through use of latches and flip-flops as shown in Figure 6.12.

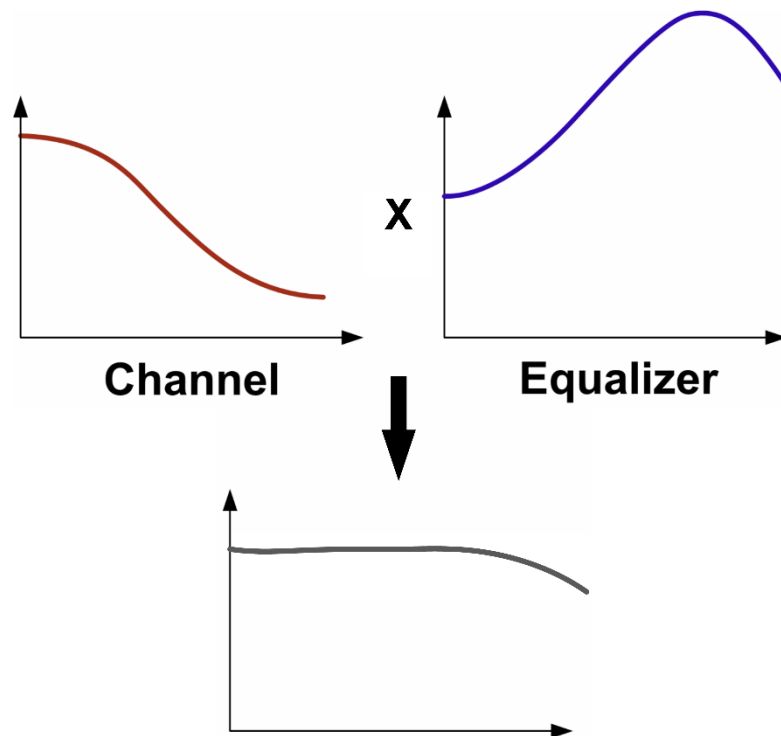


Figure 6.10: Transmitter equalization boosts the high frequency component to achieve a flat response.

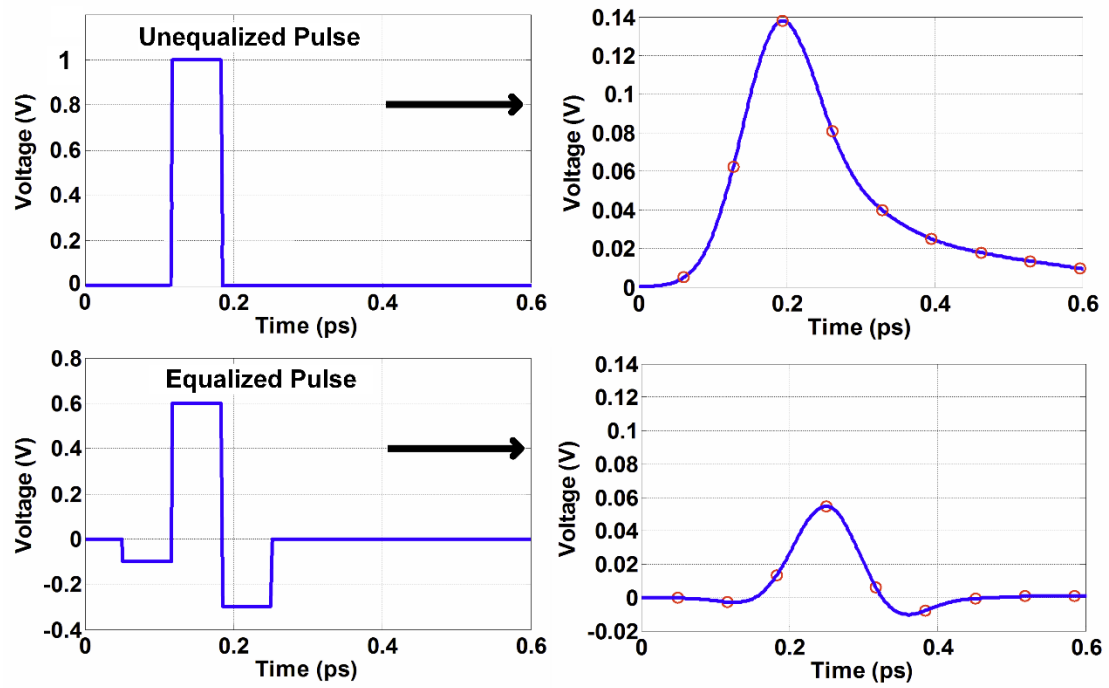


Figure 6.11: Pulse response of channel (right) before and after pre-emphasis.

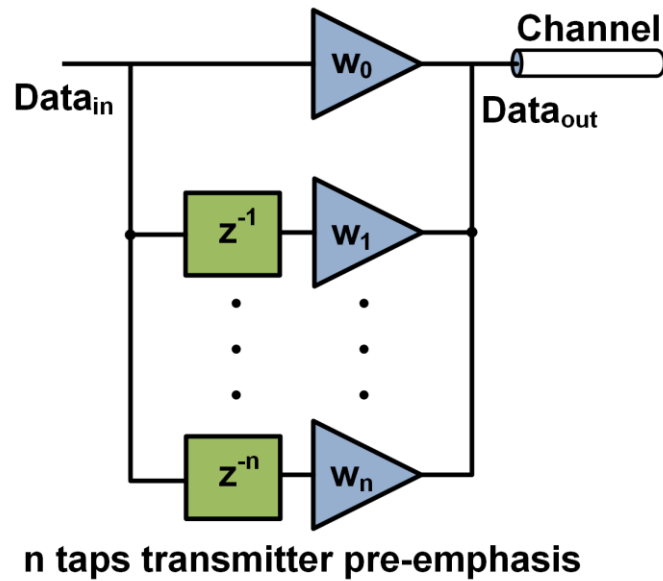


Figure 6.12: Block diagram of a transmitter with  $n$ -tap FIR-based equalization.

### 6.5.2 Proposed Equalization Technique

Conventional pre-emphasis technique is designed to efficiently equalize linear time invariant channels (eg. electrical copper traces). However, a VCSEL does not have a linear frequency response. Figure 6.13 (a) and (b) show the responses of isolated one and zero pulses generated from our model. The responses are superimposed after flipping the zero response. Figure 6.13 (c) shows that responses are not equivalent.

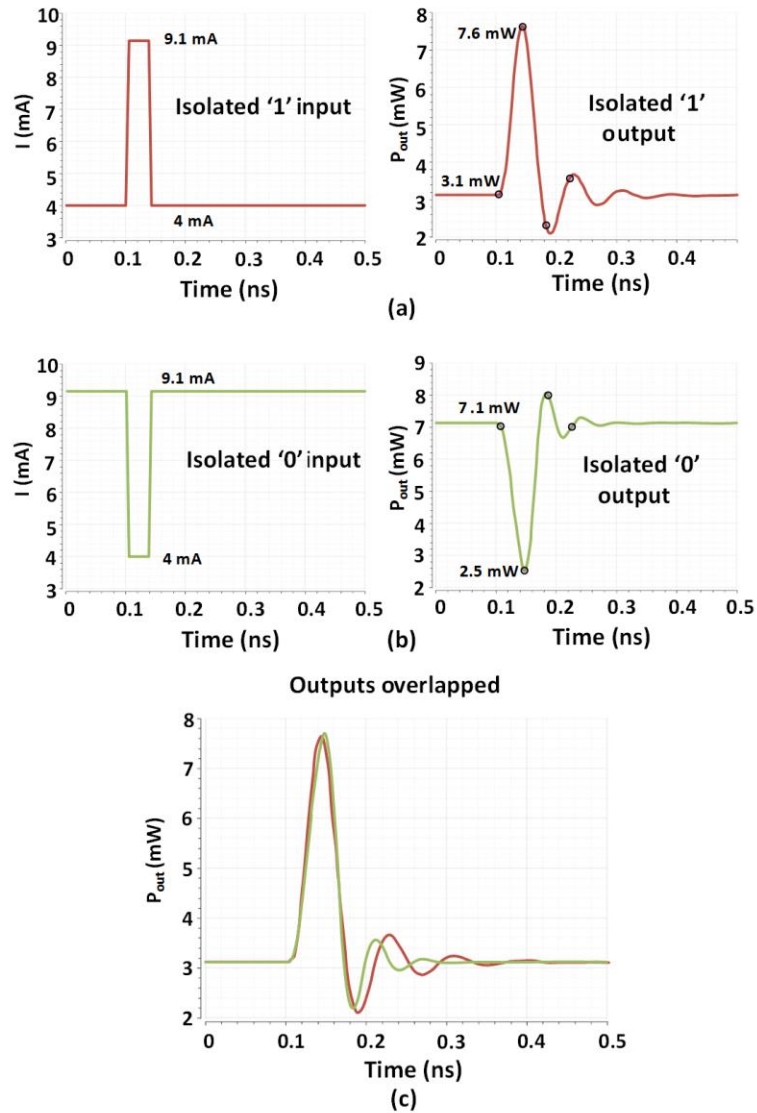


Figure 6.13: VCSEL pulse response for (a) isolated 1, (b) isolated 0, (c) responses superimposed.

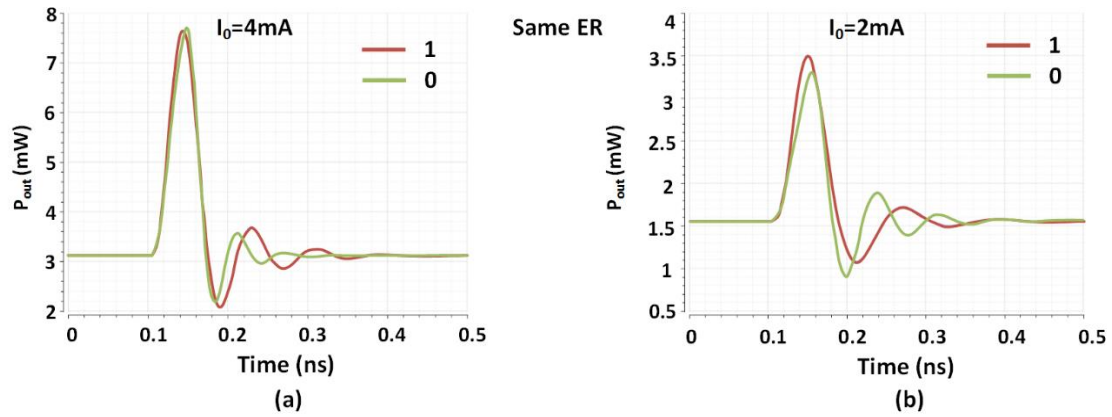


Figure 6.14: VCSEL pulse responses for different bias currents.

The asymmetry becomes more pronounced as the bias current is reduced. Figure 6.14 shows the pulse responses for isolated one and an isolated zero, for two cases. In Figure 6.14 (a),  $I_0$  is set at a high value, (4mA) whereas in Figure 6.14 (b) the  $I_0$  is set at a lower value (2mA). For the same extinction ratio (ER), there is greater difference between the one and the zero responses for the lower current case. The conventional FIR based transmitter equalization would be “blind” to this asymmetry, i.e. it would equalize an isolated one pulse in the same manner as the isolated zero, leading to sub-optimal performance.

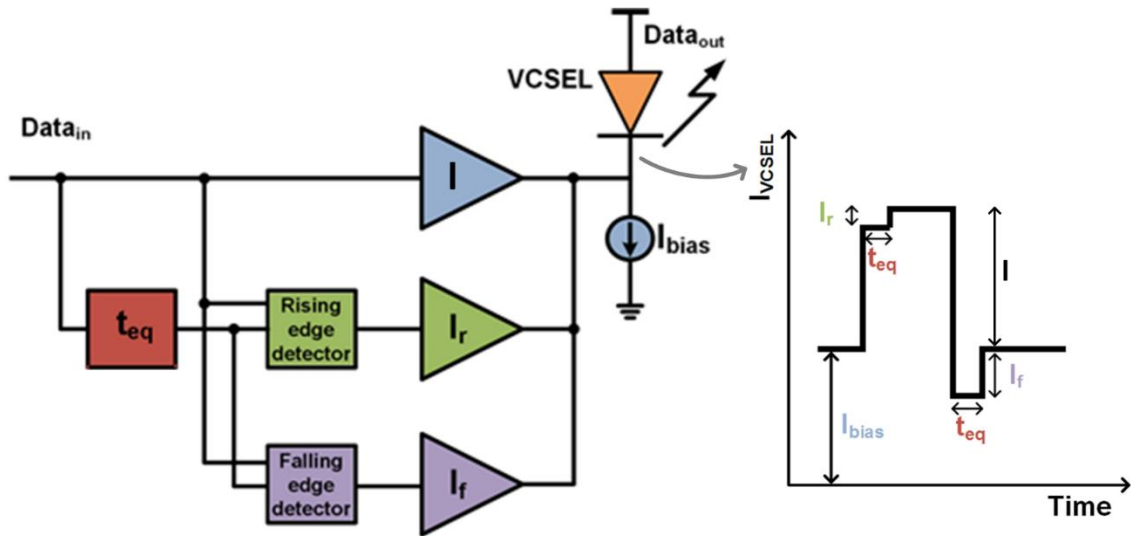


Figure 6.15: Proposed equalization technique.



The fundamental cause of the asymmetry between isolated one and zero responses is that the non-linearity in the VCSEL causes, it to respond differently to rising and falling edges of data. To take this effect into account, we propose a modification to the conventional pre-emphasis equalization. We detect the rising and falling edges and equalize them differently, based on the response of the VCSEL to an isolated zero and isolated one (Figure 6.13). Figure 6.15 shows the architecture of the proposed equalization technique. Input data ( $D_{in}$ ) is delayed by an equalization delay of  $t_{eq}$ . Unlike conventional digital FIR-transmitter pre-emphasis the  $t_{eq}$  is not set to be a multiple of the bit period. Simulations based on the VCSEL model show that the effect of the proposed equalization technique is to cancel the peaking in the typical second order response of the VCSEL. The minimum of this “anti-peak” occurs at  $1/2t_{eq}$ . Thus, we set the  $t_{eq}$  based on the position of the peak of the VCSEL’s modulation response. This response itself is dependent on the bias current (Figure 6.8) and independent of the data rate.

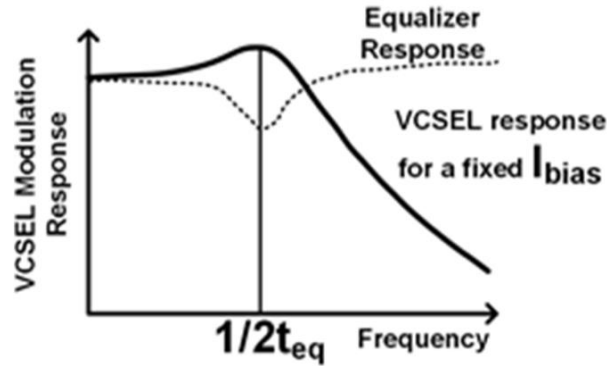


Figure 6.16: Proposed method for selecting  $t_{eq}$ .

## 6.6 Simulated Results

To investigate the efficacy of the proposed equalization technique, we performed two sets of simulations to generate optical eye-diagrams using the VCSEL model (for a PRBS15 data sequence). In the first case no equalization was used and in the second case we used the proposed technique.

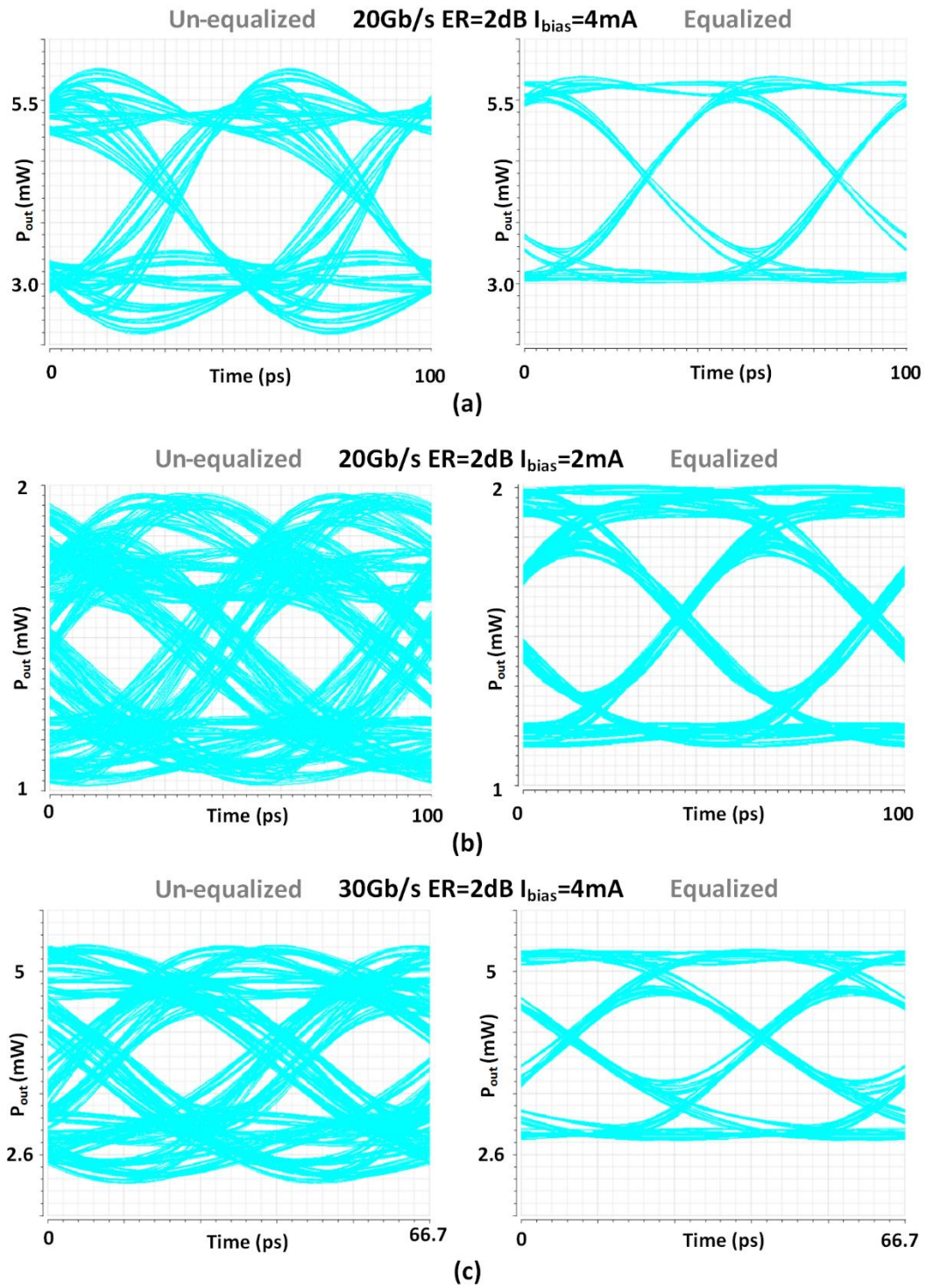


Figure 6.17: Simulated optical eye-diagrams with and without equalization. (a) 20Gb/s high current, (b) 20Gb/s low current, (c) 30Gb/s.

Figure 6.17 (a) and (b) show the simulated eye-diagram for 20Gb/s with the VCSEL biased at ( $I_{bias}$ ) 4mA and 2mA respectively. Figure 6.17 (c) shows the simulated eye-diagrams for 30Gb/s with an  $I_{bias}$  of 4mA. The extinction ratio was fixed to 2dB for all three cases. The percentage improvement in the vertical and horizontal eye opening and the required tap strengths ( $I_r/I$  and  $I_f/I$ ) and  $t_{eq}$  (Figure 6.15) are presented in Table 6.3.

Data Rate	$I_{bias}$	Rise Tap ( $I_r/I$ )	Fall Tap ( $I_f/I$ )	$t_{eq}$	% vertical improvement	% horizontal improvement
20 Gb/s	4mA	0.25	0.19	33ps	16%	22%
20 Gb/s	2mA	0.45	0.25	45ps	70%	38%
30 Gb/s	4mA	0.19	0.28	33ps	10%	33%

Table 6.3: Summary of simulated improvement by the proposed VCSEL equalization technique.

Three important facts are suggested by Table 6.3. Firstly, for efficient VCSEL equalization the rise and fall taps must be asymmetric. Secondly the proposed technique is more effective when the VCSEL is biased at a low current. And finally, the  $t_{eq}$  delay is independent of the data rate and is dependent on the bias current ( $I_{bias}$ ).

## 6.7 Circuit Implementation

Figure 6.18 shows the circuit architecture of the proposed VCSEL equalization scheme. In order to generate a (pseudo) random, an on-chip high-speed quarter-rate PRBS-15 transmitter is used. Quarter-rate architecture is chosen to relieve the speed requirement of the PRBS generator. A high-speed, 16bit shift register is also integrated to enable the application of arbitrary patterns to the transmitter for testing and debugging purposes. A QLL based front-end is used for converting the low swing input clock ( $\sim 100mV$ ) to the rail-to-rail digital domain. The QLL also enables the generation of quadrature phase clocks for the quarter-rate PRBS. Conventional clock front-ends

[75] use power hungry CML-to-CMOS converters (Figure 6.19). The quadrature phases are provided externally [75] which requires the usage of two CML-CMOS converters thereby doubling the power consumption.

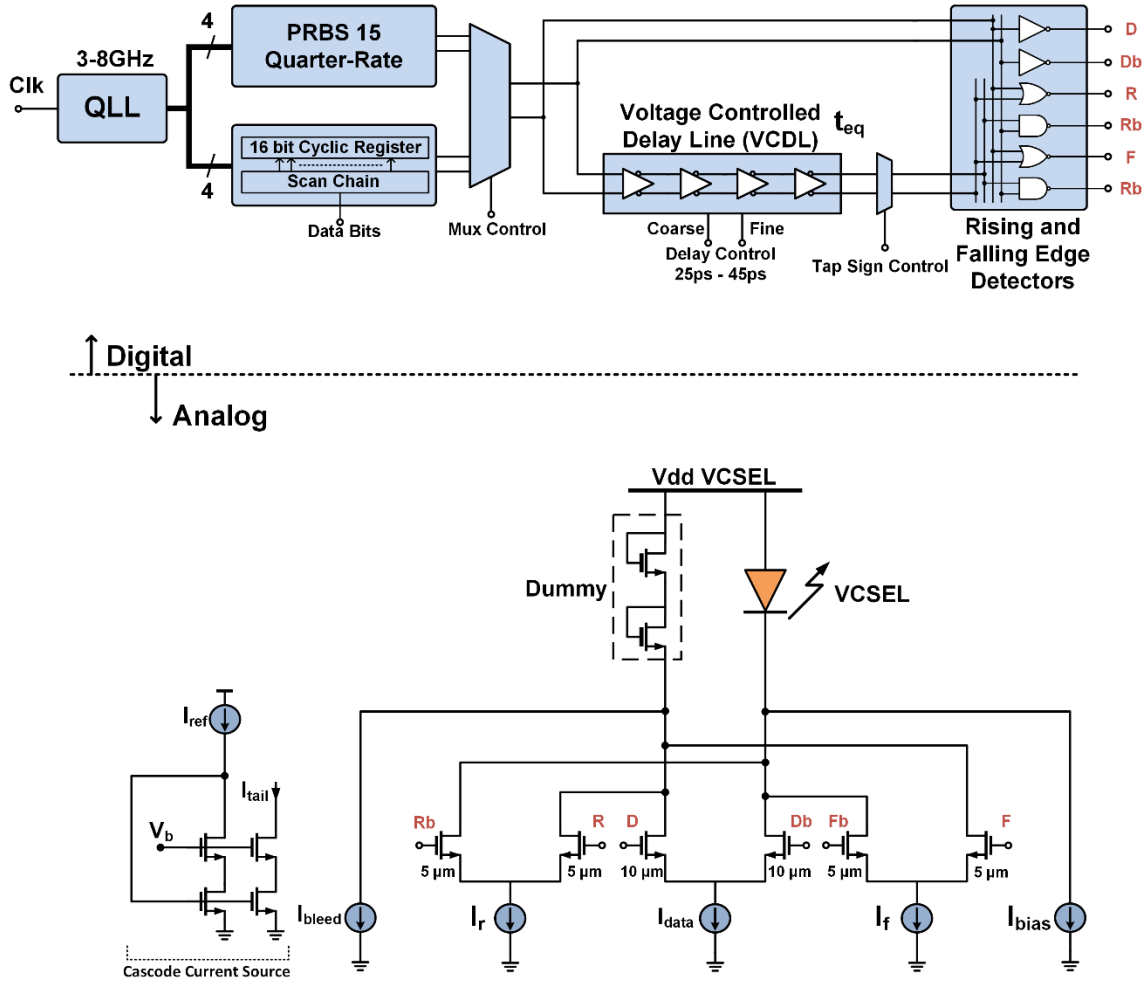


Figure 6.18: Circuit architecture.

In contrast, the QLL based clocking (Figure 6.20) uses the inherent high voltage gain of injection locking [53] to generate rail-to-rail clock from the low amplitude analog clock input at a low power overhead. The quadrature error tracking loop ensures a large locking range (3-8GHz) and accurate quadrature phase generation from a single phase of clock.

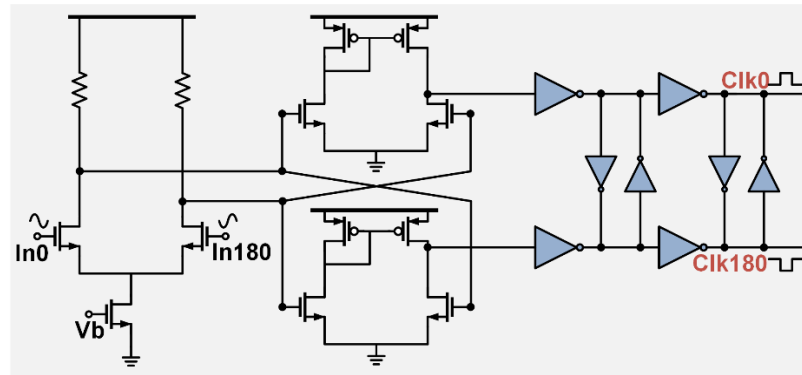


Figure 6.19: Conventional CML-to-CMOS structure used for digital clock generation from an analog input.

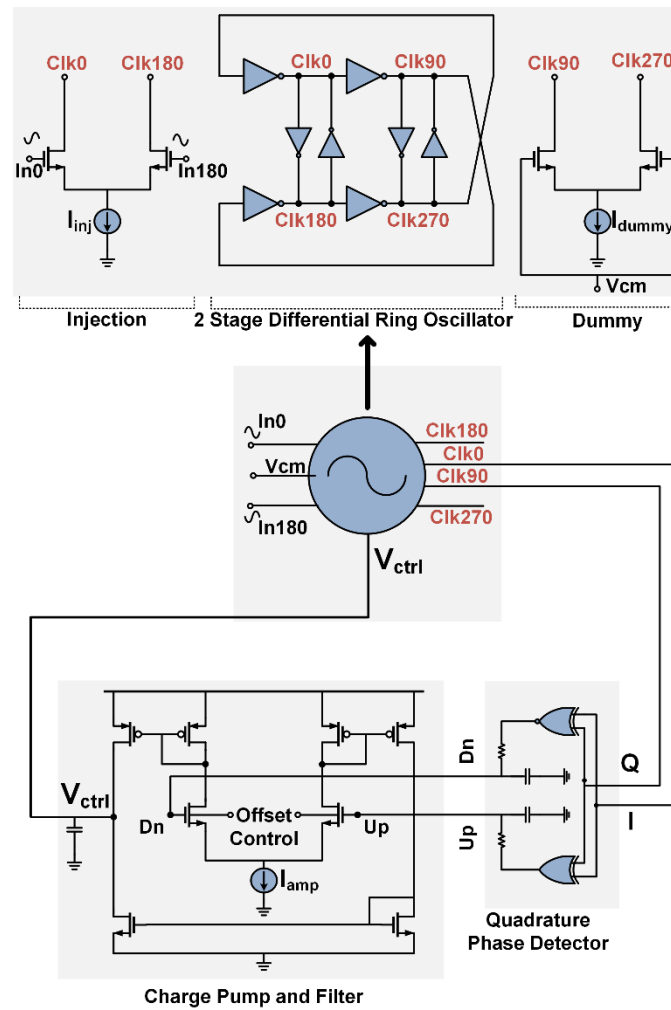


Figure 6.20: QLL based CML-to-CMOS conversion and quadrature phase generation.

The equalization delay ( $t_{eq}$ ) is implemented by a four stage differential delay stage with analog and digital delay controls for fine and coarse delay controls. It has a total delay range of 25ps to 40ps. The rising and falling edge detectors are implemented via digital CMOS gates. A typical VCSEL output driver, with a differential stage steering current between the VCSEL and a dummy load, and an additional static current source ( $I_{bias}$ ), to bias the VCSEL sufficiently above the threshold current, is used. The rise and fall taps are implemented by adding additional differential pairs to the output driver. The tail current sources for all the differential pairs are implemented using the low voltage cascode structure. The tail currents are controlled externally to control the strength of the taps. The output stage is designed for a higher voltage supply (2.5V) due to the typical VCSEL diode knee voltage (1.7V) exceeding normal CMOS supplies (1V).

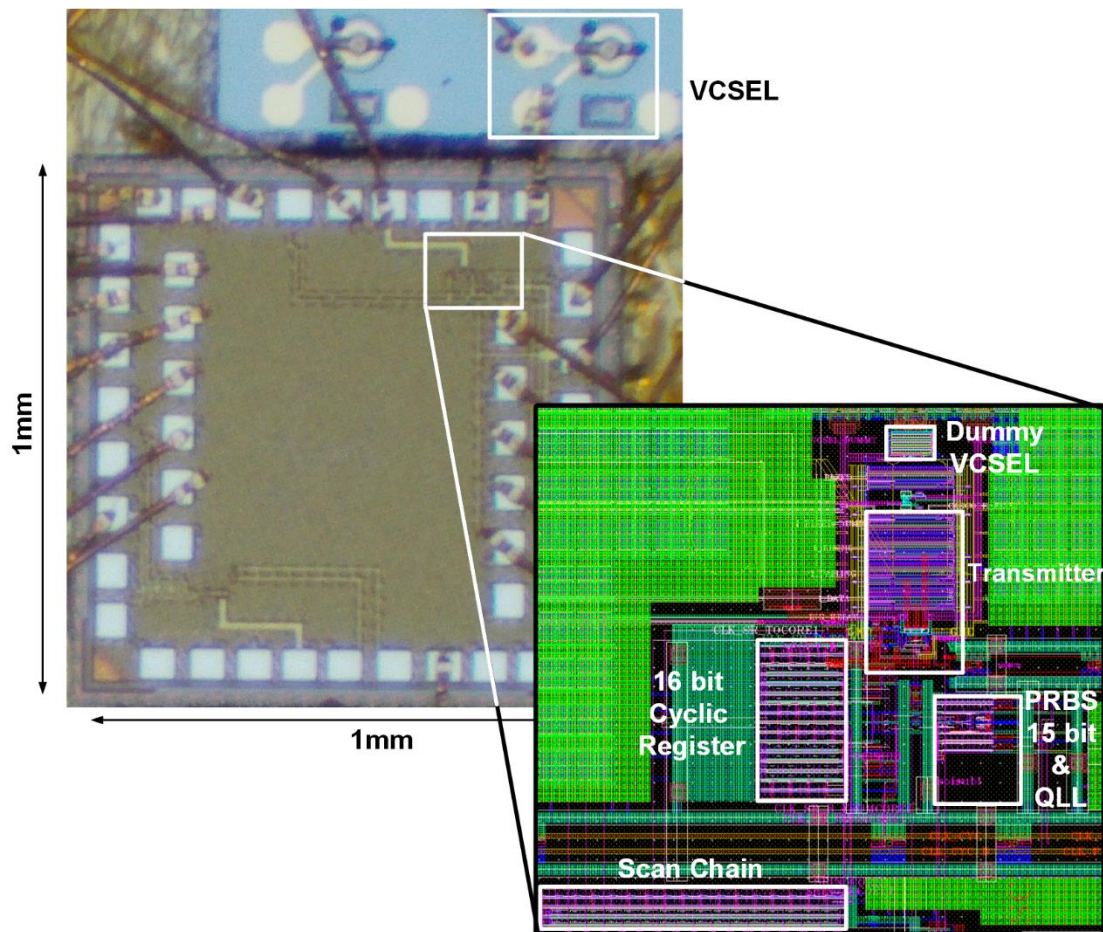


Figure 6.21: Chip micrograph and layout details.



## 6.8 Experimental Results

The test chip was fabricated in a 32nm SOI CMOS process. The die micrograph and core detail are presented in Figure 6.21. Core area is  $100\mu\text{m} \times 60\mu\text{m}$ , in a  $1\text{mm} \times 1\text{mm}$  die. The VCSEL is wire-bonded to the test chip.

### 6.8.1 Optical Measurement Setup

An essential part of the optical measurement setup is coupling the light from the VCSEL to the optical fiber. Light can be simply coupled by appropriately positioning a cleaved bare optical fiber near the surface of the VCSEL (butt coupling). However, due to the divergence angle out of the VCSEL being larger than the acceptance angle into the fiber, there is a loss of about -3dB. In addition, vibrations (due to air) in the bare fiber translates to optical noise. Figure 6.22 shows the setup for bare fiber coupling.

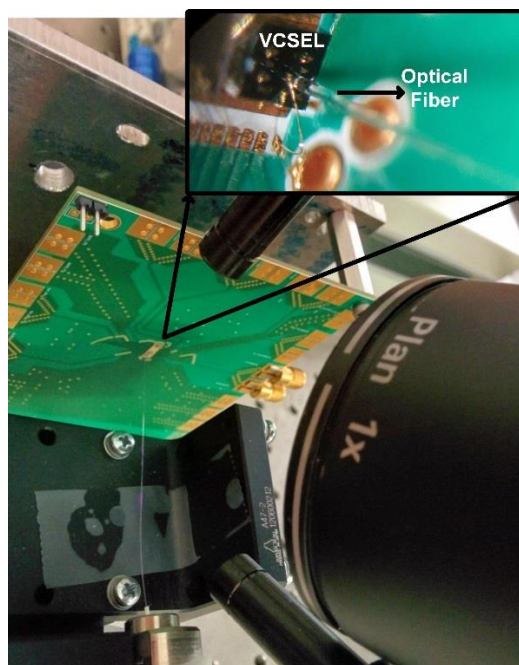


Figure 6.22: Butt coupling proves too lossy and noisy for VCSEL measurements.

Instead of butt coupling the measurement setup shown in Figure 6.23 is used. The setup relays the image of the VCSEL onto the surface of the fiber, with the magnification of 2x. With a magnification of 2x the  $4\mu\text{m}$  diameter VCSEL spot gets imaged to an  $8\mu\text{m}$  diameter at the

surface of the fiber, while at the same time the divergence angle going into the fiber is divided by two relative to the divergence angle directly out of the VCSEL, leading to more efficient coupling. Two lenses with a ratio of two in focal lengths are used to achieve this. A 6mm (A110TM-B) lens is used to collimate the light coming from the VCSEL and an 11mm (F220APC-780) lens is used to focus the collimated light into the fiber. An angle-polished multi-mode fiber is connected to the lens setup via a standard APC connector. The fiber is polished at an  $8^\circ$  angle to avoid optical feedback. This setup helped in reducing the coupling loss to -0.5dB.

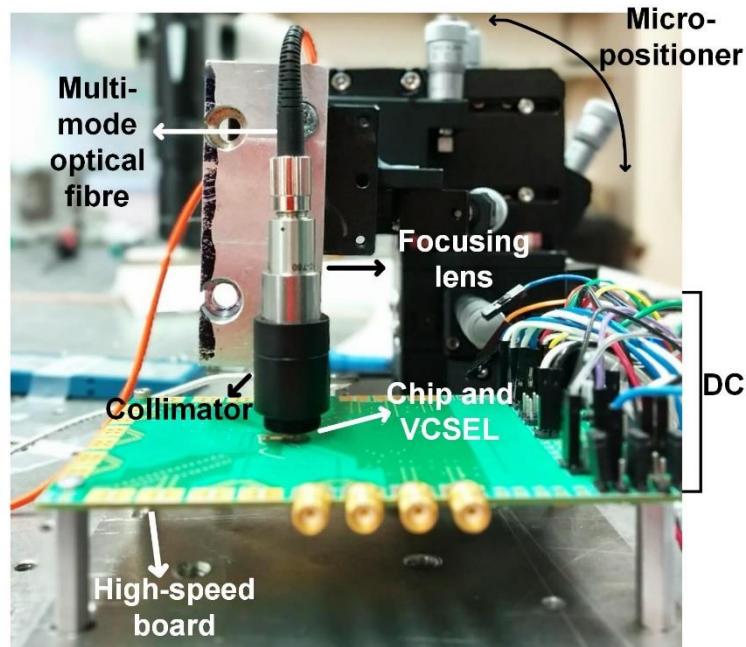


Figure 6.23: Optical measurement setup.

## 6.8.2 Measured Eye-Diagrams

An Anritsu clock generator is used to supply single phase clock to the QLL frontend. The QLL frontend is used to generate the quadrature phase clocks for the high speed quarter-rate PRBS-15 generator. The QLL has a locking range of 3-8GHz; correspondingly the PRBS generator has measured working range of 15-32Gb/s.

In order to establish the efficacy of the proposed equalization technique, VCSEL outputs were measured for four cases at a data-rate of 16Gb/s at a low current bias ( $I_{bias}$ ). As shown in Figure 6.24, without any equalization the eye is open but there is an asymmetry of the one and



zero levels. The optical noise is greater for the zero level than for the one level. The rise tap proves more effective in countering this asymmetry than the fall tap Figure 6.24. The optimum symmetrical eye is achieved when the rise and fall taps have a ratio of 2:1. The  $t_{eq}$  was set to its maximum value (45ps). Average optical DC power was fixed at 1.5mW for all four measurements.

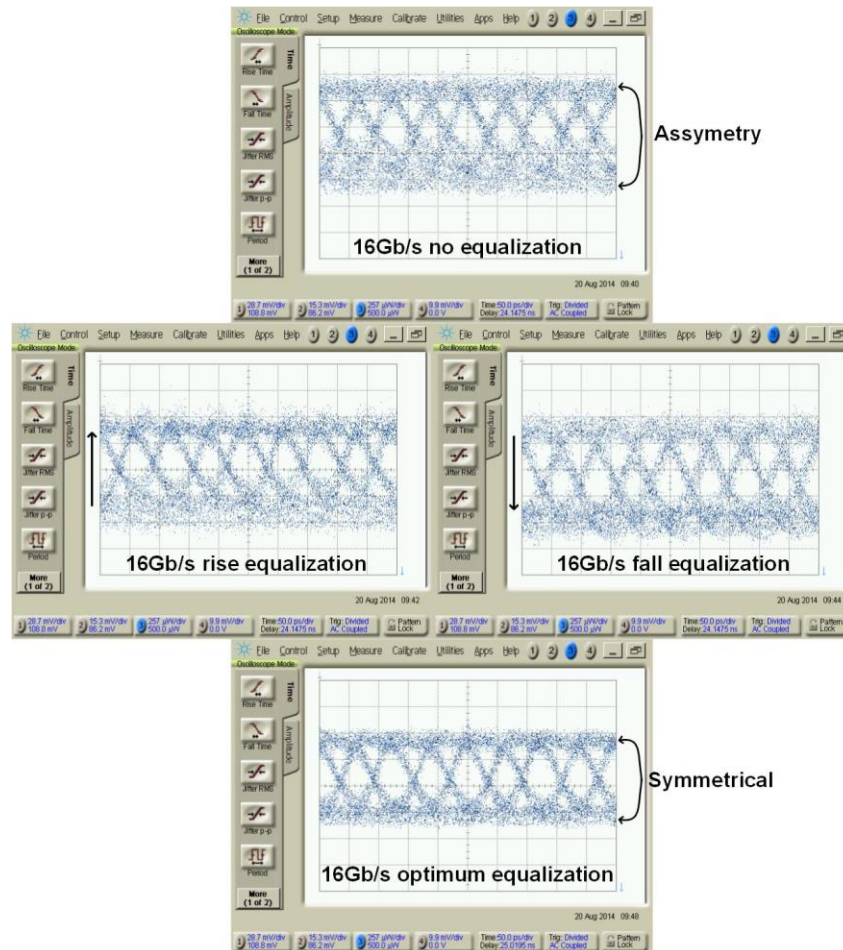
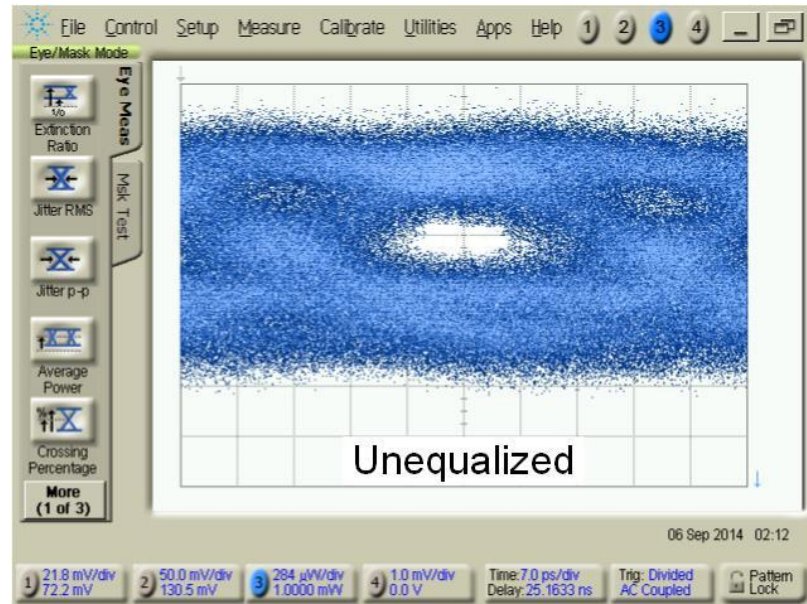


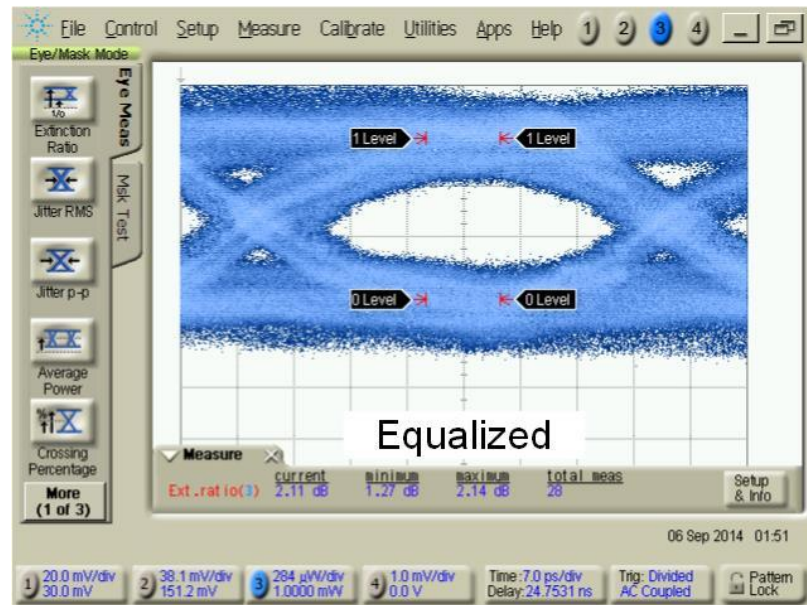
Figure 6.24: Measured VCSEL optical output at 16Gb/s (PRBS-15), with and without equalization.

A maximum data rate of 20Gb/s is achieved (Figure 6.25 (b)). The optimum optical eye at 20Gb/s is achieved with an extinction ratio of 2dB and 65% horizontal opening. To show the improvement achieved by the proposed equalization technique, the unequalized eye at 20Gb/s is also shown in Figure 6.25 (a). The ratio of the rise and fall taps is again 2:1 and  $t_{eq}$  is set to its lowest setting 25ps. Single-ended operation is used to save power. The VCSEL output stage

draws 5.5mA from a 2.5V power supply. The rest of the equalization circuit consumes 1.6mW from a 1V supply. This translates to an ultra-low power efficiency of 0.77pJ/bit. The maximum data rate is essentially limited by the bandwidth of the VCSELs (Figure 6.25 (a)).



(a)



(b)

Figure 6.25: Measured optical eye-diagram for PRBS-15 data at 20Gb/s. (a) Unequalized  
(b) Equalized.

## 6.9 Summary

We presented a novel modelling technique that takes into account the inherent non-linearity in the VCSEL's frequency response. The time domain optical responses for a one and a zero were used to arrive at an optimum equalization strategy. The rising and falling edges were equalized separately and the equalization delay was selected based on the bias current of the VCSEL. The equalization technique was used to achieve ultra-low power efficiency of 0.77pJ/bit at a data-rate of 20Gb/s. The ideas generated could be easily be integrated in to the next generation of VCSEL based optical transmitters.

## Chapter 7: Conclusion

Over the past decade, wireline I/O has been instrumental in enabling the incredible scaling of computer systems, ranging from handheld electronics to supercomputers. In part, this increase in bandwidth is enabled by expanding the number of I/O pins per component. As a result, I/O circuitry consumes an increasing amount of area and power on today's chips. Increasing bandwidth has also been enabled by rapidly accelerating the per-pin data-rate. As shown in Figure 7.1, this trend is anticipated to continue, according to the International Technology Roadmap for Semiconductors (ITRS) [76]. However, enabling this rather amazing trend for I/O scaling will require more than just Moore's law scaling [77] of transistor sizes. Significant advances in both energy efficiency and signal integrity are required in order to enable the next generation of low-power and high-performance computing systems. To this effect, this dissertation presents high performance design techniques for the three fundamental components of a high-speed link, namely, transmitter, receiver, and clocking.

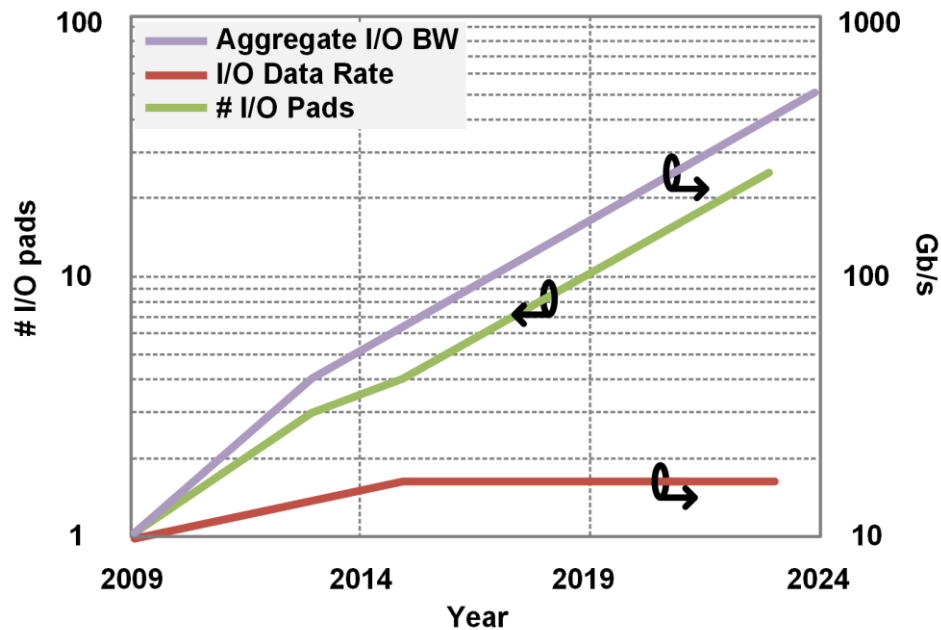


Figure 7.1: Constant growth of the required I/O bandwidth according to ITRS.

At the clocking front, injection locking is fast emerging as an ultra-low power alternative to the conventional PLL and DLL based approaches. As shown in Figure 7.2, number of publications (in ISSCC) based on injection locked clocking for wireline applications has increased steadily throughout the past decade. However, there are still some challenges that have not been successfully tackled by previous publications. Among them the most important is the limited locking range of injection locked oscillators. A small locking range makes injection locking less suitable for wideband application (e.g. transceivers in modern FPGAs [54]). In addition this also makes the injection locking based system prone to PVT variations. In this dissertation we introduced two architectures that tackle this issue. In addition, we also used these architectures for low-power quadrature phase generation, a prerequisite for energy efficient quarter-rate clocking architectures.

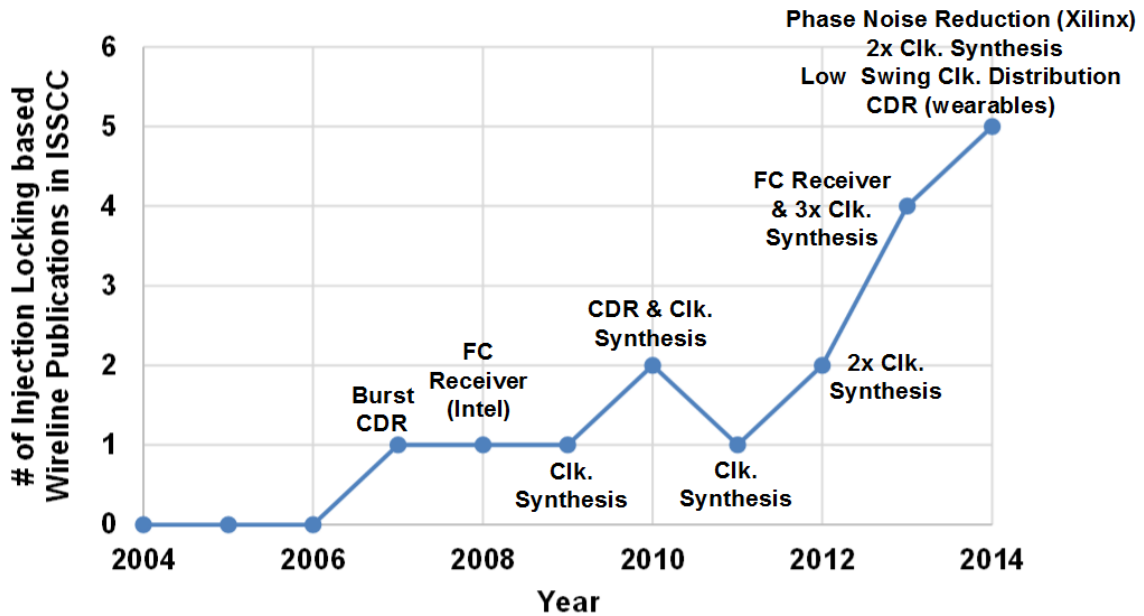


Figure 7.2: Number of injection locking based wireline publications in International Solid-State Circuits Conference (ISSCC) across a decade.

In the first part of this dissertation we described a wideband injection locking scheme in an LC oscillator. PLL and injection locking elements were combined symbiotically to achieve wide locking range while retaining the simplicity of the latter. The method does not require a phase frequency detector or a loop filter to achieve phase lock. A mathematical analysis of the system was presented and puts the technique on a firm theoretical footing. A locking range of 13.4 GHz–17.2 GHz (25%) and an average jitter tracking bandwidth of up to 400 MHz were measured in

a high- $Q$  LC oscillator. This architecture was used to generate quadrature phases from a single clock without any frequency division. It also provides high frequency jitter filtering while retaining the low frequency correlated jitter essential for forwarded clock receivers.

To improve the locking range of an injection locked ring oscillator, QLL (quadrature locked loop) was introduced. We mathematically proved that the phase mismatch in the outputs of a quadrature ring ILO contains information about the difference between its natural and injected frequencies, in both locked and unlocked states. The phase mismatch was measured and used to track the injected frequency dynamically and increase the effective locking range. The technique improves an ILO's locking range from 5.5% (7-7.4GHz) to 90% (4-11GHz) without using a phase frequency detector (PFD). The dynamics of the system were derived and were shown to have first order characteristics. This guarantees stability without peaking, in contrast to a second order IL PLL. The system was used to generate accurate quadrature phases, without any frequency division, from a single phase of reference clock input, supplied electrically or optically. A power efficient two stage ring oscillator combined with the low jitter performance of the ILO allows us to achieve the best (jitter and power) FOM. This technique could be easily extended to be used for wideband injection in injection locking based frequency multipliers [17] and CDR [39].

As the bandwidth demand for traditional electrical wireline interconnects has accelerated, optics has become an increasingly attractive alternative for interconnects within computing systems. The negligible frequency dependent loss of optical channels provides the potential for optical link designs to fully utilize increased data rates provided through CMOS technology scaling without excessive equalization complexity. However, this can only be a viable solution if significant power benefits can be achieved. To address future optical interconnects power consumption requirement, we proposed QLL based low power clocking circuit for a four channel quarter-rate optical receiver and a low-power VCSEL based optical transmitter.

The QLL was used to generate accurate clock phases for a four channel optical receiver using a forwarded clock at quarter-rate. The QLL drives an ILO at each channel, without any repeaters, for local quadrature clock generation. Each local ILO has deskew capability for phase alignment. The optical receiver uses the inherent frequency-to-voltage conversion provided by the QLL to dynamically body bias its devices. The wide locking range of the QLL helps to achieve a reliable data-rate of 16-32Gb/s and adaptive body biasing aids in maintaining an ultra-low power consumption of 153fJ/bit. Measured results validated the feasibility of the QLL and the optical receiver for ultra-low-power, high data-rate, and massively parallel optical links.

We ended the dissertation by presenting a novel modelling technique that takes into account the inherent non-linearity in the VCSEL's frequency response. The modelling provided an important insight. The conventional FIR-based pre-emphasis works well for LTI electrical channels but is not optimum for the non-linear optical response of the VCSEL. The time domain optical responses for a one and q zero were used to derive an optimum equalization strategy. The rising and falling edges were equalized separately, and the equalization delay was selected, based on the bias current of the VCSEL. The equalization technique was used to achieve an ultra-low power efficiency of 0.77pJ/bit at a data-rate of 20Gb/s. The ideas generated in this dissertation could be easily be integrated into the next generation of VCSEL based optical transmitters.

# List of Abbreviations

AWGN	Additive white Gaussian noise
BB	Body biasing
BER	Bit error rate
BOX	Buried oxide layer
CDR	Clock-data recovery
CMOS	Complementary meta-oxide-semiconductor
DJ	Deterministic jitter
DLL	Delay-locked loop
DFE	Decision-feedback equalizer
EC	Embedded clock
FC	Forwarded clock
FDSOI	Fully depleted silicon on insulator
FIR	Finite impulse response
FLL	Frequency locked loop
FOM	Figure of merit
FPGA	Field-programmable gate array
Gb/s	Gigabit-per-second
IC	Integrated circuit
I/O	Input/Output
IL	Injection locking
ILO	Injection locked loop
IL PLL	Injection locked phase locked loop
ISI	Inter symbol interference
LBW	Low bandwidth
LPF	Low-pass filter
LTI	Linear time invariant
MQPE	Mean quadrature phase error
PFD	Phase frequency detector
PI	Phase interpolator



PLL	Phase-locked loop
PRBS	Pseudo-random bit sequence (usually appended with a number indicating its length; for example, a PRBS-7 is $2^7-1 = 127$ bits long)
PVT	Process, voltage, temperature
QLL	Quadrature locked loop
RJ	Random jitter
RO	Ring oscillator
RMS	Root mean square
SNR	Signal-to-noise ratio
TIE	Time interval error
UI	Unit interval (one bit-time in a data stream)
VCDL	Voltage-controlled delay line
VCO	Voltage-controlled oscillator
VCSEL	Vertical-cavity surface-emitting laser
WDM	Wavelength division multiplexing

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